

Cardiac Rhythm Disease Management Product Performance Report

Important Patient Management Information for Physicians

2009

First Edition – Issue 60







A Message from the Vice President

Dear Customer,

At Medtronic, product quality and reliability have been and will continue to be a priority. For over 25 years, Medtronic has compiled and produced product performance reports with one primary goal, to provide you with the product information you need to best care for your patients.

Our commitment to you is best expressed in Medtronic's mission: "To strive without reserve for the greatest possible reliability and quality in our products; to be the unsurpassed standard of comparison and to be recognized as a company of dedication, honesty, integrity, and service." To this end, we continually explore new ways to expand, improve, and learn from our product performance systems and measures.

Our quality goals cannot be reached alone. We welcome your collaboration, insight, and recommendations. Please contact our Technical Services Department at 1 (800) 723-4636 with your feedback comments and any questions.

Your participation and assistance in returning explanted products are also critical. Returned products are tested and evaluated so that we can fully measure the performance of our devices. Please refer to the instructions on page 2 for assistance in returning products to the Medtronic CRDM Returned Product Analysis Laboratory.

As we constantly strive to exceed your expectations, we thank you for your dedication to improving and saving the lives of those suffering from cardiac rhythm disorders.

With appreciation and warm regards,

Tim Samsel

Vice President, Quality and Regulatory

Medtronic Cardiac Rhythm Disease Management

Medtronic, Inc.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

US Technical Services Department

Phone: 1 (800) 723-4636 (Tachy)

1 (800) 505-4636 (Brady)

1 (800) 824-2362 Fax:

www.medtronic.com/corporate/contact.jsp

International Technical Centers

Europe (Heerlen NL) +31-45-566-8844 Japan (Tokyo) +81-3-5753-4116

For questions related to this CRDM Product Performance Report, please call US Technical Services at the number above, or write to:

> Timothy Smith Medtronic, Inc. 8200 Coral Sea Street NE MS MVN61 Mounds View, MN 55112 USA

Email: tim.smith@medtronic.com

For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States:

Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

Medtronic, Inc.

7000 Central Avenue NE MS RCE172 Minneapolis, MN 55432-3576 USA

1 (800) 328-2518, ext. 44800

Email: crdm.returnedproduct@medtronic.com

Editorial Staff

Independent Physician Quality Panel

Angelo Auricchio, MD, Lugano, Switzerland Hugh Calkins, MD, Baltimore, MD Steven J. Compton, MD, Anchorage, AK John P. DiMarco, MD, PhD, Charlottesville, VA Kevin Hackett, MD, Columbus, OH Mariell Jessup, MD, Philadelphia, PA R. Hardwin Mead, MD, Palo Alto, CA

Tim Samsel, Vice President, CRDM Quality and Regulatory

Authors

Timothy Smith, Senior Principal Product Performance Engineer, CRDM, Product Performance Reporting Corrine Buchanan, Senior Clinical Trial Leader Mike Lenarz, Senior Statistician, CRDM Scott McRae, Statistician, CRDM Tim Hamann, Graphic Designer, CRDM

Medtronic Review Board

David Steinhaus, MD, Vice President and Medical Director, CRDM Lonny Stormo, Vice President, CRDM, Therapy Delivery Subu Mangipudi, Director, Product Vigilance and Reliability

Trademarks of Medtronic, Inc.

Adapta® InSync III Protect™ AT500® InSync Sentry® Attain® Intrinsic® CapSure® Jewel® CapSure Sense® Kappa® CapSureFix® Capture Legend® Management® Marquis® CareLink® Maximo® Concerto® Medtronic CareAlert® Consulta™ Medtronic EnPulse® CareLink® EnRhythm® Micro Jewel EnTrust® Micro Minix GEM® Minix InSync® Minuet InSync ICD® MVP^{\otimes} InSync Marquis™ Onyx® InSync II Marquis™ Patient Alert™ $InSync\ III\ Marquis^{\scriptscriptstyle{TM}}$ Preva InSync Maximo® Prevail® InSync II

Protect™

Prodigy

Relia™ Secura™ SelectSecure®

Sensia® Sensing Assurance Sigma® Spectraflex Sprint™ Sprint Fidelis® Sprint Quattro® Sprint Quattro Secure® SureFix® Target Tip® Tenax Thera®-i Transvene Versa® Virtuoso®

Quick Look™

CRDM Product Performance Report

Introduction 4
Method for Estimating CRT, ICD, and IPG Device Performance 9

CRT Cardiac Resynchronization Therapy 13

CRT Survival Summary 20 CRT Reference Chart 22

ICD Implantable Cardioverter Defibrillators 23

ICD Survival Summary 34 ICD Reference Chart 37 ICD Connector Styles 39

IPG Implantable Pulse Generators 40

IPG Survival Summary 69 IPG Reference Chart 77

Leads

Method for Estimating Lead Performance 80

Left-Heart Leads 83 Lead Survival Summary 86 US Returned Product Analysis Summary 86 Reference Chart 86

Defibrillation Leads 87 Lead Survival Summary 95 US Returned Product Analysis Summary 96

US Returned Product Analysis Summar Reference Chart 97 Pacing Leads 98

Lead Survival Summary 130 US Returned Product Analysis Summary 134 Reference Chart 136

Epi/Myocardial Pacing Leads 138

Lead Survival Summary 141 US Returned Product Analysis Summary 142 Reference Chart 142

VDD Single Pass Pacing Leads 143 Lead Survival Summary 144 US Returned Product Analysis Summary 144 Reference Chart 144

ICD and CRT-D Charge Time Performance 145

Advisories 151

(in order of communication date, from most recent to oldest)

Performance Notes 160

Clinical Management of VCM near Elective Replacement 160
Ensuring the Accuracy of Battery Longevity Estimates 161
Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation 162
AT500 Pacing System Follow-Up Protocol 163
Insertion of the Lead into the Device 164
GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior 165
General Follow-Up and Replacement of ICD Leads 166
Clinical Management of High Voltage Lead System Oversensing 167
Tests and Observations for Clinical Assessment of Chronic Pacing Leads 168

Index 169

Issue 60 Date cutoff for this edition is January 31, 2009

2009 First Edition

This report is available online at www.CRDMPPR.medtronic.com

Introduction

All product performance reports are not created equal. For 26 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), cardiac resynchronization therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic Cardiac Rhythm Disease Management (CRDM) uses both returned product analysis and multicenter clinical studies to monitor performance.

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study. Medtronic CRDM is unique in the industry in that we track CRT, ICD, and IPG device survival using both methods.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is

designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead-related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure.

The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

Since May 2000, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly, Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted products from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab. For information on how to contact the Lab, refer to Contact Information on page 2 of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see Contact Information on page 2 of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for each individual device and lead in the *population sample*. The population sample for CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in our multicenter, international prospective System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined for the study.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads
- implanted in patients who are lost to follow-up

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles Method for Estimating CRT, ICD, and IPG Device Performance (page 9) and Method for Estimating Lead Performance (page 80).

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with an orange X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

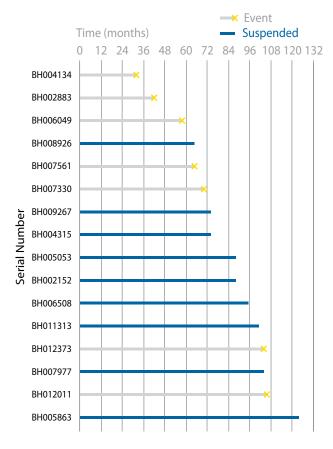


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that seven of the 16 devices suffered events, and nine are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized, as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For the interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The Effective Sample Size (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval overestimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices underestimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The Interval Survival Probability (F) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the Proportion with Event (E). This number can be interpreted as the estimated rate at which events do not occur in the time interval.

The Cumulative Survival Probabilities (G) from the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

Table 1 Life Table for Figure 1

	Α	В	C	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Definitions:

A Number Entered	B Number Suspended	C Number of Events	D Effective Sample Size	E Proportion with Event	F Interval Survival Probability	G Cumulative Survival Probability
Number of devices active at the start of the interval	Number of devices removed from service for reasons other than an event	Number of units removed from service due to an event	Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered.	Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size.	The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event.	The overall probability of surviving to the end of the interval. Computed by multiplying the Interval Survival Probability by the previous interval's Cumulative Survival Probability.

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the Interval Survival Probability (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%.

The *Cumulative Survival Probabilities* (**G**) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.

Cumulative Survival Probability (%)

100 90 80 70 60 50 30 12 24 48 108 120 36 60 72 84 96 Time (months) 36 48 60 72 96 108 120 0 12 84 132 100 93.8 87.5 81.3 68.3 68.3 68.3 34.1 34.1 100 100 34.1 16 16 16 16 15 12.5 0.5 **Effective Sample Size**

Figure 2 Survival Curve for Data Given in Table 1

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product Performance Report

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using 1-month intervals (for CRT, ICD, and IPG devices) or 3-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.¹

¹ Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis – 3rd Edition (Wiley Series in Probability and Statistics).

Method for Estimating CRT, ICD, and IPG Device Performance

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's United States device registration data and US returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) has functioned normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Definition of Malfunction

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function, and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion – The condition when:

- (a) a device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) a device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include estimated longevities for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

Expanded Malfunction Detail

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component - Findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – Findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery - Findings linked to the battery and its components

Software/Firmware - Findings linked to software or firmware function

Possible Early Battery Depletion – Findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – Findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive

Returned Product Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first 5 years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables are rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more malfunctions or battery depletions. This occurs because, even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way

to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

A CRT, ICD, or IPG model or model family will be included in this report when it has accumulated at least 10,000 implant months and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in clinical studies (including the System Longevity Study) and the device registration system.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

However, at this time, no adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to non-device related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, the patient mortality rate derived from our device registration system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in our device registration is significantly different from published rates, an adjustment is applied to correct the difference.

7272 InSync ICD

US Market Release	Jul-02	Malfunctions (US)
Registered US Implants	13,000	Therapy Function Not Compromised
Estimated Active US Implants	1,000	Battery
Normal Battery Depletions (US)	1,284	Electrical Component
Advisories	None	Software/Firmware
		Possible Early Battery Depletion
		Therapy Function Compromised
		Battery

Product Characteristics

238

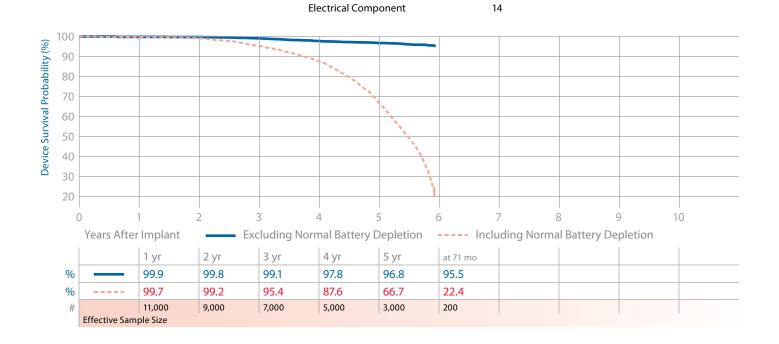
184

15

1

14

NBD Code	VVED
Serial Number Prefix	PJP
Max Delivered Energy	34 J
Estimated Longevity	See page 22

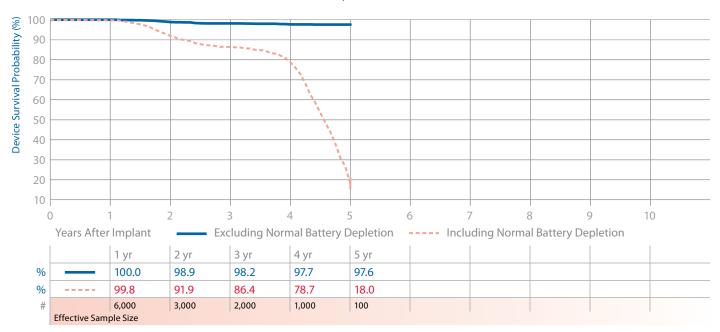




7277 InSync Marquis

US Market Release	Ma	ar-03	Malfunctions (US)	74
Registered US Implants 7,0		7,000	Therapy Function Not Compromised	63
Estimated Active US Im	plants	100	Battery	1
Normal Battery Depletions (US)		588	Electrical Component	8
Advisories: See page 153 – 2005 Potential			Software/Firmware	1
Premature Battery Depletion Due to Battery Short			Possible Early Battery Depletion	53
			Therapy Function Compromised	11
			Battery (10 malfunctions related to advisory)	10
			Electrical Component	1

NBD Code	VVED
Serial Number Prefix	PLT
Max Delivered Energy	30 J
Estimated Longevity	See page 22





7289 InSync II Marquis

US Market Release	Jul-03
Registered US Implants	28,000
Estimated Active US Implants	1,000
Normal Battery Depletions (US)	5,001
Advisories: See page 153 – 2005 Po Premature Battery Depletion Due to Battery Short	

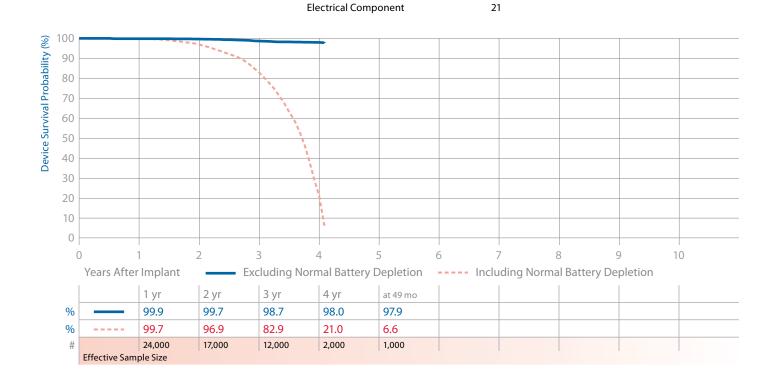
Malfunctions (US)	284
Therapy Function Not Compromised	253
Electrical Component	20
Software/Firmware	1
Possible Early Battery Depletion	232
Therapy Function Compromised	31

Battery (8 malfunctions related to advisory)

10

Product Characteristics

'VED
RJ
0 J
ee page 22

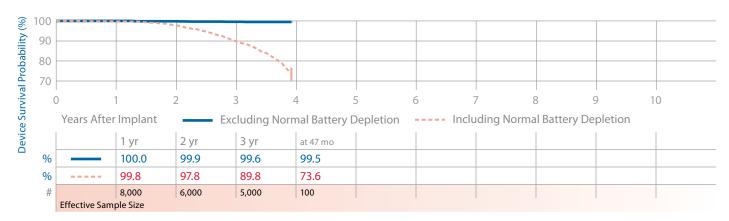


7297 InSync Sentry

US Market Release	Nov-04
Registered US Implants	9,000
Estimated Active US Implants	4,000
Normal Battery Depletions (US)	458
Advisories	None

Malfunctions (US)	30
Therapy Function Not Compromised	29
Battery	1
Electrical Component	6
Software/Firmware	1
Possible Early Battery Depletion	21
Therapy Function Compromised	1
Electrical Component	1

NBD Code	VVED
Serial Number Prefix	PRK
Max Delivered Energy	35 J
Estimated Longevity	See page 22



7299 InSync Sentry

US Market Release	Apr-05
Registered US Implants	31,000
Estimated Active US Implants	18,000
Normal Battery Depletions (US)	708
Advisories	None

Malfunctions (US)	48
Therapy Function Not Compromised	43
Electrical Component	9
Software/Firmware	2
Possible Early Battery Depletion	32

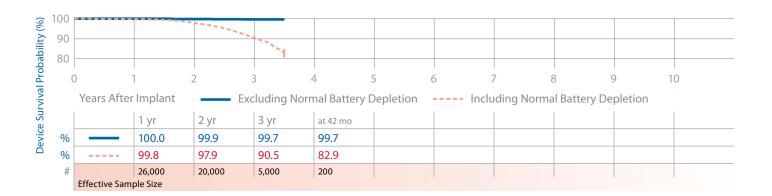
Therapy Function Compromised

Electrical Component

Product Characteristics

5 5

NBD Code	VVED
Serial Number Prefix	PRK
Max Delivered Energy	35 J
Estimated Longevity	See page 22

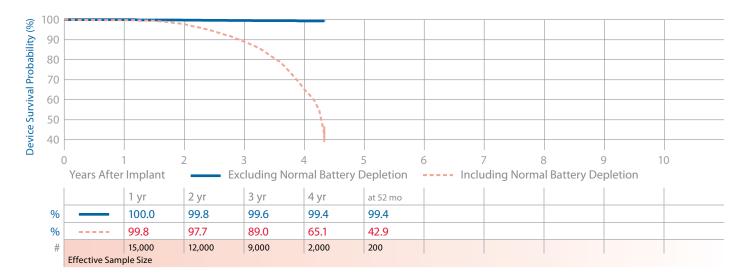


7303 InSync Maximo

US Market Release	Jun-04
Registered US Implants	17,000
Estimated Active US Implants	6,000
Normal Battery Depletions (US)	1,408
Advisories	None

Malfunctions (US)	62
Therapy Function Not Compromised	57
Electrical Component	11
Software/Firmware	2
Possible Early Battery Depletion	44
Therapy Function Compromised	5
Electrical Component	5

NBD Code	VVED
Serial Number Prefix	PRL
Max Delivered Energy	35 J
Estimated Longevity	See page 22





7304 InSync Maximo

US Market Release	Apr-05
Registered US Implants	18,000
Estimated Active US Implants	11,000
Normal Battery Depletions (US)	344
Advisories	None

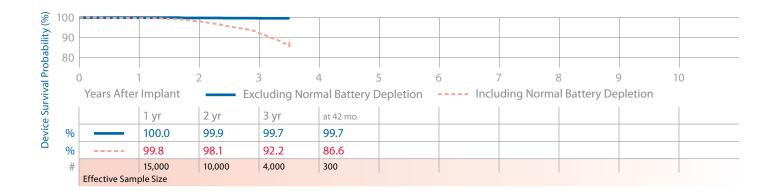
Malfunctions (US)	24
Therapy Function Not Compromised	22
Battery	1
Electrical Component	7
Possible Early Battery Depletion	14
Therapy Function Compromised	2

Electrical Component

Product Characteristics

2

NBD Code	VVED
Serial Number Prefix	PRL
Max Delivered Energy	35 J
Estimated Longevity	See page 22

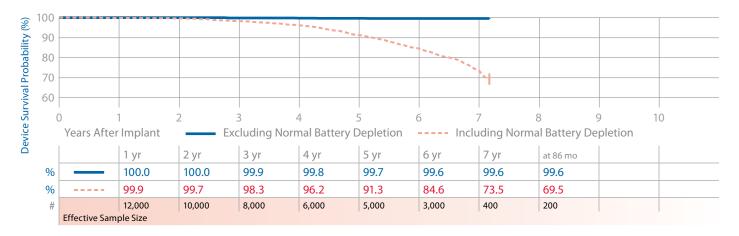


8040 InSync

US Market Release	Aug-01
Registered US Implants	15,000
Estimated Active US Implants	3,000
Normal Battery Depletions (US)	533
Advisories	None

Malfunctions (US)	28
Therapy Function Not Compromised	7
Electrical Component	4
Possible Early Battery Depletion	3
Therapy Function Compromised	21
Electrical Interconnect	21

NBD Code DDDR Serial Number Prefix PIN		
Serial Number Prefix PIN	,	DDDR
	,	PIN
Estimated Longevity See page 2		See page 22



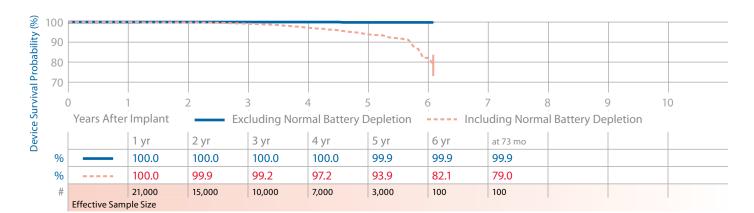
8042 InSync III

US Market Release	Feb-03
Registered US Implants	29,000
Estimated Active US Implants	16,000
Normal Battery Depletions (US)	243
Advisories	None

Malfunctions (US)	6
Therapy Function Not Compromised	3
Electrical Component	2
Possible Early Battery Depletion	1
Therapy Function Compromised	3
Flectrical Interconnect	3

Product Characteristics	
-------------------------	--

NBD Code	DDDR
Serial Number Prefix	PKF
Estimated Longevity	See page 22



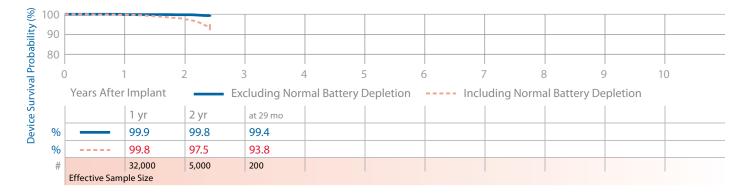
C154DWK, C164AWK, C174AWK Concerto

US Market Release	May-06
Registered US Implants	68,000
Estimated Active US Implants	57,000
Normal Battery Depletions (US)	168
Advisories	None

Malfunctions (US)	50
Therapy Function Not Compromised	36
Electrical Component	7
Possible Early Battery Depletion	29
Therapy Function Compromised	14
Electrical Component	13
Electrical Interconnect	1

Product Characteristics

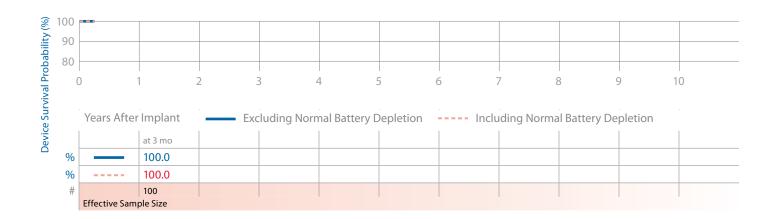
NBD Code	VVED
Serial Number Prefix	PVU, PVT, PVR
Max Delivered Energy	35 J
Estimated Longevity	See page 22





D224TRK Consulta CRT-D

US Market Release	Aug-08	Malfunctions (US)	0	NBD Code	DDED
Registered US Implants	2,000	Therapy Function Not Compromised	0	Serial Number Prefix	PUD
Estimated Active US Implants	2,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0			Estimated Longevity	See page 22
Advisories	None				



D284TRK Maximo II CRT-D

US Market Release	Mar-08
Registered US Implants	1,000
Estimated Active US Implants	1,000
Normal Battery Depletions (US)	0
Advisories	None

Malfunctions (US)	
Therapy Function Not Compromised	
Therapy Function Compromised	

Product Characteristics

0 0 0

NE	BD Code	VVED	
Se	rial Number Prefix	PZP	
M	ax Delivered Energy	35 J	
Es	timated Longevity	See page 22	



Device Survival Summary (95% Confidence Interval)

The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

		10 yr														
		10														
		8 yr														
		7 yr														
		6 yr	95.5 +0.6/-0.7 at 71 mo	22.4 +2.3/-2.2 at 71 mo												
		5 yr	96.8 +0.4/-0.5	66.7	97.6 +0.5/-0.7	18.0 +3.0/-2.8	97.9 +0.2/-0.3 at 49 mo	6.6 +0.8/-0.7 at 49 mo					99.4 +0.1/-0.2 at 52 mo	42.9 +3.8/-3.9 at 52 mo		
(%)		4 yr	97.8 +0.3/-0.4	87.6 +0.8/-0.8	97.7 +0.5/-0.6	78.7	98.0 +0.2/-0.3	21.0	99.5 +0.2/-0.2 at 47 mo	73.6 +3.1/-3.4 at 47 mo	99.7 +0.1/-0.1 at 42 mo	82.9 +2.1/-2.3 at 42 mo	99.4 +0.1/-0.2	65.1 +1.2/-1.3	99.7 +0.1/-0.2 at 42 mo	86.6 +1.3/-1.5 at 42 mo
Device Survival Probability (%)	÷	Y	99.1 +0.2/-0.2	95.4 +0.4/-0.5	98.2 +0.4/-0.5	86.4	98.7 +0.2/-0.2	82.9 +0.6/-0.6	99.6 +0.1/-0.2	89.8 +0.7/-0.8	99.7 +0.1/-0.1	90.5	99.6 +0.1/-0.1	89.0+0.6/-0.6	99.7 +0.1/-0.1	92.2 +0.6/-0.7
ırvival Pr	er Implar	2 yr	99.8 +0.1/-0.1	99.2 +0.2/-0.2	98.9 +0.3/-0.4	91.9 +0.8/-0.9	99.7 +0.1/-0.1	96.9 +0.2/-0.3	99.9 +0.1/-0.1	97.8 +0.3/-0.4	99.9+0.0/-0.1	97.9 +0.2/-0.2	99.8 +0.1/-0.1	97.7	99.9 +0.0/-0.1	98.1 +0.2/-0.3
Device Su	Years After Implant		99.9	99.7 +0.1/-0.1	100.0	99.8	99.9	99.7 +0.1/-0.1	100.0 +0.0/-0.1	99.8	100.0 +0.0/-0.0	99.8	100.0	99.9	100.0 +0.0/-0.0	99.8
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion								
			2	N	No	Nor	N	Nor	Nor	Norn	Nor	Norn	Nor	Norn	Š	Non
ons (US)	pəsimoro		= 238	io _N	= 74		= 284		= 30	Norn	= 48	Norn	= 62	Norn	= 24	Nor
Malfunctions (US)	toN not bəsimorc	Comp Thers Funct	238	Nor	74		284		30	Norn	48	Norn	62	Norn	24	Non
Malfunctions (US)	yqr ion Not somised	Deplo Thers Comp Thers Functional	+ 223 = 238	Nor	+ 63 = 74	$\frac{(10)}{(advisory-related subset)}$	+ 253 = 284	$\frac{(8)}{(advisory-related subset)}$	+ 29 = 30	Norn	+ 43 = 48	Norn	+ 57 = 62	Norn	+ 22 = 24	Non
Malfunctions (US)	nal Battery etions (US) to Punction spy Function spy qer tion Not tion Not	Impla Norm Thera Comp Thera Funci	15 + 223 = 238	Nor	11 + 63 = 74	$\frac{(10)}{(advisory-related subset)}$	31 + 253 = 284	$\frac{(8)}{(advisory-related subset)}$	1 + 29 = 30	Nom	5 + 43 = 48	Norm	5 + 57 = 62	Norn	2 + 22 = 24	Non
Malfunctions (US)	sints Sal Battery Scions (US) The properties of the properties	US Im Estim Activ Morm Deplo Thers Comp Thers Funct	1,284 15 + 223 = 238	Nor	588 11 + 63 = 74	$\frac{(10)}{(advisory-related subset)}$	5,001 31 + 253 = 284	$\frac{(8)}{(advisory-related subset)}$	458 1 + 29 = 30	Nom	708 5 + 43 = 48	Norm	1,408 5 + 57 = 62	Norn	344 2 + 22 = 24	Non
Malfunctions (US)	stered balants e US e US sints sints consistency solutions consistency consist	Regisa NS Implis Morm Morm Morm Morm Deplo Comp	1,000 1,284 15 + 223 = 238	Non	100 588 11 + 63 = 74	$\frac{(10)}{(advisory-related subset)}$	1,000 5,001 31 + 253 = 284	$\frac{(8)}{(advisory-related subset)}$	4,000 458 1 + 29 = 30	Nom	18,000 708 5 + 43 = 48	Norm	6,000 1,408 5 + 57 = 62	Norn	11,000 344 2 + 22 = 24	Non
Malfunctions (US)	reted higherts based batter based be US but batter but based by the CO but be better but be better but be better but	Regisa NS Implis Morm Morm Morm Morm Deplo Comp	13,000 1,000 1,284 15 + 223 = 238	Nor	7,000 100 588 11 + 63 = 74		28,000 1,000 5,001 31 + 253 = 284		9,000 4,000 458 1 + 29 = 30	Nom	31,000 18,000 708 5 + 43 = 48	Norm	$17,000 6,000 1,408 \qquad 5 + 57 = 62$	Norn	18,000 11,000 344 2 + 22 = 24	Non

		10 yr										
		8 yr	99.6 +0.1/-0.2 at 86 mo	69.5 +2.7/-2.9 at 86 mo								
		7 yr	99.6	73.5 +1.9/-2.0	99.9 +0.0/-0.1 at 73 mo	79.0 +4.8/-5.9 at 73 mo						
		6 yr	99.6 +0.1/-0.2	84.6 +0.9/-1.0	99.9 +0.0/-0.1	82.1 +4.1/-5.1						
		5 yr	99.7 +0.1/-0.2	91.3 +0.7/-0.7	99.9 +0.0/-0.1	93.9 +0.6/-0.7						
y (%)		4 yr	99.8 +0.1/-0.1	96.2 +0.4/-0.4	100.0	97.2 +0.3/-0.4						
Device Survival Probability (%)	ınt	3 yr	99.9 +0.0/-0.1	98.3 +0.2/-0.3	100.0	99.2 +0.1/-0.2	99.4 +0.3/-0.5 at 29 mo	93.8 +1.3/-1.7 at 29 mo				
Survival F	Years After Implant	2 yr	100.0	99.7 +0.1/-0.1	100.0	99.9	99.8 +0.1/-0.1	97.5 +0.3/-0.3				
Device !	Years Af	1 yr	100.0	99.9	100.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0	99.8 +0.0/-0.1	100.0 +0.0/-0.0 at 3 mo	100.00 +0.0/-0.0 at 3 mo	100.0 +0.0/-0.0 at 2 mo	100.00 +0.0/-0.0 at 2 mo
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion						
			Norr	Norn	Norn	Nor	Nor	Norm	Nor	Norm	Nor	Norm
S)	ls	тот	28 Norn	Norn	6 Norn	Norn		Norm		Norm		Norm
ins (US)	ubromised	ıoɔ		Norn		Norm	= 50	Norm	0	Norm	0	Norm
unctions (US)		ıoɔ	7 = 28	Norn	3 = 6	Norn	36 = 50	Norm	0 = 0	Norm	0 = 0	Norm
Malfunctions (US)	ubromised	The The run ³ Cor	= 28	Norn	9	Norm	= 50	Norm	0	Norm	0	Norm
Malfunctions (US)	npromised erapy Iction Not npromised	The Cor The The Tun Tun Too	+ 7 = 28	Norn	+ 3 = 6	Norra	+ 36 = 50	Norm	0 = 0 +	Norm	0 = 0 +	Norm
Malfunctions (US)	oletions (US) grapy Function npromised grapy trapy ction Not hytomised	Act Inpp Inpp Inpp Inpp Inpp Inpp Inpp Inp	21 + 7 = 28	Norn	3 + 3 + 5	Norm	14 + 36 = 50	Norm	0 = 0 + 0	Norm	0 = 0 + 0	Norm
Malfunctions (US)	ive US blants mal Battery siletions (US) mpromised mpromised srapy srapy stapy mpromised	SU Esti Acti Impli	533 21 + 7 = 28	Norn	243 3 + 3 = 6	Norm	168 14 + 36 = 50	Norm	0 = 0 + 0	Norm	0 = 0 + 0	Norm
Malfunctions (US)	Implants ive US ive US solidate mal Battery solidate ive US) function stepy Function promised function solidate	Reci US String Moi Uni Moi Dep The Con	3,000 533 21 + 7 = 28	Norn	16,000 243 3 + 3 = 6	Norm	57,000 168 14 + 36 = 50	Norm	2,000 0 0 + 0 = 0	Norm	1,000 0 0 0 0 0 0 0	Norm
Malfunctions (US)	pistered implants imated by the US ive US ive US inal Battery inal	Reci US String Moi Uni Moi Dep The Con	15,000 3,000 533 21 + 7 = 28	Norn	29,000 16,000 243 3 + 3 = 6	Norm	68,000 57,000 168 14 + 36 = 50	Norm	2,000 $2,000$ 0 0 $+ 0 = 0$	Norm	1,000 $1,000$ 0 0 0 0 0 0 0	Norm



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					E	stimate	d Longe	vity		Elective	End of	
	Family			Delivered Energy	**					(ERI)***		
Model Number		Connector Style			Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	me ()	Life (EOL) Battery Voltage
7272	InSync ICD	DR+LV	66 cc 117 g	34 J	Monthly Quarterly Semiannual	5.4 6.5 6.9	6.3 8.0 8.5	7.3 9.4 10.3	7.8 10.3 11.2	≤ 4.91 V	_	≤ 4.57 V
7277	InSync Marquis	DR+LV split	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.7 5.0 5.5	4.3 6.0 6.7	4.7 7.0 8.0	4.9 7.5 8.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7295	InSync II Protect	DR+LV true	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.7 4.9 5.4	4.0 5.5 6.2	4.2 5.9 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

		Estimated Lo	ngevity				
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Time Indicators		
InSync	8040	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	**		
InSync III	8042	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	**		

					Es	Estimated Longevity				Recommended			
					*					Replace	ment (RRT)***		
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)	
C154DWK, C164AWK, C174AWK	Concerto	DR+LV true	38 cm 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 11.0	≤ 2.62 V	_	3 month after RRT or > 16-second charge time	
D224TRK	Consulta	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time	
D284TRK	Maximo II	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time	

^{*} Volume and mass differ by connector style.

^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).



7227 GEM Product Characteristics

S Ma	arket Release	2	Oct-	98 Ma	Ifunctions (US)		148	NBD	Code		VVEV
egis [.]	tered US Imp	olants	22,00	00				Seria	ıl Number Pref	ix	PIP, PLN,
stim	ated Active l	JS Implants	3,00	00							PLP, PLR
lorm	al Battery De	epletions (US) 1,8	24				Max	Delivered Ener	rgy	35 J
	ories: See pa	age 155 – 199	9 Potential					Estir	nated Longevit	ty	See page
100	COVENDAG										
90											
80								-			
70											
60											
50											
40											
30									· ·		
										1	
20										Y	
10	0	1	2	3	4	5	6 7	7	8	9	10
,	Years Afte	r Implant	_		lormal Battery			dina Nor	o mal Battery D	_	10
			1	1		1	1	_	1	i	at 112 mo
%		1 yr	2 yr 99.6	3 yr 99.5	4 yr	5 yr		7 yr 99.1	8 yr 99.1	9 yr 99.0	99.0
% %		99.7	98.9	99.5	98.1	97.2		82.7	64.6	33.4	13.1
90 #		20,000	17,000	15,000	13,000	11,000		5,000	3,000	1,000	200
π	Effective San		17,000	13,000	13,000	11,000	0,000	3,000	3,000	1,000	200

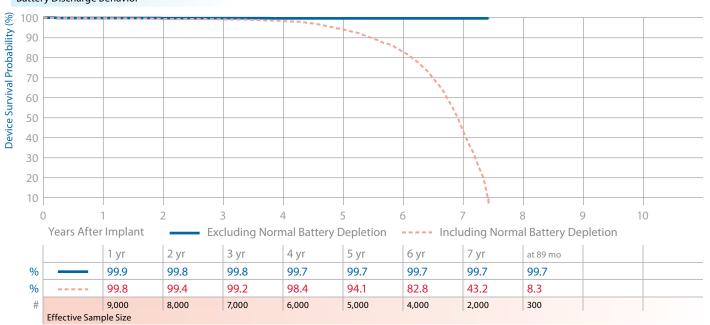
7229 GEM II VR

US Market Release	Jul-99	Malfunctions (US)	27	NBD Code	VVEV
Registered US Implants	11,000			Serial Number Prefix	PJJ
Estimated Active US Implants	40			Max Delivered Energy	30 J
Normal Battery Depletions (US)	1,932			Estimated Longevity	See page 37

Advisories: See page 155 – 1999 Potential

Circuit Overload

<u>Also see page 165</u> – Performance note on ICD Battery Discharge Behavior



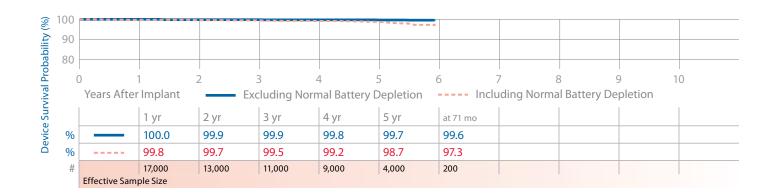


7230 Marquis VR

US Market Release	Dec	-02	Malfunctions (US)	31
Registered US Implants	19,000		Therapy Function Not Compromised	21
Estimated Active US Implants	9,0	000	Electrical Component	11
Normal Battery Depletions (US)		52	Software/Firmware	1
Advisories: See page 153 – 2005 Pote	ential		Possible Early Battery Depletion	8
Premature Battery Depletion Due to Battery Short	ue to		Other	1
battery short			Therapy Function Compromised	10
			Battery (3 malfunction related to advisory)	5
			Electrical Component	5

Product Characteristics

NBD Code	VVEV
Serial Number Prefix	PKD, PLW, PLY
Max Delivered Energy	30 J
Estimated Longevity	See page 37



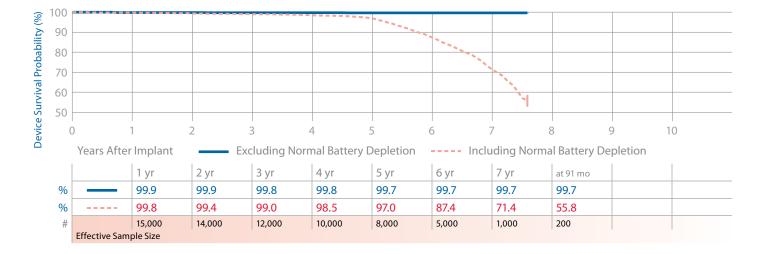
7231 GEM III VR

US Market Release	Dec-00
Registered US Implants	17,000
Estimated Active US Implants	7,000
Normal Battery Depletions (US)	795
Performance Note: See page 165 –	

Performance note on ICD Battery Discharge Behavior

Malfunctions (US)	37
Therapy Function Not Compromised	27
Battery	1
Electrical Component	22
Possible Early Battery Depletion	4
Therapy Function Compromised	10
Battery	1
Electrical Component	9

NBD Code	VVEV
Serial Number Prefix	PJL
Max Delivered Energy	30 J
Estimated Longevity	See page 37





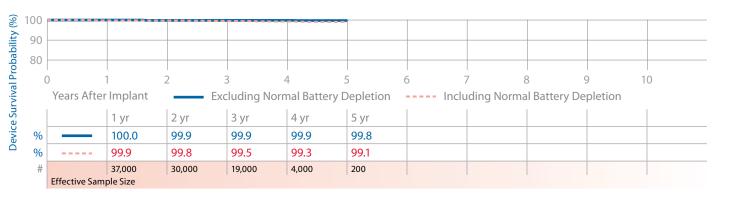
7232 Maximo VR

US Market Release	Oct-03	Malfund
Registered US Implants	43,000	Therap
Estimated Active US Implants	30,000	Ele
Normal Battery Depletions (US)	47	Pos
Advisories: See page 153 – 2005 Por Premature Battery Depletion Due to Battery Short		Therap Elec

Malfunctions (US)	35
Therapy Function Not Compromised	25
Electrical Component	13
Possible Early Battery Depletion	12
Therapy Function Compromised	10
Electrical Component	8
Electrical Interconnect	1
Possible Early Battery Depletion	1

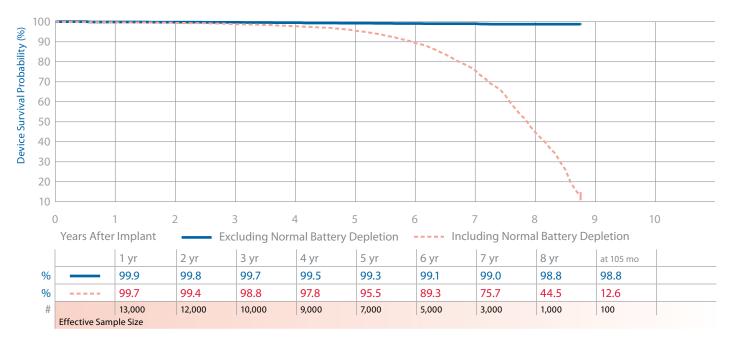
Product Characteristics	
NBD Code	VVED
6 1 111 1 5 6	221

NBD Code	VVED
Serial Number Prefix	PRN
Max Delivered Energy	35 J
Estimated Longevity	See page 37



7271 GEM DR

US Market Release	Oct-98	Malfunctions (US)	96	NBD Code	VVED
Registered US Implants	15,000			Serial Number Prefix	PIM
Estimated Active US Implants	2,000			Max Delivered Energy	27 J
Normal Battery Depletions (US)	1,370			Estimated Longevity	See page 37
Advisories	None				



ICD

7274 Marquis DR

US Market Release	Mar-02	
Registered US Implants	48,000	
Estimated Active US Implants	15,000	
Normal Battery Depletions (US)	1,495	
Advisories: See page 153 - 2005 Potential		

Advisories: See page 153 – 2005 Potential Premature Battery Depletion Due to Battery Short

Malfunctions (US) 150 Therapy Function Not Compromised 75 Battery (3 malfunctions related to advisory) 5 Electrical Component 23 Possible Early Battery Depletion 47

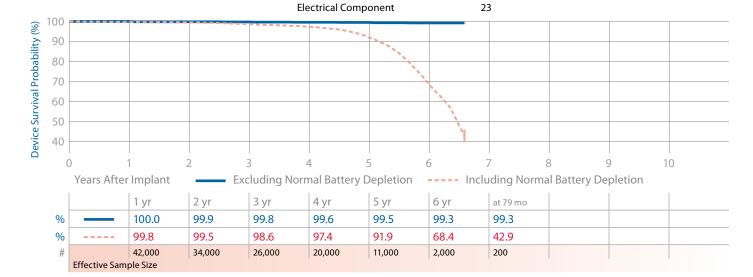
Electrical Component 23
Possible Early Battery Depletion 47

Therapy Function Compromised 75
Battery (42 malfunctions related to advisory) 52

75 Se 5 M 23 Es 47

NBD Code VVED
Serial Number Prefix PKC
Max Delivered Energy 30 J
Estimated Longevity See page 37

Product Characteristics



7275 GEM III DR

US Market Release Nov-00 Registered US Implants 20,000 Estimated Active US Implants 2,000 Normal Battery Depletions (US) 3,471

Performance Note: See page 165 – Performance note on ICD Battery Discharge Behavior

Product Characteristics

NBD Code

Malfunctions (US)	41
Therapy Function Not Compromised	30
Battery	1
Electrical Component	11
Software/Firmware	1
Possible Early Battery Depletion	17
Therapy Function Compromised	11
Battery	2
Floatrical Component	0

Serial Number Prefix

Max Delivered Energy

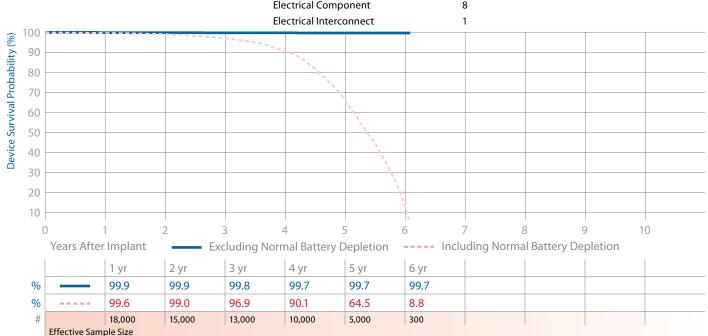
Estimated Longevity

VVED

PJM

30 J

See page 37





7276 GEM III AT

US Market Release	Feb-01	Malfunctions (US)
Registered US Implants	14,000	Therapy Function Not Compromised
Estimated Active US Implants	1,000	Electrical Component
Normal Battery Depletions (US)	2,700	Software/Firmware
Performance Note: See page 165 -		Possible Early Battery Depletion
Performance note on ICD Battery Discharge Behavior		Therapy Function Compromised
Discharge Deriavior		

Product Characteristics

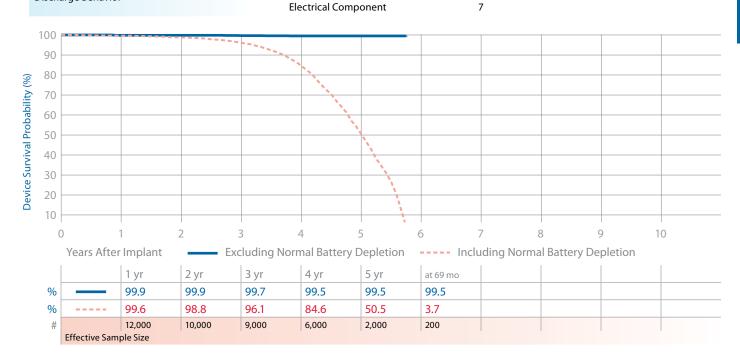
46

39 7 1

31

7

NBD Code	DDED
Serial Number Prefix	PKE
Max Delivered Energy	30 J
Estimated Longevity	See page 3



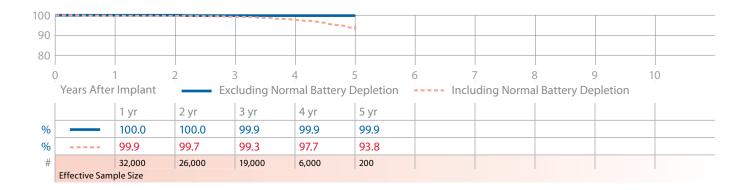
7278 Maximo DR

US Market Release	Oct-03
Registered US Implants	37,000
Estimated Active US Implants	25,000
Normal Battery Depletions (US)	194
Advisories: See page 153 – 2005 Potent Premature Battery Depletion Due to Battery Short	tial

Malfunctions (US) 29 Therapy Function Not Compromised 21 Electrical Component 12 Possible Early Battery Depletion 9 Therapy Function Compromised 8 Electrical Component 7 Possible Early Battery Depletion 1

Proc	luct C	harac	ter	istics

NBD Code	VVED
Serial Number Prefix	PRM
Max Delivered Energy	35 J
Estimated Longevity	See page 37





7288 Intrinsic

US Market Release	Aug-04
Registered US Implants	31,000
Estimated Active US Implants	22,000
Normal Battery Depletions (US)	85
Advisories	None

Malfunctions (US)	33
Therapy Function Not Compromised	27
Battery	2
Electrical Component	10
Software/Firmware	1
Possible Early Battery Depletion	14
Therapy Function Compromised	6

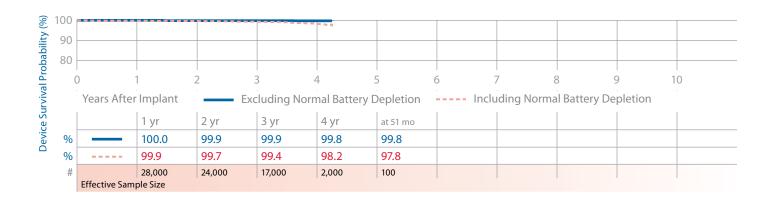
Electrical Component

Product Characteristics

6

4

NBD Code	VVED
Serial Number Prefix	PUB
Max Delivered Energy	35 J
Estimated Longevity	See page 37

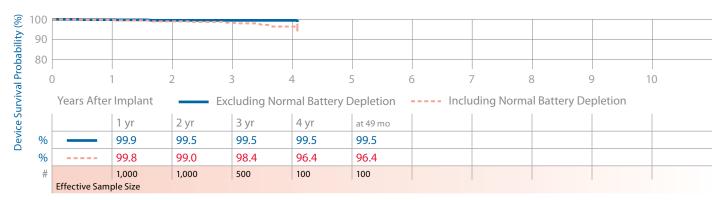


7290 Onyx

US Market Release	Mar-04
Registered US Implants	1,000
Estimated Active US Implants	1,000
Normal Battery Depletions (US)	6
Advisories	None

Malfunctions (US)
Therapy Function Not Compromised
Electrical Component
Possible Early Battery Depletion
Therapy Function Compromised
Electrical Component

NBD Code	VVEV
Serial Number Prefix	PRP
Max Delivered Energy	30 J
Estimated Longevity	See page 37

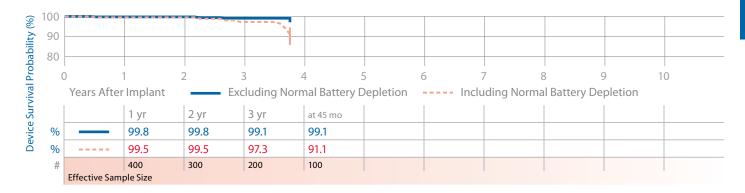




D153ATG, D153DRG EnTrust

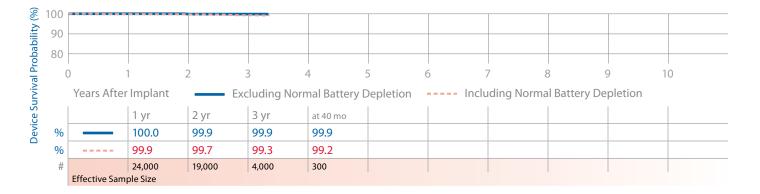
Product Characteristics

US Market Release	Jun-05	Malfunctions (US)	3	NBD Code	DDED, VVED
Registered US Implants	400	Therapy Function Not Compromised	2	Serial Number Prefix	PNR
Estimated Active US Implants	300	Possible Early Battery Depletion	2	Max Delivered Energy	30 J
Normal Battery Depletions (US)	7	Therapy Function Compromised	1	Estimated Longevity	See page 38
Advisories	None	Electrical Component	1		



D154ATG, D154DRG EnTrust

US Market Release	Jun-05	Malfunctions (US)	20	NBD Code	DDED, VVED
Registered US Implants	28,000	Therapy Function Not Compromised	14	Serial Number Prefix	PNR
Estimated Active US Implants	22,000	Electrical Component	5	Max Delivered Energy	35 J
Normal Battery Depletions (US)	33	Possible Early Battery Depletion	9	Estimated Longevity	See page 38
Advisories	None	Therapy Function Compromised	6		
		Electrical Component	6		





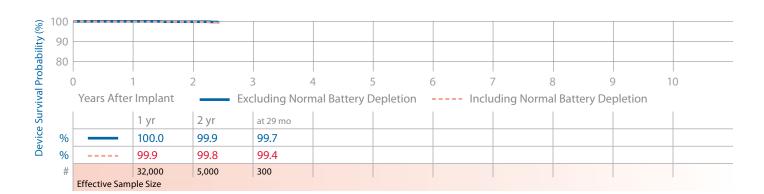
D154AWG, D164AWG Virtuoso

US Market Release	May-06
Registered US Implants	62,000
Estimated Active US Implants	56,000
Normal Battery Depletions (US)	14
Advisories	None

Malfunctions (US)	25
Therapy Function Not Compromised	10
Electrical Component	8
Electrical Interconnect	1
Possible Early Battery Depletion	1
Therapy Function Compromised	15
Electrical Component	15

Product Characteristics

NBD Code	VVED
Serial Number Prefix	PVV, PUL
Max Delivered Energy	35 J
Estimated Longevity	See page 38



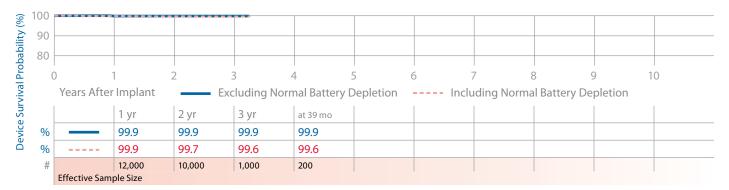
D154VRC EnTrust

U	JS Market Release	J	un-05
R	Registered US Implants	1	4,000
Е	stimated Active US Imp	plants 1	1,000
Ν	lormal Battery Depletic	ons (US)	7
Α	Advisories		None

Malfunctions (US)
Therapy Function Not Compromised
Electrical Component
Possible Early Battery Depletion
Therapy Function Compromised
Electrical Component

Product Characteristics

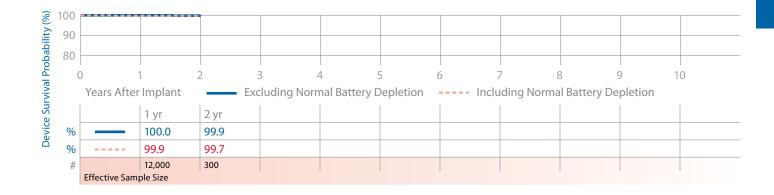
NBD Code	VVEV
Serial Number Prefix	PNT
Max Delivered Energy	35 J
Estimated Longevity	See page 38





D154VWC, D164VWC Virtuoso

US Market Release	May-06	Malfunctions (US)	8	NBD Code	VVEV
Registered US Implants	26,000	Therapy Function Not Compromised	3	Serial Number Prefix	PUN
Estimated Active US Implants	24,000	Electrical Component	2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	7	Electrical Interconnect	1	Estimated Longevity	See page 38
Advisories	None	Therapy Function Compromised	5		
		Electrical Component	5		

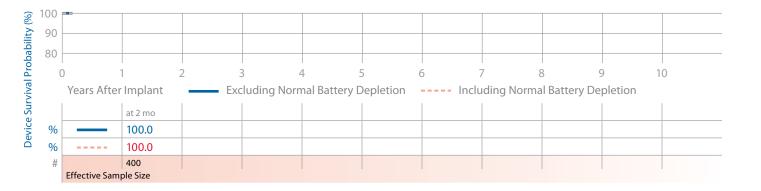


D224DRG Secura DR

US Market Release	Aug-08
Registered US Implants	1,000
Estimated Active US Implants	1,000
Normal Battery Depletions (US)	0
Advisories	None

Malfunctions (US)	
Therapy Function Not Compromise	d
Therapy Function Compromised	

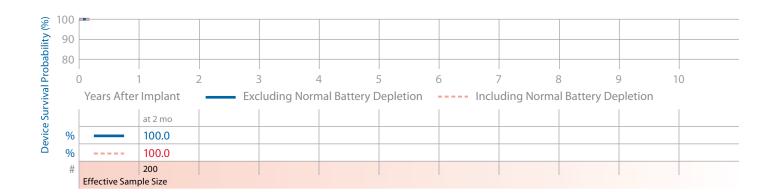






D224VRC Secura VR

US Market Release	Aug-08	Malfunctions (US)	0	NBD Code	VVEV
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PUX
Estimated Active US Implants	1,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0			Estimated Longevity	See page 38
Advisories	None				



D284DRG Maximo II DR

US Market Release

Advisories

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Malfunctions (US) 0 NBD Code VVED Therapy Function Not Compromised 0 Serial Number Prefix PZM Therapy Function Compromised 0 Max Delivered Energy 35 J Estimated Longevity See page 38

Product Characteristics

Product Characteristics

100											
90											
80											
		1	1								
(0	1	2	3	4	5	6	7	8	9	10
(0 Years Afte	1 r Implant	2 E	3 excluding No	4 ormal Battery	5 y Depletion		7 luding Norr	_	_	
(1 r Implant at 2 mo	E	3 excluding No	4 ormal Battery	5 y Depletion		7 Iuding Norr	_	_	
%		1	E	3 excluding No	4 ormal Battery	5 y Depletion		7 Iuding Norr	_	_	
		at 2 mo	2 E	3 Excluding No	4 rmal Battery	5 y Depletion		7 Iuding Norr	_	_	

Mar-08

1,000

1,000

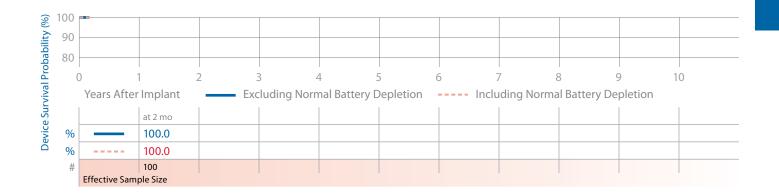
None

0



D284VRC Maximo II VR

US Market Release	Mar-08	Malfunctions (US)	0	NBD Code	VVEV
Registered US Implants	400	Therapy Function Not Compromised	0	Serial Number Prefix	PZN
Estimated Active US Implants	400	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0			Estimated Longevity	See page 38
Advisories	None				





Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

Device Survival Probability (%)	Years After Implant	1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 10 yr	Excluding Depletion 99.7 by 1/0.1 99.6 by 2 99.4 by 2 99.2 by 2 99.2 by 3 99.1 by 3 99.0 by 3 </th <th>Including Depletion 99.3 by 3 by 3 by 1/0.01 98.9 by 3 by 3 by 1/0.02 98.7 by 3 by</th> <th>Excluding Depletion 99.9 big 99.8 big 99.7 big<!--</th--><th>Including 99.8 99.4 99.2 98.4 94.1 82.8 43.2 8.3 Normal Battery +0.1/-0.1 +0.1/-0.2 +0.2/-0.2 +0.3/-0.3 +0.6/-0.6 +1.0/-1.1 +1.6/-1.6 +1.4/-1.3 Depletion *** *** *** *** *** *** ***</th><th>Excluding 100.0 99.9 99.9 99.9 99.9 99.6 Normal Battery +0.0/-0.0 +0.0/-0.1 +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 at 71 mo</th><th>Including Department 99.8 big 1.00 - 0.1 99.7 big 1.00 big 1</th><th>Excluding Department Pattery 99.9 99.8 99.8 99.7 99.7 99.7 99.7 99.7 Depletion Hould be propertion Hould be propertion Hould be propertied be propertied be propertied by properties by properties be properties be properties by properties be properties by properties be properties by properties by properties be properties by proper</th><th>Including 99.8 99.4 99.0 98.5 97.0 87.4 71.4 55.8 Normal Battery +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.3/-0.2 +0.3/-0.4 +0.7/-0.8 +1.4/-1.5 +2.9/-3.1 Depletion Depletion 40.3/-0.2 +0.3/-0.2 +0.3/-0.8 +1.4/-1.5 +2.9/-3.1</th><th>Excluding Normal Battery 100.0 99.9 99.9 99.9 99.9 Depletion +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0</th><th>Including 99.9 99.8 99.5 99.3 99.1 Normal Battery +0.0/-0.0 +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.2/-0.2</th><th>Excluding 99.9 99.8 99.7 99.5 99.3 99.1 99.0 98.8 98.8 Normal Battery +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.1/-0.2 +0.2/-0.3 +0.2/-0.3 +0.2/-0.3 Depletion at 105 mo</th><th>Including Depletion 99.7 99.4 98.8 97.8 95.5 89.3 75.7 44.5 12.6 Normal Battery Depletion +0.1/-0.1 +0.1/-0.1 +0.2/-0.2 +0.3/-0.3 +0.4/-0.4 +0.7/-0.7 +1.2/-1.2 +1.8/-1.8 +2.1/-1.9</th><th>Excluding 100.0 99.9 99.8 99.6 99.5 99.3 99.3 Normal Battery +0.0/-0.0 +0.0/-0.0 +0.0/-0.1 +0.1/-0.1 +0.1/-0.2 +0.1/-0.2 +0.1/-0.2 Depletion at 79 mo</th><th></th></th>	Including Depletion 99.3 by 3 by 3 by 1/0.01 98.9 by 3 by 3 by 1/0.02 98.7 by 3 by	Excluding Depletion 99.9 big 99.8 big 99.7 big </th <th>Including 99.8 99.4 99.2 98.4 94.1 82.8 43.2 8.3 Normal Battery +0.1/-0.1 +0.1/-0.2 +0.2/-0.2 +0.3/-0.3 +0.6/-0.6 +1.0/-1.1 +1.6/-1.6 +1.4/-1.3 Depletion *** *** *** *** *** *** ***</th> <th>Excluding 100.0 99.9 99.9 99.9 99.9 99.6 Normal Battery +0.0/-0.0 +0.0/-0.1 +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 at 71 mo</th> <th>Including Department 99.8 big 1.00 - 0.1 99.7 big 1.00 big 1</th> <th>Excluding Department Pattery 99.9 99.8 99.8 99.7 99.7 99.7 99.7 99.7 Depletion Hould be propertion Hould be propertion Hould be propertied be propertied be propertied by properties by properties be properties be properties by properties be properties by properties be properties by properties by properties be properties by proper</th> <th>Including 99.8 99.4 99.0 98.5 97.0 87.4 71.4 55.8 Normal Battery +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.3/-0.2 +0.3/-0.4 +0.7/-0.8 +1.4/-1.5 +2.9/-3.1 Depletion Depletion 40.3/-0.2 +0.3/-0.2 +0.3/-0.8 +1.4/-1.5 +2.9/-3.1</th> <th>Excluding Normal Battery 100.0 99.9 99.9 99.9 99.9 Depletion +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0</th> <th>Including 99.9 99.8 99.5 99.3 99.1 Normal Battery +0.0/-0.0 +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.2/-0.2</th> <th>Excluding 99.9 99.8 99.7 99.5 99.3 99.1 99.0 98.8 98.8 Normal Battery +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.1/-0.2 +0.2/-0.3 +0.2/-0.3 +0.2/-0.3 Depletion at 105 mo</th> <th>Including Depletion 99.7 99.4 98.8 97.8 95.5 89.3 75.7 44.5 12.6 Normal Battery Depletion +0.1/-0.1 +0.1/-0.1 +0.2/-0.2 +0.3/-0.3 +0.4/-0.4 +0.7/-0.7 +1.2/-1.2 +1.8/-1.8 +2.1/-1.9</th> <th>Excluding 100.0 99.9 99.8 99.6 99.5 99.3 99.3 Normal Battery +0.0/-0.0 +0.0/-0.0 +0.0/-0.1 +0.1/-0.1 +0.1/-0.2 +0.1/-0.2 +0.1/-0.2 Depletion at 79 mo</th> <th></th>	Including 99.8 99.4 99.2 98.4 94.1 82.8 43.2 8.3 Normal Battery +0.1/-0.1 +0.1/-0.2 +0.2/-0.2 +0.3/-0.3 +0.6/-0.6 +1.0/-1.1 +1.6/-1.6 +1.4/-1.3 Depletion *** *** *** *** *** *** ***	Excluding 100.0 99.9 99.9 99.9 99.9 99.6 Normal Battery +0.0/-0.0 +0.0/-0.1 +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 at 71 mo	Including Department 99.8 big 1.00 - 0.1 99.7 big 1.00 big 1	Excluding Department Pattery 99.9 99.8 99.8 99.7 99.7 99.7 99.7 99.7 Depletion Hould be propertion Hould be propertion Hould be propertied be propertied be propertied by properties by properties be properties be properties by properties be properties by properties be properties by properties by properties be properties by proper	Including 99.8 99.4 99.0 98.5 97.0 87.4 71.4 55.8 Normal Battery +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.3/-0.2 +0.3/-0.4 +0.7/-0.8 +1.4/-1.5 +2.9/-3.1 Depletion Depletion 40.3/-0.2 +0.3/-0.2 +0.3/-0.8 +1.4/-1.5 +2.9/-3.1	Excluding Normal Battery 100.0 99.9 99.9 99.9 99.9 Depletion +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.0	Including 99.9 99.8 99.5 99.3 99.1 Normal Battery +0.0/-0.0 +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.2/-0.2	Excluding 99.9 99.8 99.7 99.5 99.3 99.1 99.0 98.8 98.8 Normal Battery +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.1/-0.2 +0.2/-0.3 +0.2/-0.3 +0.2/-0.3 Depletion at 105 mo	Including Depletion 99.7 99.4 98.8 97.8 95.5 89.3 75.7 44.5 12.6 Normal Battery Depletion +0.1/-0.1 +0.1/-0.1 +0.2/-0.2 +0.3/-0.3 +0.4/-0.4 +0.7/-0.7 +1.2/-1.2 +1.8/-1.8 +2.1/-1.9	Excluding 100.0 99.9 99.8 99.6 99.5 99.3 99.3 Normal Battery +0.0/-0.0 +0.0/-0.0 +0.0/-0.1 +0.1/-0.1 +0.1/-0.2 +0.1/-0.2 +0.1/-0.2 Depletion at 79 mo	
rvival Pro	r Implan							-0.1				-0.1				
Device Su	Years Afte							-0.1			0.0		0.1			
													Excluding mal Battery Depletion			
100			ž	ž	ž	ž	Š	Š	Š	Š	Š	No	No	Š	ž	
US)	le:	тоТ	148 NG	ž	27 NG	N N	31 No		37 No	0 N	35		96 Nor	9 N	150	
nctions (US)	yqpy ton Noitor bəzimorqm ls	rui Coi				¥	21 = 31		27 = 37	ON.	25 = 35			ON.	75 = 150	1
Malfunctions (US)	otion Not mpromised	The Turi				J	31	(1) ted subset)	= 37	ON	= 35	= (0) ed subset)		ON.	= 150	į
Malfunctions (US)	mpromised erapy nction Not mpromised	The Col		1		load; — — —	+ 21 = 31	(1) (0) (1) (advisory-related subset)	+ 27 = 37		+ 25 = 35	$\begin{array}{rcl} (0) & + & (0) & = & (0) \\ (advisory-related subset) \end{array}$		ON	+ 75 = 150	<u> </u>
Malfunctions (US)	pletions (US) srapy Function mpromised srapy ortion Not mpromised	Act Mo Dell Dell The Col	148	1	27	load; — — —	10 + 21 = 31	(1) (0) (1) (advisory-related subset)	10 + 27 = 37		10 + 25 = 35	$\begin{array}{rcl} (0) & + & (0) & = & (0) \\ (advisory-related subset) \end{array}$	96 – –	ο _ν	75 + 75 = 150	6
Malfunctions (US)	ive US Splants real Battery pletions (US) pletions (US) mpromised mpromised verse basion Not notion Not mpromised	US Est Imp Moi Del The Coi The The	1,824 — — 148	1	1,932 — — 27	load; — — —	52 10 + 21 = 31	(1) (0) (1) (advisory-related subset)	795		47 10 + 25 = 35	$\begin{array}{rcl} (0) & + & (0) & = & (0) \\ (advisory-related subset) \end{array}$	1,370 — — 96	02	1,495 75 + 75 = 150	
Malfunctions (US)	imated sive US soloris soloris simal Battery pletions (US) solorised mpromised scion Not notion Mot motomised	Reg US Ling Mos Mos Cos The The The The Cos	3,000 1,824 — — 148	1	40 1,932 – – 27	load; — — —	9,000 52 10 + 21 = 31	(1) (0) (1) (advisory-related subset)	7,000 795 10 + 27 = 37		30,000 47 10 + 25 = 35	$\begin{array}{rcl} (0) & + & (0) & = & (0) \\ (advisory-related subset) \end{array}$	2,000 1,370 — — 96	ο _ν	15,000 1,495 75 + 75 = 150	<u> </u>
Malfunctions (US)	gistereed implants in a lead of the US of the	Reg US Ling Mos Mos Cos The The The The Cos	22,000 3,000 1,824 — — 148	Advisories: <u>See page 155</u> – 1999 Potential Circuit Overload	11,000 40 1,932 — — 27	Advisories: See page 155 – 1999 Potential Circuit Overload; Also see page 165 – Performance note on ICD Battery Discharge Behavior	19,000 9,000 52 10 + 21 = 31		17,000 7,000 795 10 + 27 = 37	See page 165 – Performance note on ICD Battery Discharge Behavior	43,000 30,000 47 10 + 25 = 35		15,000 2,000 1,370 — — 96	ο _ν	48,000 15,000 1,495 75 + 75 = 150	3

				ŀ	Malfunctions	ctior	S			Device S	Device Survival Probability (%)	robability	(%)					
	Narket sase	istered stafqm	bətsm ZU əvi stnsl	mal Battery sletions	rapy Function npromised	rapy ction Not	npromised	Įŧ		Years Af	Years After Implant	nt						
Family	NS I	I SN Bəy	ĵэA		The	edT Fun∃	רסו	tot		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
GEM III DR	Nov-00	20,000	2,000	3,471	+	30	II	14	Excluding Normal Battery Depletion	99.9	99.9	99.8 +0.1/-0.1	99.7 +0.1/-0.1	99.7 +0.1/-0.1	99.7 +0.1/-0.1			
See page 165 Discharge Be	See page 165 – Performance note on ICD Battery Discharge Behavior	ce note on l	CD Battery					-	Including Normal Battery Depletion	99.6 +0.1/-0.1	99.0	96.9 +0.3/-0.3	90.1	64.5 +1.0/-1.0	8.8 +1.2/-1.1			
GEM III AT	Feb-01	14,000	1,000	2,700	+ _	39	п	46	Excluding Normal Battery Depletion	99.9	99.9	99.7 +0.1/-0.1	99.5 +0.1/-0.2	99.5 +0.1/-0.2	99.5 +0.1/-0.2 at 69 mo			
See page 165 Discharge Be	See page 165 – Performance note on ICD Battery Discharge Behavior	ce note on l	ICD Battery					-	Including Normal Battery Depletion	99.6 +0.1/-0.1	98.8 +0.2/-0.2	96.1	84.6 +0.8/-0.8	50.5 +1.3/-1.3	3.7 +1.0/-0.8 at 69 mo			
Maximo DR	Oct-03	37,000	25,000	194	+ &	21	II	29	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9	99.9				
Advisories: S Battery Depl	Advisories: See page 153 – 2005 Potential Premature Battery Depletion Due to Battery Short	2005 Poter attery Shor	ntial Prematur t	ē	(0) + (advisory	+ $(0) = (0)sory-related subset)$	= d subs		Including Normal Battery Depletion	99.9	99.7	99.3	97.7 +0.3/-0.3	93.8 +1.1/-1.3				
Intrinsic	Aug-04	31,000	22,000	85	9	27	П	33	Excluding Normal Battery Depletion	100.0	99.9	99.9	99.8 +0.1/-0.1	99.8 +0.1/-0.1 at 51 mo				
								-	Including Normal Battery Depletion	99.9	99.7	99.4 +0.1/-0.1	98.2 +0.3/-0.4	97.8 +0.6/-0.8 at 51 mo				
Onyx	Mar-04	1,000	1,000	9	+	m	П	4	Excluding Normal Battery Depletion	99.9	99.5	99.5 +0.3/-0.8	99.5 +0.3/-0.8	99.5 +0.3/-0.8 at 49 mo				
								_	Including Normal Battery Depletion	99.8 +0.2/-0.7	99.0	98.4 +0.7/-1.2	96.4	96.4 +1.5/-2.4 at 49 mo				
EnTrust DR	Jun-05	400	300	7	+	2	Ш	m	Excluding Normal Battery Depletion	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.1 +0.6/-2.0	99.1 +0.6/-2.0 at 45 mo					
								-	Including Normal Battery Depletion	99.5 +0.4/-1.4	99.5	97.3 +1.3/-2.7	91.1 +3.4/-5.3 at 45 mo					
EnTrust DR	Jun-05	28,000	22,000	33	+ 9	4	П	20	Excluding Normal Battery Depletion	100.0	99.9	99.9	99.9 +0.1/-0.1 at 40 mo					
								-	Including Normal Battery Depletion	99.9	99.7	99.3 +0.1/-0.2	99.2 +0.2/-0.3 at 40 mo					

	C	D
_		

ility (%)		4yr 5yr 6yr 7yr 8yr	5,0	5	99.9 1 +0.1/-0.1 at 39 mo	99.6 2 +0.1/-0.2 at 39 mo										
Device Survival Probability (%)	plant	3 yr	99.7 +0.2/-0.5 at 29 mo	99.4 +0.3/-0.5 at 29 mo	99.9 +0.1/-0.1	99.6 +0.1/-0.2	5	.2								
Surviv	fter Im	2 yr	99.9	99.8 +0.0/-0.1	99.9	99.7	99.9	99.7								
Device	Years After Implant	1 yr	100.0	99.9	99.9 +0.0/-0.1	99.9 +0.0/-0.1	100.0	99.9 +0.0/-0.1	100.0 +0.0/-0.0 at 2 mo							
			Excluding Normal Battery Depletion	Including Normal Battery Depletion												
	Įe	toT	25		15		∞		0		0		0		0	
tions	rapy ction Not npromised	unⅎ	10 =		= 11		п М		0		0		0		0	
Malfunctions	rapy Function npromised	uoɔ	15 +		4		+		+		+		+		+	
	mal Battery snoisele		14		7		7		0		0		0		0	
	bətem ZU əvi stnslı	ЭA	26,000		11,000		24,000		1,000		1,000		1,000		400	
	istered mplants	I SN Bəy	62,000		14,000		26,000		1,000		1,000		1,000		400	
	Market ease	NS I	May-06		Jun-05		May-06		Aug-08		Aug-08		Mar-08		Mar-08	
		Family	Virtuoso DR		EnTrust VR		Virtuoso VR		Secura DR		Secura VR		Maximo II DR		Maximo II VR	
	-	Model Number	D154AWG D164AWG		D154VRC		D154VWC, D164VWC		D224DRG		D224VRC		D284DRG		D284VRC	



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

		Estimated Longevity					Elective	Replacement				
Model Number	Family	Connector Style	Volume/ Mass*	Delivered	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing		Charge Time ***(IN:	End of Life (EOL) Battery
7227	GEM GEM	B, Cx, D, E	49 cc* 90 g	Energy 35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	_	Voltage ≤ 2.40 V [§]
7229	GEM II VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.6 5.0 5.6	3.9 5.5 6.3	4.1 6.0 6.9	4.2 6.2 7.1	≤ 2.55 V	_	≤ 2.40 V
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231	GEM III VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	_	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V [§]
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7276	GEM III AT	DR	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.3 4.5	3.8 5.1 5.5	4.3 5.9 6.5	4.5 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7287	Intrinsic 30	DR	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.5 6.2	4.3 6.3 7.2	4.7 7.0 8.2	4.8 7.4 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.4 6.1	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V	> 16-second charge time	≤ 2.40 V

^{*} Volume and mass differ by connector style.

 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

^{‡‡} For Model 7223 devices, if charge time exceeds 60 seconds, the devices are at EOL. If two consecutive charge cycles exceed 60 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency output VVI pacing are disabled.

[§] For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If three consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.



Reference Chart continued

					Estimated Longevity						nmended	
					Charging Frequency**	, 10#	# 61	# 61	ing	(R	acement RT)***	- End of
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charg Frequ	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Service (EOS)
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D153VRC	EnTrust	Сх	32 cc 63 g	30 J	Monthly Quarterly Semiannual	4.4 6.8 7.9	4.7 7.4 8.7	4.9 7.9 9.5	5.0 8.1 9.8	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154AWG, D164AWG	Virtuoso	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D154VRC	EnTrust	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D224DRG	Secura DR	DR	37 cc 68 g	35J	Monthly Quarterly Semiannual	3.60 5.07 5.70	4.08 6.05 7.00	4.50 7.00 8.27	4.67 7.50 9.00	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D224VRC	Secura VR	Сх	37 cc 68 g	35J	Monthly Quarterly Semiannual	4.33 6.67 7.76	4.67 7.45 8.85	4.92 8.05 9.79	5.00 8.41 10.25	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D284DRG	Maximo II DR	DR	37 cc 68 g	35J	Monthly Quarterly Semiannual	3.60 5.07 5.70	4.08 6.05 7.00	4.50 7.00 8.27	4.67 7.50 9.00	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D284VRC	Maximo II VR	Сх	37 cc 68 g	35J	Monthly Quarterly Semiannual	4.33 6.67 7.76	4.67 7.45 8.85	4.92 8.05 9.79	5.00 8.41 10.25	≤ 2.63 V	_	3 months after RRT or > 19-second charge time

^{*} Volume and mass differ by connector style.

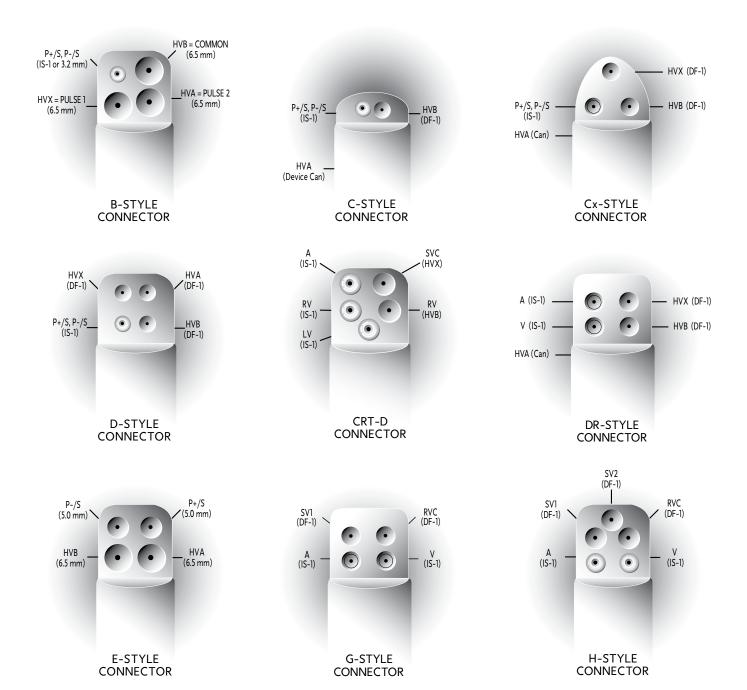
 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel.



ICD Connector Styles



Adapta DR ADDR01, ADDR03, ADDR06, ADD01

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	10	NBG Code	DDDR, DDD
Registered US Implants	116,000	Therapy Function Not Compromised	6	Serial Number Prefix	PWB, PWD,
Estimated Active US Implants 104,00		Electrical Component	6		PWC, PWF, NWB, NWC,
Normal Battery Depletions (US)	1	Therapy Function Compromised	4		NWD
Advisories	None	Electrical Component	4	Estimated Longevity	See page 77



Adapta DR ADDRL1

Product Characteristics

ı	US Market Release Jul-06					Malfunctions (US)				NBG Code			DDDR
F	Regist	ered US Impla	ants	11,000) Th	erapy Functio	n Not Compr	omised	0	Serial Number Prefix			PWE, NWE
E	Estima	ted Active US	S Implants	10,000) Th	erapy Functio	n Compromis	sed	0				
1	Norma	al Battery Dep	oletions (US)	()					Estimat	ed Longevity		See page 77
,	Advisc	ories		None	9								
(%)	100 =												
	90 -												
abil													
rob	80												
valF	0	1	2	2 3		4	5	6	7	8	3) 1	0
urvi		Years After	Implant	Exc	luding N	ormal Battery	Depletion	Ind	ludin	ig Norma	l Battery De	pletion	
Device Survival Probability			1 yr	2 yr									
Oevi	%		100.0	100.0									
_	%		100.0	100.0									

200

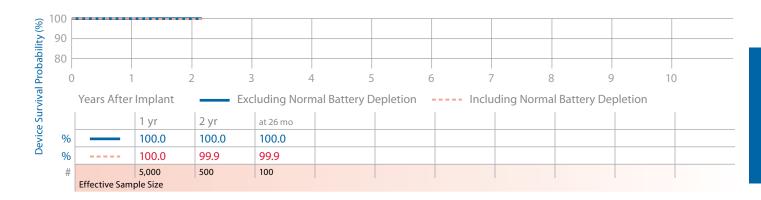
4,000

Effective Sample Size



Adapta DR ADDRS1

•					
US Market Release	Jul-06	Malfunctions (US)	1	NBG Code	SSIR
Registered US Implants	10,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWA
Estimated Active US Implants	9,000	Therapy Function Compromised	1		
Normal Battery Depletions (US)	1	Electrical Component	1	Estimated Longevity	See page 77
Advisories	None				



Adapta SR ADSR01, ADSR03, ADSR06

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	0	NBG Code	SSIR
Registered US Implants	22,000	Therapy Function Not Compromised	0	Serial Number Prefix	NWN, NWM,
Estimated Active US Implants	19,000	Therapy Function Compromised	0		NWP
Normal Battery Depletions (US)	1			Estimated Longevity	See page 77
Advisories	None				



Adapta VDD ADVDD01

Product Characteristics

JS Market Release		Jul-06	Malfun	ctions (US)			0	NBG Co	de		VDO
Registered US Impl	lants	400	Thera	py Function N	ot Compron	ised	0	Serial N	umber Prefix	(PWG, NWC
Estimated Active U	S Implants	400	Thera	py Function C	ompromised		0	Estimate	ed Longevity	/	See page 7
Normal Battery De	pletions (US)	0									
Performance Note: Performance note on System Follow-Up Pro	AT500 Pacing										
100											
90											
80											
0	1 2	2 3		5	6		7	8	3	9	10
Years After		1	uding Norn	nal Battery De	epletion •	Inclu	uding	g Norma	l Battery De	epletion	
	1 yr	at 16 mo	uding Norn	nal Battery De	epletion •	Inclu	uding	g Norma	l Battery De	epletion	
Years After		1	uding Norn	nal Battery De	epletion	Inclu	uding	g Norma	l Battery De	epletion	

AT500 AT501, 7253 Product Characteristics

US M	arket Release		Mar-0	3 Malf	unctions (US)			10	NBG Code		DDDRP			
Regis	tered US Impla	ants	11,00	0 The	rapy Function	Not Compre	omised	5	Serial Number Pre	efix	IJF			
Estim	ated Active US	S Implants	5,00	0	Electrical Comp	onent		2	Estimated Longev	/ity	See page 77			
Norm	al Battery Dep	oletions (US)	48	1	Possible Early E	Battery Deple	etion	3						
Perfo	rmance Note:	See page 163 -	-	The	rapy Function	Compromis	ed	5						
	mance note on a n Follow-Up Pro			I	Electrical Comp	onent		3						
				ı	Electrical Interd	connect		1						
	Possible Early Battery Depletion 1													
= 100														
% 90 £														
abilit 80														
oba														
4 Page 70														
₹ 60						1								
e Su						•								
Device Survival Probability (%) 00 00 00 00 00 00 00 00 00 00 00 00 00	0 1	1	2 :	3	4	5	6	7	8	9	10			
	Years After	Implant	Exc	cluding No	rmal Battery I	Depletion	Ir	ncludin	g Normal Battery	Depletion				
		1 yr	2 yr	3 yr	4 yr	5 yr	at 67 mo							
%		100.0	100.0	100.0	99.9	99.9	99.9							
%		99.9	99.9	99.5	97.5	83.8	57.2							
#		10,000	9,000	8,000	6,000	2,000	100							
	Effective Sam	ple Size												

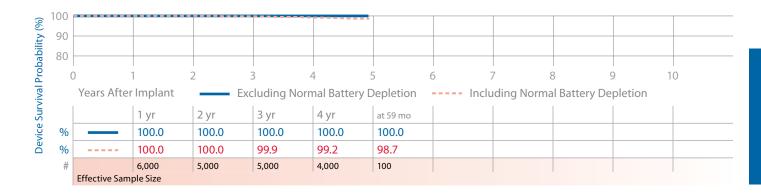


Advisories

EnPulse DR E1DR01, E1DR03, E1DR06

Product Characteristics

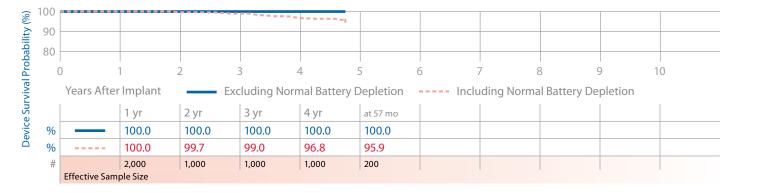
US Market Release	Dec-03	Malfunctions (US)	1	NBG Code	DDDR
Registered US Implants	7,000	Therapy Function Not Compromised	1	Serial Number Prefix	PRA
Estimated Active US Implants	4,000	Electrical Component	1	Estimated Longevity	See page 77
Normal Battery Depletions (US)	26	Therapy Function Compromised	0		
Advisories	None				



EnPulse DR E1DR21 **Product Characteristics**

None

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	DDDR
Registered US Implants	2,000	Therapy Function Not Compromised	0	Serial Number Prefix	PPT
Estimated Active US Implants	1,000	Therapy Function Compromised	0	Estimated Longevity	See page 77
Normal Battery Depletions (US)	23				



EnPulse 2 DR E2DR01, E2DR03, E2DR06

US Market Release	Feb-04	Malfunctions (US)
Registered US Implants	101,000	Therapy Function Not Compromised
Estimated Active US Implants	70,000	Electrical Component
Normal Battery Depletions (US	5) 81	Possible Early Battery Depletion
Advisories	None	Therapy Function Compromised

Product Characteristics

13

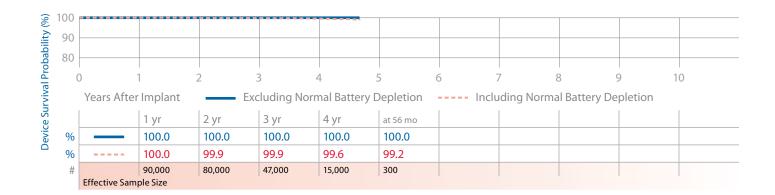
10 9

3

2

0

NBG Code	DDDR
Serial Number Prefix	PNB, PNC, PNH
Estimated Longevity	See page 77



Battery

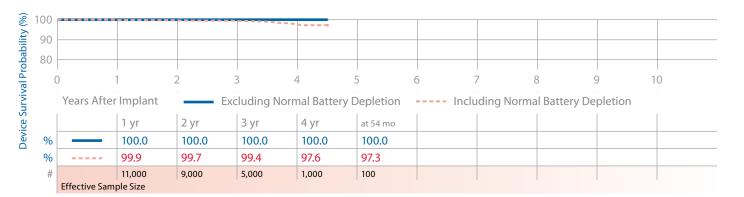
Electrical Component

EnPulse 2 DR E2DR21

US Market Release Feb-04 Registered US Implants 12,000 Estimated Active US Implants 8,000 Normal Battery Depletions (US) 48 Advisories None

Malfunctions (US) Therapy Function Not Compromised Therapy Function Compromised Electrical Component

NBG Code DDDR Serial Number Prefix PMU Estimated Longevity See page 77



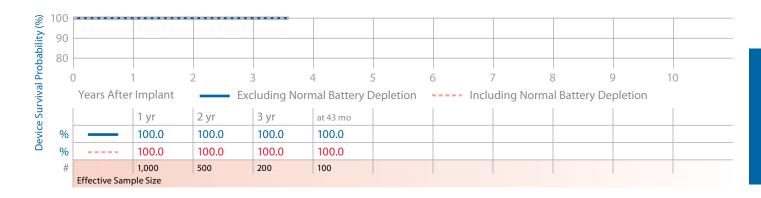


EnPulse 2 DR E2DR31, E2DR33

Product Characteristics

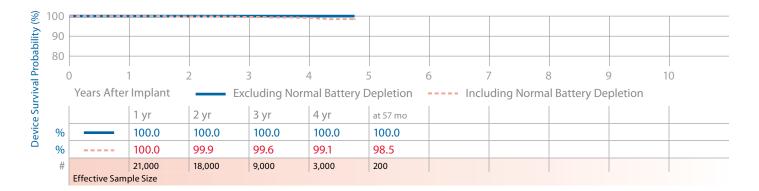
US Market Release	Feb-04	Malfunctions (US)
Registered US Implants	1,000	Therapy Function Not Compromised
Estimated Active US Implants	400	Therapy Function Compromised
Normal Battery Depletions (US)	0	
Advisories	None	

inctions (US)	0	NBG Code	DDDR
apy Function Not Compromised	0	Serial Number Prefix	PNL
apy Function Compromised	0	Estimated Longevity	See page 77



EnPulse 2 SR E2SR01, E2SR03, E2SR06

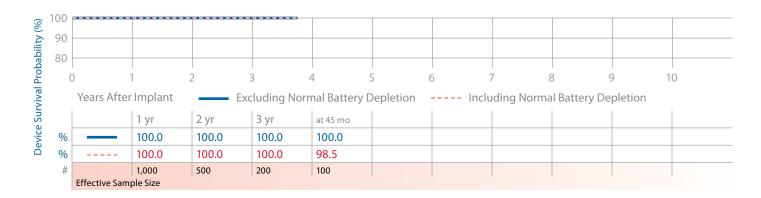
US Market Release	Dec-03	Malfunctions (US)	3	NBG Code	SSIR
Registered US Implants	25,000	Therapy Function Not Compromised	2	Serial Number Prefix	PMW, PMY,
Estimated Active US Implants	15,000	Electrical Component	1		PNA
Normal Battery Depletions (US)	42	Possible Early Battery Depletion	1	Estimated Longevity	See page 77
Advisories	None	Therapy Function Compromised	1		
		Other	1		



EnPulse 2 VDD E2VDD01

Product Characteristics

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PMV
Estimated Active US Implants	500	Therapy Function Compromised	0	Estimated Longevity	See page 77
Normal Battery Depletions (US)	1				
Advisories	None				



EnRhythm DR P1501DR

JS Market Release	May-05	Malfu	Malfunctions (US)			30	NBG Co	de		DDDRP
Registered US Implants 78,000 Therapy Funct				n Not Comp	romised	5	Serial N	umber Prefix	x	PNP
Estimated Active US Implants	62,000	El	ectrical Com	nponent		5	Estimate	ed Longevit	у	See page 7
Normal Battery Depletions (US)	4	Thera	apy Function	n Compron	ised	25				
Advisories	None	El	ectrical Com	nponent		23				
		Po	ossible Early	Battery De	oletion	1				
100										
100										
90										
90										
	2 3		4	5	6	7	8	}	9	10
80		uding Nori	4 mal Battery	5 Depletion		7 Includir		Battery D		10
0 1 2	Excl	uding Nori 3 yr	4 at 43 mo	5 Depletion		7 Includir				10
0 1 2 Years After Implant	Excl	_	1	5 Depletion		7 Includir				10
0 1 2 Years After Implant	Exclusion 2 yr 100.0	3 yr	at 43 mo	5 Depletion		7 Includir				10



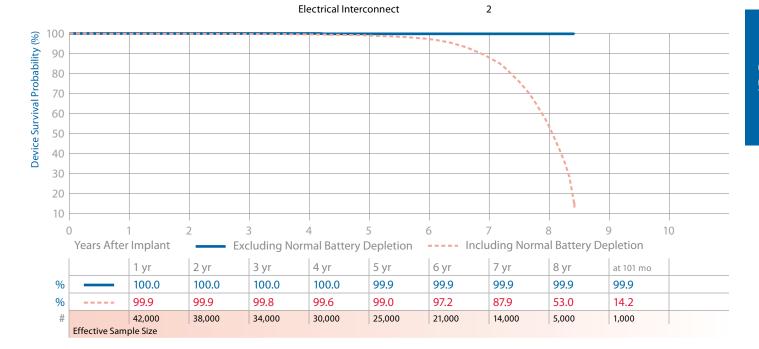
Kappa 400 DR KDR401, KDR403

US Market Release	Jan-98	Malfunctions (US)	22
Registered US Implants	47,000	Therapy Function Not Compromised	13
Estimated Active US Implants	5,000	Electrical Component	9
Normal Battery Depletions (US)	5,271	Electrical Interconnect	1
Advisories	None	Possible Early Battery Depletion	2
		Other	1
		Therapy Function Compromised	9

Product Characteristics

7

NBG Code	DDD/RO
Serial Number Prefix	PER, PET
Estimated Longevity	See page 77



Electrical Component

Kappa 400 SR KSR401, KSR403

Product Characteristics

app	a 400 SR K	(SR401, KSR	403						Produc	t Characteri	stics	
US I	Market Release Feb-98			Malfur	ctions (US)			5	NBG Co	de		SSI/R
Reg	istered US Impl	lants	15,000	Thera	py Function	Not Compro	nised	4	Serial N	umber Prefix		PEU, PGD
Esti	mated Active U	S Implants	2,000	Ele	ectrical Comp	onent		3	Estimat	ed Longevity		See page 77
Nor	mal Battery De	pletions (US)	870	Po	ssible Early B	attery Deplet	ion	1				
Adv	risories		None	Thera	py Function	Compromise	d	1				
				Ele	ectrical Interc	onnect		1				
<u>ş</u> 10	0											
9	0							-				
Device Survival Probability (%)	0											
<u>2</u> 7	0								**	.		
≥ 6	0									1		
2 nc	0											
7 JUG 7												
Dev										1		
3											1.	
2	0										1	
1	0											
	0		2 3				6	7	,	-	9	10
	Years After	r Implant	Excl	uding Norn	nal Battery [Depletion	Inclu	ıdin	g Norma	al Battery De	pletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 y	r	8 yr	9 yr	at 111 mo
g	/o 	100.0	100.0	100.0	100.0	100.0	99.9	99.	9	99.9	99.9	99.9

99.2

7,000

97.8

5,000

92.9

4,000

600 DD

Effective Sample Size

99.9

13,000

99.9

11,000

99.8

10,000

99.5

8,000

%

Dua du at Ch

70.3

2,000

32.6

300

20.3

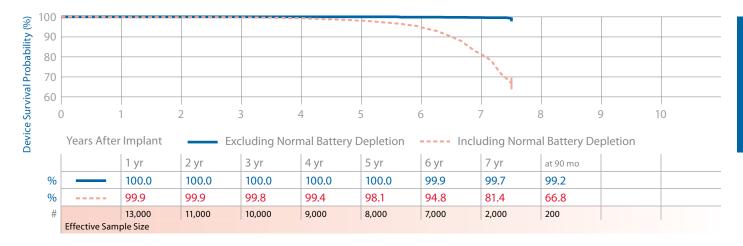
100

US Market Release Jan-99			set Release Jan-99 Malfunctions (US) 33				33	NBG Co	de	DDD/RO		
Registered US Implants 24,000			0 Th	Therapy Function Not Compromised Electrical Component				Serial Number Prefix			PHF, PHH, PHG	
Estima	stimated Active US Implants 2,000											
Norma	al Battery De	pletions (US)	2,41	7 Th	erapy Functio	n Compromis	ed	30	Estimat	ed Longevity		See page 7
Advisories: See page 154 – 2002 Potential Fractured Power Supply Wires				Electrical Cor Electrical Inte (15 malfunction	-	ory)	2 28					
100							- L _					
90												
80								***				
70												
60												
										1		
50										1		
40												
30												
20										\ \ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\		
10										1		
()	1 :	2	3	4	5	6	7	8	3	9	10
	Years After	r Implant	Ex	cluding No	ormal Batter	y Depletion	Ir	ncluding	g Norma	al Battery De	pletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yı	r	8 yr	at 106 mo	
%		100.0	100.0	100.0	99.9	99.9	99.9	99.	8	99.7	99.7	
%		99.9	99.9	99.8	99.5	98.8	96.8	87.9)	58.9	15.5	
#		21,000	19,000	17,000	15,000	13,000	12,000	9,00	0	3,000	200	



Kappa 600 DR KDR651, KDR653

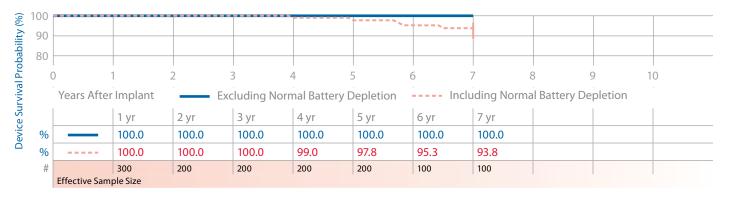
US Market Release	Mar-01	Malfunctions (US)	19	NBG Code	DDD/RO
Registered US Implants	14,000	Therapy Function Not Compromised	2	Serial Number Prefix	PLJ, PLK
Estimated Active US Implants	5,000	Electrical Component	1	Estimated Longevity	See page 77
Normal Battery Depletions (US)	569	Possible Early Battery Depletion	1		
Advisories: See page 154 – 2002 Po	tential	Therapy Function Compromised	17		
Fractured Power Supply Wires		Electrical Component	1		
		Electrical Interconnect (1 malfunction related to advisory)	16		



Kappa 700 D KD701, KD703, KD706

• •					
US Market Release	Jan-99	Malfunctions (US)	0	NBG Code	DDD
Registered US Implants	300	Therapy Function Not Compromised	0	Serial Number Prefix	PHK
Estimated Active US Implants	100	Therapy Function Compromised	0	Estimated Longevity	See page 78
Normal Battery Depletions (US)	11				

Advisories: See page 154 – 2002 Potential Fractured Power Supply Wires



Product Characteristics

Feb-99

192,000

54,000

12,539



US Market Release

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

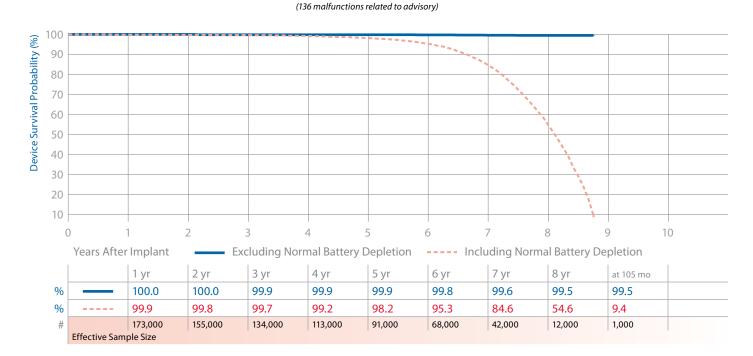
Fractured Power Supply Wires

Kappa 700 DR KDR701, KDR703, KDR706

Advisories: See page 154 – 2002 Potential

351
28
1
21
1
3
2
323
15
308

NBG Code	DDD/RO
Serial Number Prefix	PGU, PGY, PGW
Estimated Longevity	See page 78



DDD/RO

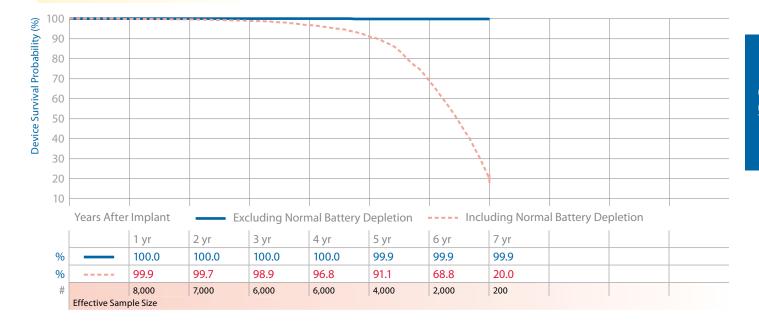
See page 78

PGR



Kappa 700 DR KDR721

US Market Release	Feb-99	Malfunctions (US)	5	NBG Code
Registered US Implants	10,000	Therapy Function Not Compromised	1	Serial Number Prefix
Estimated Active US Implants	100	Electrical Component	1	Estimated Longevity
Normal Battery Depletions (US)	1,237	Therapy Function Compromised	4	
Advisories: See page 154 – 2002 Fractured Power Supply Wires	Potential	Electrical Interconnect (4 malfunctions related to advisory)	4	



Kappa 700 SR KSR701, KSR703, KSR706

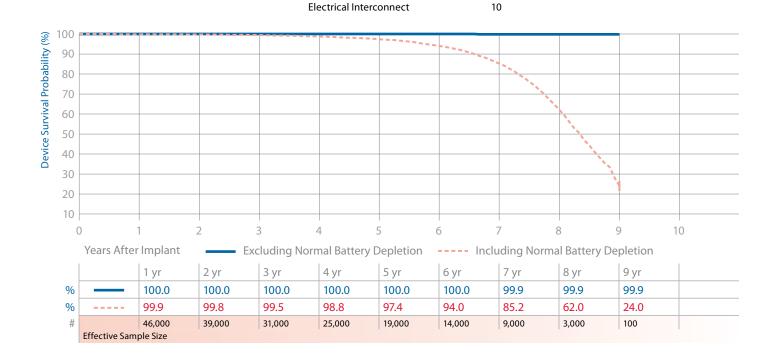
Product Characteristics

17 3 2

4

US Market Release	Feb-99	Malfunctions (US)
Registered US Implants	55,000	Therapy Function Not Compromised
Estimated Active US Implants	13,000	Electrical Component
Normal Battery Depletions (US)	2,265	Possible Early Battery Depletion
Advisories	None	Therapy Function Compromised
		Electrical Component

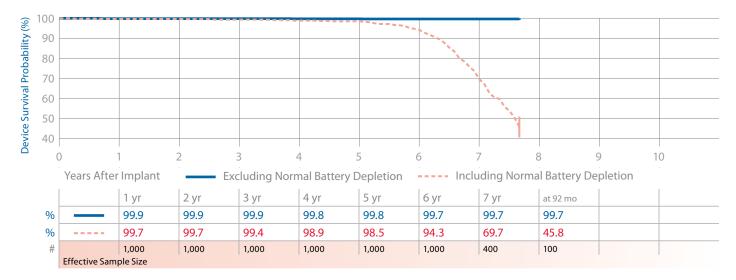
NBG Code	SSI/R
Serial Number Prefix	PHT, PHW, PHU
Estimated Longevity	See page 78



Kappa 700 VDD KVDD701

Fractured Power Supply Wires

US Market Release	Jan-99	Malfunctions (US)	3	NBG Code	VDD/RO
Registered US Implants	2,000	Therapy Function Not Compromised	0	Serial Number Prefix	PHP
Estimated Active US Implants	100	Therapy Function Compromised	3	Estimated Longevity	See page 78
Normal Battery Depletions (US)	149	Electrical Interconnect	3		
Advisories: See page 154 – 2002 Por	tential	(3 malfunctions related to advisory)			



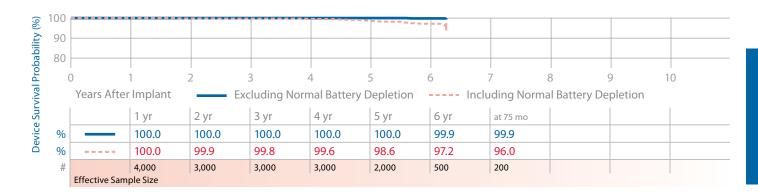


Kappa 800 DR KDR801, KDR803

US Market Release Jan-02 Registered US Implants 4,000 Estimated Active US Implants 2,000 Normal Battery Depletions (US) 27 Advisories None

Product Characteristics

Malfunctions (US)	1	NBG Code	DDD/RO
Therapy Function Not Compromised	0	Serial Number Prefix	PKW, PKY
Therapy Function Compromised	1	Estimated Longevity	See page 78
Electrical Interconnect	1		

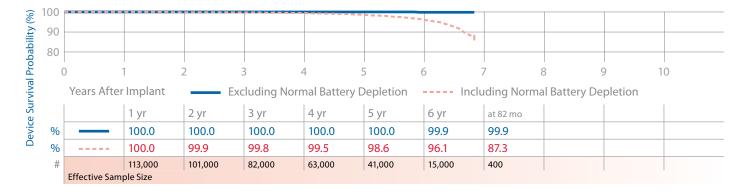


Kappa 900 DR KDR901, KDR903, KDR906

US Market Release Jan-02 Registered US Implants 125,000 Estimated Active US Implants 70,000 Normal Battery Depletions (US) 907 Advisories None

Malfunctions (US)	36
Therapy Function Not Compromised	12
Electrical Component	12
Therapy Function Compromised	24
Electrical Component	8
Electrical Interconnect	16

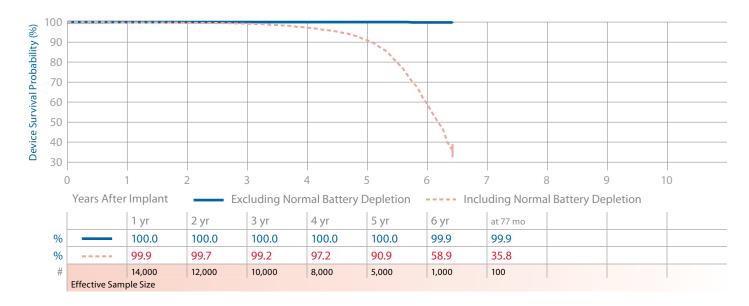
NBG Code DDD/RC)
Serial Number Prefix PKM, PK PKP	N,
Estimated Longevity See pag	e 78



Kappa 920 DR KDR921

Product Characteristics

US Market Release	Jan-02	Malfunctions (US)	3	NBG Code	DDD/RO
Registered US Implants	16,000	Therapy Function Not Compromised	0	Serial Number Prefix	PKR
Estimated Active US Implants	6,000	Therapy Function Compromised	3	Estimated Longevity	See page 78
Normal Battery Depletions (US)	902	Electrical Interconnect	3		
Advisories	None				



anna 900 SR KSROOT KSROOZ KSROOG

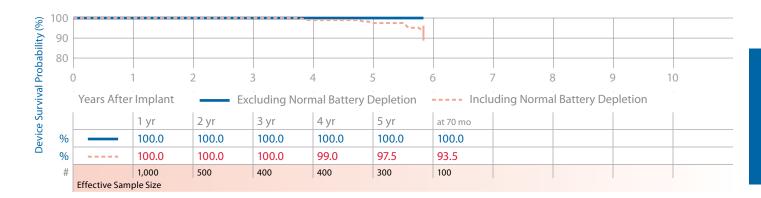
ppa	900 SK K	SR901, KSF	1903, KSR90	6					Product Char	racteristics	
US Ma	rket Release		Jan-()2 N	Malfunctions (US	5)		11	NBG Code		VVEV
Regist	ered US Impl	ants	37,00	00	Therapy Function	on Not Com	promised	8	Serial Number	Prefix	PLF, PLG,
Estima	ated Active U	S Implants	17,00	00	Electrical Co	mponent		7			PLH
Norma	al Battery De _l	pletions (US)	24	10	Possible Earl	y Battery De	pletion	1	Estimated Lon	gevity	See page 7
Adviso	ories		Nor	ne	Therapy Function	on Compron	nised	3			
					Electrical Int	erconnect		3			
90								1			
90 80 0)	1	2	3	4	5	6	7	8	9	10
	Years After	Implant	Ex	cluding	Normal Batter	y Depletion	1 I	ncludir	ng Normal Batte	ery Depletion	1
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at	81 mo		
%		100.0	100.0	100.0	100.0	99.9	99.9	99	0.8		
0/0		999	99.8	99.7	99.0	97.5	95.1	22	2.0		



Kappa 900 VDD KVDD901

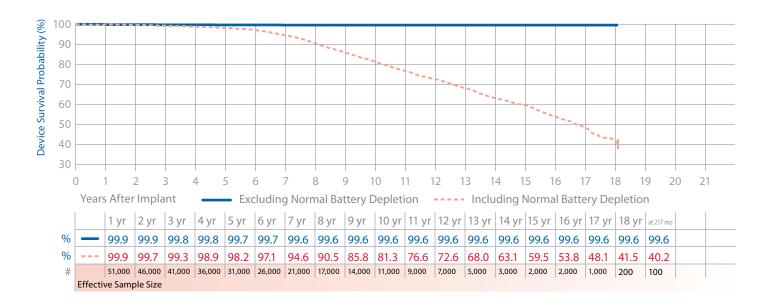
Product Characteristics

US Market Release	Jan-02	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PLE
Estimated Active US Implants	300	Therapy Function Compromised	0	Estimated Longevity	See page 78
Normal Battery Depletions (US)	9				
Advisories	None				



Legend 8416, 8417, 8417M, 8418, 8419

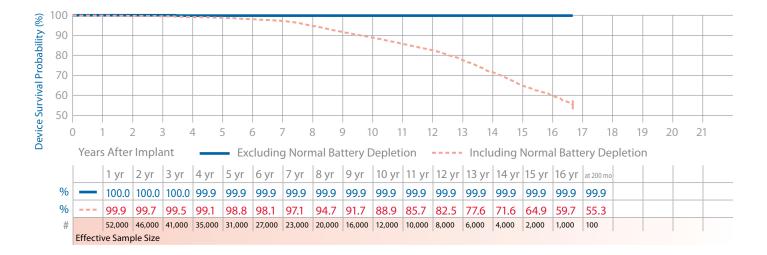
US Market Release	Aug-89	Malfunctions (US)	143	NBG Code	SSIRO
Registered US Implants	57,000			Serial Number Prefix	XT, WJ, WN,
Estimated Active US Implants	2,000				ZT
Normal Battery Depletions (US)	2,900			Estimated Longevity	See page 78
Advisories	None				



Legend II 8424, 8426, 8427

Product Characteristics

US Market Release	Nov-91	Malfunctions (US)	36	NBG Code	SSIRO
Registered US Implants	59,000			Serial Number Prefix	2P, 2T, 2U
Estimated Active US Implants	4,000			Estimated Longevity	See page 78
Normal Battery Depletions (US)	2,203				
Advisories	None				

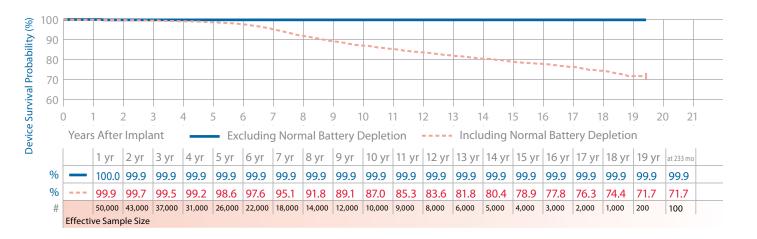


Minix/Minix ST 8330, 8331, 8331M, 8340, 8341, 8341M, 8342

Product Characteristics

US Market Release	Dec-89	Malfunctions (US)	49	NBG Code	SSIRO
Registered US Implants	58,000			Serial Number Prefix	2P, 2T, 2U
Estimated Active US Implants	4,000			Estimated Longevity	See page 78
Normal Battery Depletions (US)	1,594				

Advisories: See page 159 – 1991 Potential Delayed Restoration of Permanent Settings



None

None

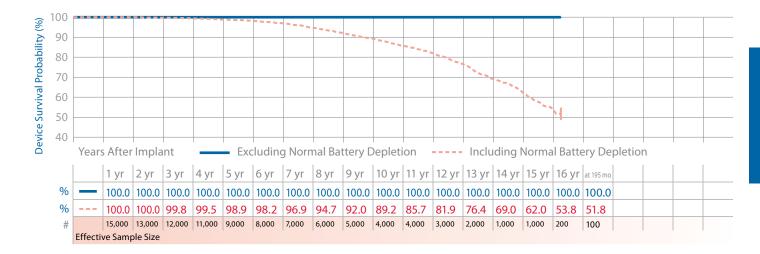


Minuet 7107, 7108

Advisories

Product Characteristics

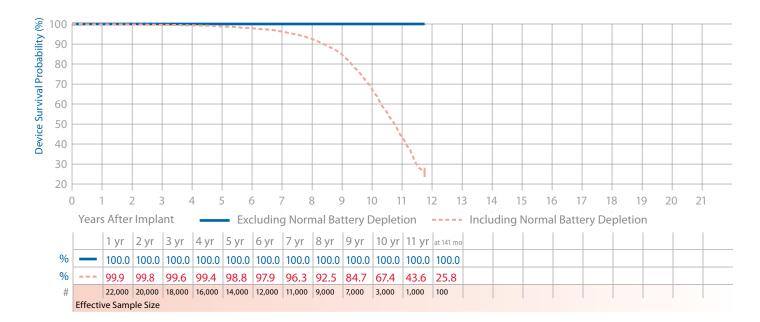
US Market Release	Mar-92	Malfunctions (US)	4	NBG Code	DDDCO
Registered US Implants	17,000			Serial Number Prefix	1Z1, 2G1
Estimated Active US Implants	1,000			Estimated Longevity	See page 78
Normal Battery Depletions (US)	762				



Preva DR 7088, 7089

Advisories

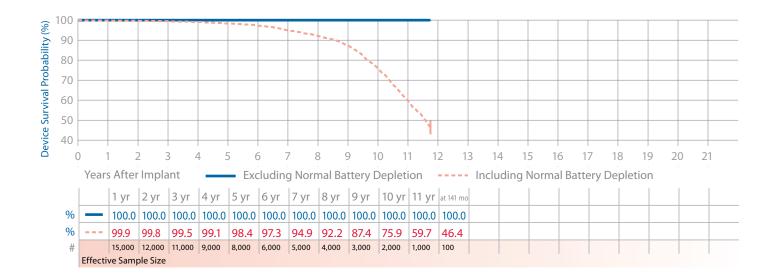
US Market Release	Jul-96	Malfunctions (US)	4	NBG Code	DDD/RO
Registered US Implants	26,000			Serial Number Prefix	PGJ, PGK
Estimated Active US Implants	3,000			Estimated Longevity	See page 78
Normal Battery Depletions (US)	1,828				



Preva SR 8088, 8089

Product Characteristics

US Market Release	Jul-96	Malfunctions (US)	1	NBG Code	SSI/R
Registered US Implants	18,000			Serial Number Prefix	PGL, PGM
Estimated Active US Implants	2,000			Estimated Longevity	See page
Normal Battery Depletions (US)	687				
Advisories	None				



Prevail S 8085, 8086

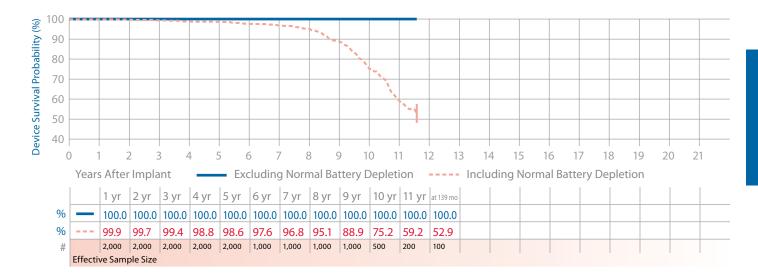
US Ma	arket Re	elease				Oct-9	5	Malfur	nctions	(US)				1		NBG Co	ode				SS	SI	
Regist	tered U	S Impl	ants			4,00	0									Serial N	lumbe	r Prefi	ix		PGL, PGM		
Estima	ated Ad	tive U	S Impla	nts		1,00	0									Estima	ted Loi	ngevit	y		Se	ee page 7	
Norm	al Batte	ery Dep	oletion	s (US)		3	8																
Advis	ories					Non	e																
100																	1						
90 80																							
() 1	2	2 3	3 4	1 5	5 6	5 7	7 8	3 9	9 1	0 1	1 1	2 1	3 14	1	15 1	6	17	18	19	20	21	
	Years	After	Impla	int		- Exc	luding	g Norn	nal Ba	ttery [Deplet	ion		Inclu	ding	Norma	al Batt	ery D	eple	tion			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 141 mo										
%	_	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9										
%		99.9	99.9	99.8	99.8	99.1	98.9	98.1	97.2	95.4	93.5	90.4	89.7										
#		3,000	3,000	2,000	2,000	1,000	1,000	1,000	1,000	1,000	1,000	300	100										
	Effectiv	ve Samp	ole Size																				



Prodigy D 7864, 7865, 7866

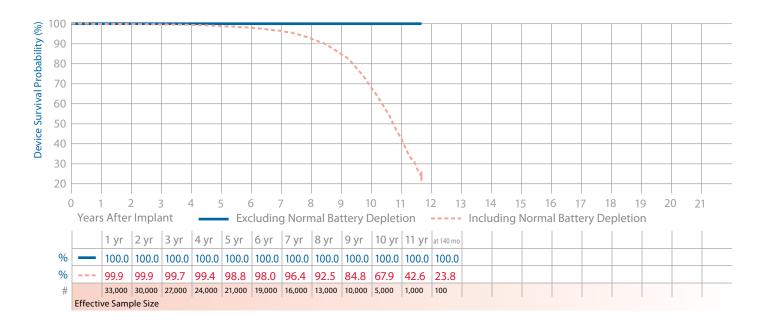
Product Characteristics

US Market Release	Oct-95	Malfunctions (US)	0	NBG Code	DDDCO
Registered US Implants	3,000			Serial Number Prefix	PDL, PDM,
Estimated Active US Implants	300				PDN
Normal Battery Depletions (US)	160			Estimated Longevity	See page 79
Advisories	None				



Prodigy DR 7860, 7861, 7862

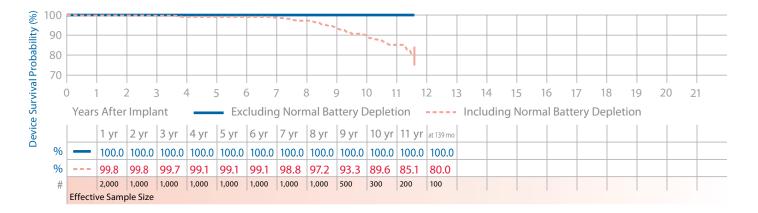
US Market Release	Oct-95	Malfunctions (US)	11	NBG Code	DDD/RO
Registered US Implants	38,000			Serial Number Prefix	PDH, PDJ,
Estimated Active US Implants	4,000				PDK
Normal Battery Depletions (US)	2,522			Estimated Longevity	See page 79
Advisories	None				



Prodigy S 8164, 8165, 8166

Product Characteristics

US Market Release	Oct-95	Malfunctions (US)	0	NBG Code	SSIC
Registered US Implants	2,000			Serial Number Prefix	PEG, PEH,
Estimated Active US Implants	300				PEJ
Normal Battery Depletions (US)	41			Estimated Longevity	See page 79
Advisories	None				



Prodigy SR 8158, 8160, 8161, 8162

Effective Sample Size

US Ma	arket Re	elease				Oct-9	5	Malfur	nctions	(US)				4	1	NBG C	ode					SSI/R	
Regist	tered U	IS Impl	ants			22,00	0									Serial	Numb	er Pre	fix			PEM, I	
Estima	ated A	ctive U	S Impla	ants		3,00	0														PEE, PEF		EF
Norm	al Batte	ery Dep	oletion	s (US)		83	6									Estima	ated Lo	ongev	ity			See pa	age 79
Adviso	ories					Non	e																
100																							T
90 80 70 60 40																							
80																							
70																							
60											1												
50												1											
40																							
) 1	 5) :] }	1 5	5 6	5 7	l 7 {	3 ()) 1	0 1	1 1	2 1	1 1 3 14	4	15	16	17	18	19	20) 2	1
	Years	After	Impla	nt					nal Ba			ion			din	g Norm		terv l					
					4 yr		6 yr						12 yr								1		
%		-	100.0	i e	100.0	-	-	100.0		-		-	100.0										
%		99.8	99.6		98.8	98.0	97.0	95.3	92.2	86.6			50.6	49.7									
#					11,000			7,000	5,000			1,000	100	100									



Sensia DR SEDR01, SED01

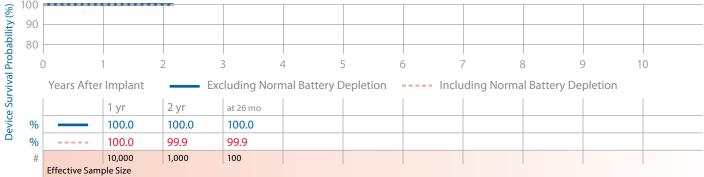
Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	1	NBG Code	DDD, DDDR
Registered US Implants	42,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWL, PWK,
Estimated Active US Implants 37,00		Therapy Function Compromised	1		NWL
Normal Battery Depletions (US)	0	Electrical Component	1	Estimated Longevity	See page 79
Advisories	None				



Sensia SR SESR01, SES01

US Market Release	Jul-06	Malfunctions (US)	0	NBG Code	SSIR, SSI
Registered US Implants	26,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWR, PWS,
Estimated Active US Implants	22,000	Therapy Function Compromised	0		NWR
Normal Battery Depletions (US)	1			Estimated Longevity	See page 79
Advisories	None				
_ 100					



Aug-99

1,000

200

5

Sigma 100 S SS103, SS106

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

US Market Release

Malfunctions (US)	0	NBG Code	SSI
Therapy Function Not Compromised	0	Serial Number Prefix	PJG, PJH
Therapy Function Compromised	0	Estimated Longevity	See page 79

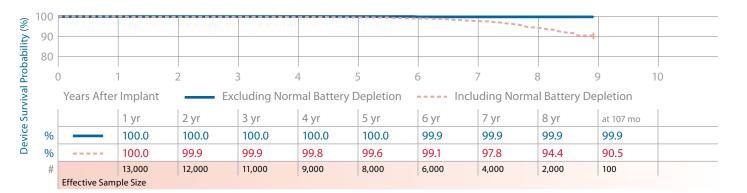
Product Characteristics

Advisories: See page 152 – 2005 Potential Separation of Interconnect Wires

100											
								•			
90 80											
	0	1	2	3	4	5	6	7	8	9 1	0
>	Years After Implant Excluding Normal Battery Depletion Including Normal Battery Depletion										
5		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 87 mo		
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0		
š %		100.0	100.0	99.6	99.6	98.7	98.7	97.5	97.5		
#		1,000	500	400	300	200	200	100	100		
	Effective Sam	ple Size									

Sigma 200 DR SDR203

US Market Release NBG Code DDD/RO Aug-99 Malfunctions (US) 6 **Therapy Function Not Compromised** Serial Number Prefix PJD Registered US Implants 16,000 1 **Estimated Active US Implants** 6,000 **Electrical Component** 1 **Estimated Longevity** See page 79 Normal Battery Depletions (US) 5 117 **Therapy Function Compromised** Advisories: See page 152 – 2005 Potential **Electrical Component** 1 Separation of Interconnect Wires **Electrical Interconnect** 4 (2 malfunction related to advisory)





Sigma 200 SR SSR203

	US Market Release	Sep-99	Malfunctions (US)
	Registered US Implants	12,000	Therapy Function Not Compromis
	Estimated Active US Implants	4,000	Therapy Function Compromised
	Normal Battery Depletions (US)	65	Electrical Interconnect (4 malfunctions related to advisory)

Advisories: See page 152 – 2005 Potential Separation of Interconnect Wires

Product Characteristics

6	NBG Code	SSI/R
0	Serial Number Prefix	PJG
6	Estimated Longevity	See page 79

§ 10	00									_	I	
	0											
robability 8 6	30											
Pro	() .	1 :	2 :	1 3 4	1 4	5 6	і б 7	7 8	3	9 1	0
vival		Years After	Implant	Exc	luding Norn	nal Battery [Depletion	Inclu	ding Norma	l Battery De	pletion	
Sur			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 106 mo	
Device	%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	
Õ	%		100.0	99.9	99.8	99.7	99.3	98.7	97.3	95.6	90.8	
	#		10,000	8,000	7,000	5,000	4,000	3,000	2,000	1,000	100	
		Effective Sam	ple Size									

Compromised

6

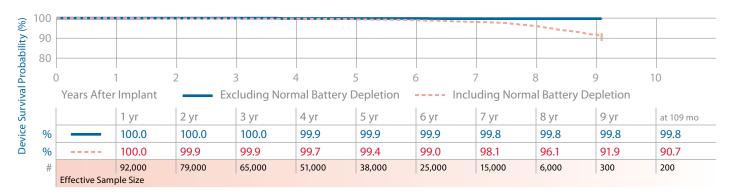
Sigma 300 DR SDR303, SDR306

US Market Release	Aug-99		
Registered US Implants	107,000		
Estimated Active US Implants	53,000		
Normal Battery Depletions (US)	394		
Advisories: See page 152 – 2005 Potential			

Separation of Interconnect Wires

Malfunctions (US)	76
Therapy Function Not Compromised	5
Electrical Component	4
Possible Early Battery Depletion	1
Therapy Function Compromised	71
Electrical Component	6
Electrical Interconnect (28 malfunctions related to advisory)	65

NBG Code	DDD/RO
Serial Number Prefix	PJD, PJE
Estimated Longevity	See page 79



Sigma 300 SR SSR303, SSR306

US Market Release	Sep-99
Registered US Implants	54,000
Estimated Active US Implants	20,000
Normal Battery Depletions (US)	191
Advisories: See page 152 – 2005 Pe	otential

Malfunctions (US)	15
Therapy Function Not Compromised	2
Electrical Component	1
Electrical Interconnect	1
Therapy Function Compromised	13
Electrical Component	3
Electrical Interconnect	10

(5 malfunctions related to advisory)

Product Characteristics

NBG Code	SSI/R
Serial Number Prefix	PJG, PJH
Estimated Longevity	See page 79

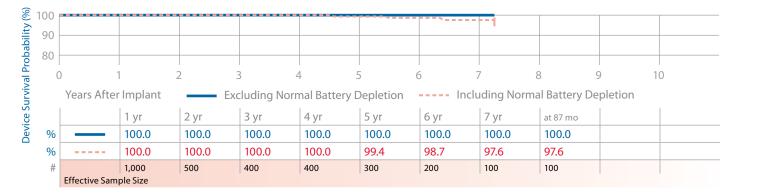
00											
90										1	
80											
			I		I	I			I		
_	1	1	2	2	/	5	6	7	8	9 1	10
0)	1	_	5	4	J	O	/	O		10
U	Years Afte	r Implant		S Excluding No	ormal Batter	y Depletion		rcluding Nor	mal Battery		10
		Implant 1 yr	2 yr	Excluding No	ormal Batter 4 yr	y Depletion 5 yr		ncluding Nor			
%	Years After		I	1	1.		In	1	rmal Battery	Depletion	
	Years After	1 yr	2 yr	3 yr	4 yr	5 yr	In	7 yr	rmal Battery	Depletion at 107 mo	

Sigma 300 VDD svDD303

US Market Release Sep-99 **Registered US Implants** 1,000 **Estimated Active US Implants** 200 Normal Battery Depletions (US) 5

Advisories: See page 152 – 2005 Potential Separation of Interconnect Wires

Malfunctions (US)	0	NBG Code	VDDD
Therapy Function Not Compromised	0	Serial Number Prefix	PJD
Therapy Function Compromised	0	Estimated Longevity	See page 79

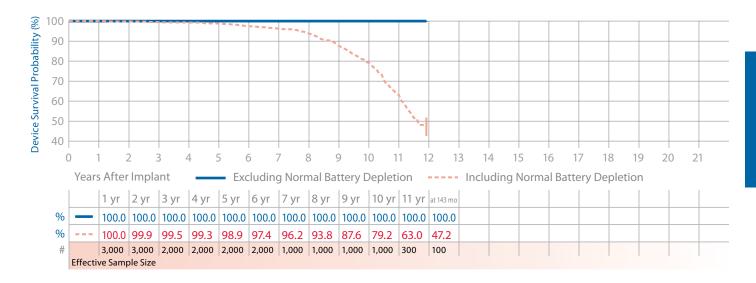




Thera-i D 7964i, 7965i, 7966i

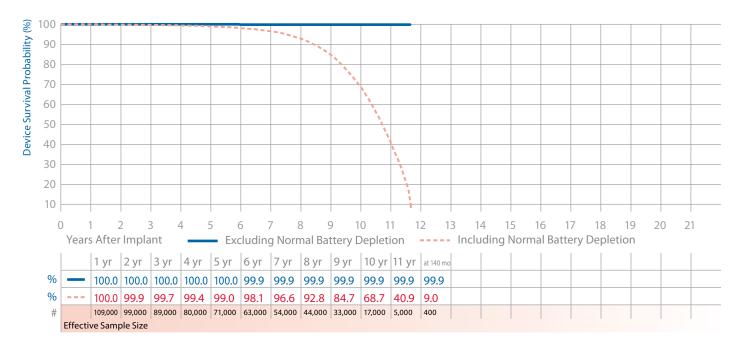
Product Characteristics

US Market Release	Oct-95	Malfunctions (US)	1	NBG Code	DDDCO
Registered US Implants	3,000			Serial Number Prefix	PDE, PDF,
Estimated Active US Implants	300				PDG
Normal Battery Depletions (US)	195			Estimated Longevity	See page 79
Advisories	None				



Thera-i DR 7960i, 7961i, 7962i

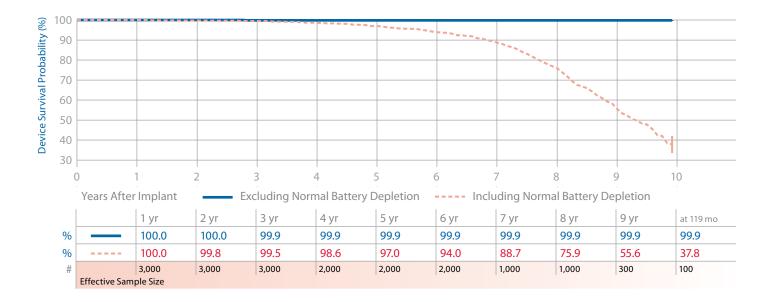
US Market Release	Oct-95	Malfunctions (US)	50	NBG Code	DDD	/RO
Registered US Implants	122,000			Serial Number Prefix	PDB,	,
Estimated Active US Implants	7,000				PDD	
Normal Battery Depletions (US)	10,066			Estimated Longevity	See p	page 79
Advisories	None					



Thera-i DR 7968i

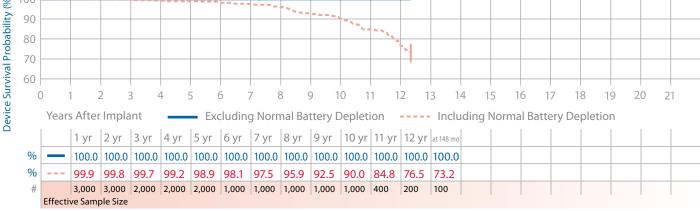
Product Characteristics

US Market Release	Jul-96	Malfunctions (US)	3	NBG Code	DDD/RO
Registered US Implants	4,000			Serial Number Prefix	PGH
Estimated Active US Implants	100			Estimated Longevity	See page 79
Normal Battery Depletions (US)	295				
Advisories	None				



Thera-i S 8964i, 8965i, 8966i

· -					
US Market Release	Oct-95	Malfunctions (US)	1	NBG Code	SSIR
Registered US Implants	4,000			Serial Number Prefix	PDY, PEA,
Estimated Active US Implants	500				PEB
Normal Battery Depletions (US)	84			Estimated Longevity	See page 79
Advisories	None				
§ 100					
© '					

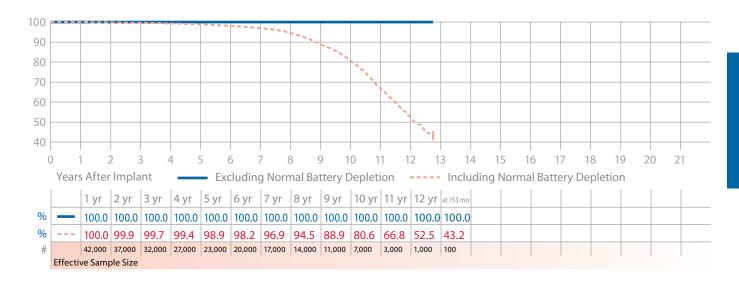




Thera-i SR 8960i, 8961i, 8962i

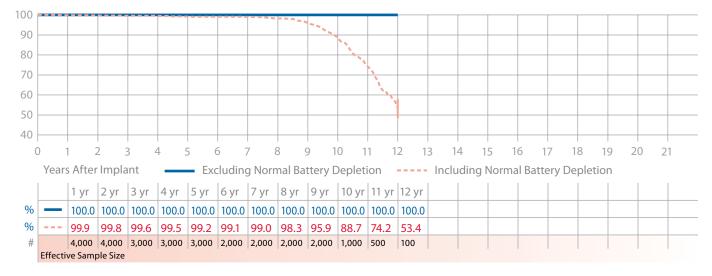
Product Characteristics

US Market Release	Oct-95	Malfunctions (US)	7	NBG Code	SSIR
Registered US Implants	50,000			Serial Number Prefix	PDU, PDV,
Estimated Active US Implants	5,000				PDW
Normal Battery Depletions (US)	2,012			Estimated Longevity	See page 79
Advisories	None				



Thera-i VDD 8968i **Product Characteristics**

US Market Release	Mar-96	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	5,000			Serial Number Prefix	PEC
Estimated Active US Implants	1,000			Estimated Longevity	See page 79
Normal Battery Depletions (US)	196				
Advisories	None				





Versa DR VEDR01

US Market Release	Jul-06	Malfunctions (US)	2	NBG Code	DDDR
Registered US Implants	38,000	Therapy Function Not Compromised	2	Serial Number Prefix	PWH, NWH
Estimated Active US Implants	34,000	Electrical Component	2	Estimated Longevity	See page 79
Normal Battery Depletions (US)	1	Therapy Function Compromised	0		
Advisories	None				



16 yr

98.7 +0.3/-0.4 at 59 mo

99.2 +0.2/-0.3

100.0

HO.0/-0.0

Including Normal Battery Depletion

100.0 +0.0/-0.1 at 59 mo

100.0

100.0 +0.0/-0.1

100.0

100.0

Excluding Normal Battery Depletion

Ш

0

26

4,000

7,000

Dec-03

EnPulse

DR

E1DR01, E1DR03, E1DR06

100.0 +0.0/-0.0 at 57 mo

100.0

100.0+0.0/-0.0

100.0

100.0

Excluding Normal Battery Depletion

0

П

0

0

23

1,000

2,000

Dec-03

E1DR21

EnPulse

96.8 +0.9/-1.2

99.0

99.7

+0.0/-0.0

Including Normal Battery Depletion

100.0



Device Survival Summary (95% Confidence Interval)

The following table shows IPG device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions

12 yr 14 yr 10 yr 8 Vr 7 yr 57.2 +4.1/-4.3 at 67 mo 99.9 +0.1/-0.1 at 67 mo 6 yr 99.9 +0.1/-0.1 83.8 +1.2/-1.3 5 yr Device Survival Probability (%) 99.9 +0.1/-0.1 97.5 +0.3/-0.4 4 yr 100.0 +0.0/-0.0 at 27 mo 100.0 +0.0/-0.0 at 27 mo 100.0 +0.0/-0.0 at 26 mo 99.5 +0.1/-0.2 100.0 +0.0/-0.1 at 26 mo +0.1/-0.2 at 26 mo 100.0 +0.0/-0.1 at 26 mo 100.0 +0.0/-0.1 3 yr Years After Implant 100.0 +0.0/-0.0 100.0 100.0+0.0/-0.0 100.0 +0.0/-0.0 100.0 +0.0/-0.0 99.9 100.0 +0.0/-0.0 at 16 mo 100.0 +0.0/-0.1 100.0 +0.0/-0.1 99.9 100.0 +0.0/-0.1 100.0 2 yr 100.0 100.0 100.0 +0.0/-0.0 100.0 +0.0/-0.0 100.0 HO.0/-0.0 100.0 +0.0/-0.1 +0.0/-0.0 HO.0/-0.0 +0.0/0.0+1 yr 100.0 1000 100.0 100.0 Including Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Depletion Excluding Including Including Excluding 10 0 0 0 10 Total Malfunctions (US) Ш П П П П Compromised Function Not 9 0 0 0 0 2 Therapy + + + + Compromised Therapy Function 4 0 0 0 2 Depletions (US) See page 163 – Performance note on AT500 Pacing System Follow-Up Protocol 0 0 481 Normal Battery 104,000 Implants 10,000 19,000 000'6 5,000 **SU evitoA** 400 Estimated 116,000 10,000 11,000 22,000 11,000 US Implants 400 Registered Mar-03 90-Inf 90-Inf 90-Inf Jul-06 Jul-06 Кејеаѕе US Market included. ADVDD01 ADDR06, ADD01 ADSR01, ADSR03, ADDR01, ADDR03, ADDRL1 **ADDRS1** AT501, 7253 уарширы IəboM Adapta DR Adapta DR Adapta SR Adapta DR Adapta AT500 VDD

Family

continued
Summary
Survival
Device

				.)S)	Malfu b		s (US)			Device	Device Survival Probability (%)	l Probab	ility (%)								
K iiii	odel mber	Market lease	gistered Implants	imated SU evit stnslq	raat Batter 2U) znoitelq	erapy Funct mpromised	erapy nction Not	mpromised Ial	ומן		Years A	Years After Implant	lant	-	-	-	-	-	-	-	-	
167	oM uM	SU Sel		ıэA	ON De		ın∃	toT	101		1 yr	2 yr	3 yr	4 yr 5	5 yr 6	6 yr 7	yr 8	yr	10 yr	12 yr	14 yr	16 yr
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Feb-04	101,000	70,000	81	m	+ 10	11	13 No	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 ai	100.0 +0.0/-0.0 at 56 mo							
									ž	Including Normal Battery Depletion	100.0	99.9	99.9	99.6 +0.1/-0.1	99.2 +0.2/-0.4 at 56 mo							
EnPulse 2 DR	E2DR21	Feb-04	12,000	8,000	48	-	0 +		N _O	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.1	100.0 +0.0/-0.1 + ai	100.0 +0.0/-0.1 at 54 mo							,
									ŭ	Including Normal Battery Depletion	99.9 +0.0/-0.1	99.7 +0.1/-0.1	99.4 +0.1/-0.2	97.6 +0.5/-0.7 at	97.3 +0.6/-0.7 at 54 mo							
EnPulse 2 DR	E2DR31, E2DR33	Feb-04	1,000	400	0	0	0 +	0	0 N	Excluding Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 43 mo								
									ž	Including Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 43 mo								
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Dec-03	25,000	15,000	42	-	7	ε Ε	N N	Excluding Normal Battery Depletion	100.0	100.0	100.0 +	100.0 +0.0/-0.0 al	100.0 +0.0/-0.0 at 57 mo							
									ŭ	Including Normal Battery Depletion	100.0	99.9	99.6	99.1 +0.2/-0.3 +	98.5 +0.4/-0.5 at 57 mo							
EnPulse 2 VDD	E2VDD01	Dec-03	1,000	200	-	0	0 +	0	0	Excluding Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 45 mo								
									ŭ	Including Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	98.5 +1.1/-4.4 at 45 mo								
EnRhythm DR	P1501DR	May-05	78,000	62,000	4	25 +	÷	= 3(30 No	Excluding Normal Battery Depletion	100.0	100.0	99.9 + 0.0-/0.0+	99.9 +0.0/-0.0 at 43 mo								
									ž	Including Normal Battery Depletion	100.0	99.9	99.9 + 0.0-/0.0+	99.9 +0.0/-0.0 at 43 mo								
Kappa 400 DR	KDR401, KDR403	Jan-98	47,000	2,000	5,271	6	+ 13	= 27	22 No	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	96.9 + 0.0/-0.0+	99.9	99.9	99.9 +0.0/-0.0 at	99.9 +0.0/-0.0 at 101 mo			
									ĕ	Including Normal Battery Depletion	99.9	99.9	99.8	99.6 + 0.1/-0.1	99.0 97.4-0.1 +0.1/-0.1	97.2 87 +0.2/-0.2 +C	87.9 +0.5/-0.5 +C	53.0 +0.9/-1.0 at	14.2 +1.2/-1.2 at 101 mo			
Kappa 400 SR	KSR401, KSR403	Feb-98	15,000	2,000	870	-	4	= 2	2 No	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0+	100.0 + 0.0/-0.1	99.9	99.9	99.9 +0.0/-0.1	99.9 +0.0/-0.1 at 111 mo			
									ĕ	Including Normal Battery Depletion	+0.0/-0.1	+0.0/-0.1	99.8	99.5 +0.1/-0.2 +	99.2 9.7	97.8 +0.3/-0.4 +0	92.9 70 +0.7/-0.8	70.3 +1.6/-1.7 at	20.3 +2.8/-2.6 at 111 mo			

Device Survival Summary continued

Malfunctions (US)

Device Survival Probability (%)

paninitud

continued
_
ā
≥
=
3
V)
<u></u>
Š
÷
2
3
Š
d)
ซ
÷
6
ŏ

	impiantai		ı		,											
		16 yr											99.6 +0.1/-0.1 at 217 mo	40.2 +2.5/-2.5 at 217 mo	99.9 +0.0/-0.0 at 200 mo	55.3 +2.2/-2.3 at 200 mo
		14 yr											99.6 +0.1/-0.1	63.1 +0.9/-0.9	99.9	71.6 +0.9/-0.9
		12 yr											99.6 +0.1/-0.1	72.6 +0.7/-0.7	99.9	82.5 +0.6/-0.6
		10 yr											99.6 +0.1/-0.1	81.3	99.9	88.9
		8 yr											99.6 +0.1/-0.1	90.5	99.9	94.7
		7 yr	99.9 +0.1/-0.6 at 75 mo	96.0 +1.4/-2.2 at 75 mo	99.9 +0.0/-0.1 at 82 mo	87.3 +1.3/-1.5 at 82 mo	99.8 +0.1/-0.5 at 81 mo	88.9 +2.1/-2.6 at 81 mo			99.9 +0.1/-0.2 at 77 mo	35.8 +3.4/-3.3 at 77 mo	99.6 +0.1/-0.1	94.6 +0.3/-0.3	99.9	97.1
		6 yr	99.9	97.2 +0.7/-1.0	99.9	96.1	99.9	95.1	100.0 +0.0/-0.0 at 70 mo	93.5 +2.8/-4.8 at 70 mo	99.9	58.9 +1.9/-2.0	99.7 +0.1/-0.1	97.1 +0.2/-0.2	99.9	98.1 +0.1/-0.2
		5 yr	100.0	98.6	100.0	98.6 +0.1/-0.1	99.9	97.5 +0.3/-0.3	100.0	97.5	100.0	90.9	99.7 +0.0/-0.1	98.2 +0.1/-0.1	99.9	98.8
oility (%)		4 yr	100.0	99.6	100.0	99.5	100.0	99.0	100.0	99.0	100.0	97.2 +0.3/-0.3	99.8 +0.0/-0.0	98.9	99.9	99.1
l Probak	lant	3 yr	100.0	99.8	100.0	99.8	100.0	99.7 +0.1/-0.1	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.1	99.2	99.8	99.3	100.0	99.5
Device Survival Probability (%)	Years After Implant	2 yr	100.0	99.9	100.0	99.9	100.0	99.8	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.7 +0.1/-0.1	99.9	99.7 +0.0/-0.1	100.0	99.7
Device	Years A	1 yr	100.0	100.0	100.0	100.0	100.0	99.9	100.0	100.0	100.0	99.9	99.9	99.9	100.0	99.9
			מאכ													
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	ĮĘ	510T	1 Excluding Normal Batter Depletio	Including Normal Battery Depletior	36 Excluding Normal Battery Depletion	Including Normal Battery Depletior	11 Excluding Normal Battery Depletion	Including Normal Battery Depletior	0 Excluding Normal Battery Depletion	Including Normal Battery Depletior	3 Excluding Normal Battery Depletior	Including Normal Battery Depletion	143 Excluding Normal Battery Depletior	Including Normal Battery Depletion	36 Excluding Normal Battery Depletior	Including Normal Battery Depletion
nns	ubkomised	น๐๖	= 1 Norm	Including Normal Battery Depletior	= 36 Norm	Including Normal Battery Depletior	= 11 Norm	Including Normal Battery Depletior	Norm	Including Normal Battery Depletior	m II	Including Normal Battery Depletion	Norm	Including Normal Battery Depletion		Including Normal Battery Depletion
ınctions		น๐๖	0 = 1	Including Normal Battery Depletior	12 = 36 Norm	Including Normal Battery Depletior	8 = 11 Norm	Including Normal Battery Depletior	0 = 0 Norm	Including Normal Battery Depletior	0 = 3	Including Normal Battery Depletion	Norm	Including Normal Battery Depletion		Including Normal Battery Depletion
Malfunctions	ubkomised	Con The Tun Con	= 1 Norm	Including Normal Battery Depletior	= 36 Norm	Including Normal Bartery Depletior	= 11 Norm	Including Normal Battery Depletior	Norm	Including Normal Battery Depletior	m II	Including Normal Battery Depletion	— 143 Norm	Including Normal Battery Depletion		Including Normal Battern Depletion
Malfunctions	rapy rapy ction Not npromised	Dep The Con The Fun Con	+ 0 = 1	Including Normal Battery Depletion	+ 12 = 36 Norm	Including Normal Battery Depletior	+ 8 = 11 Norm	Including Normal Battern Depletion	Norm	Including Normal Battery Depletion	+ 0 +	Including Normal Battery Depletion	Norm	Including Normal Battery Depletion		Including Normal Batter Depletion
Malfunctions	rapy Function rapy Function inposition and rapy rapy rapy rapy rapy rapy rapy rapy	Acti Mor Dep The Con The Tun Tun Tun	+ 0 + 1 Norm	Including Normal Battery Depletion	24 + 12 = 36 Norm	Including Normal Battery Depletior	3 + 8 = 11 Norm	Including Normal Battery Depletion	0 = 0 + 0	Including Normal Battery Depletion	3 + 0 = 3	Including Normal Battery Depletion	— 143 Norm	Including Normal Battery Depletion	36	Including Normal Batter Depletion
Malfunctions	injenus Injents Mal Battery Metions Irapy Function Irapy Ira Irapy Irapy Irapy Irapy Ira Irapy Irapy Ira Irapy Irapy Ira Irapy Ira Irapy Ira Irapy Ira Irapy	Estiti Almp Mor Mor Dep The Com	27 1 + 0 = 1 Norm	Including Normal Battery Depletion	907 24 + 12 = 36 Norm	Including Normal Battery Depletion	240 3 + 8 = 11 Norm	Including Normal Battery Depletion	0 = 0 + 0 Norm	Including Normal Battery Depletion	3 + 0 = 3	Including Normal Battery Depletion	2,900 — — 143 Norm	Including Normal Battery Depletion	2,203 — 36	Including Normal Batter Depletion
Malfunctions	mated Jonts Jants Jetions Jetions Jetion Jetion Jetion Mot Grion Mot Ction Mot Optionised	Reget USI Learning Reget USI Learning Mort Mor The Com	2,000 27 1 + 0 = 1 Norm	Including Normal Battery Depletion	70,000 907 24 + 12 = 36 Norm	Including Normal Battery Depletion	17,000 240 3 + 8 = 11 Norm	Including Normal Battery Depletion	300 9 0 + 0 = 0 Norm	Including Normal Battery Depletion	6,000 902 3 + 0 = 3	Including Normal Battery Depletion	2,000 2,900 — — 143 Norm	Including Normal Battery Depletion	4,000 2,203 — — 36	Including Normal Battery Depletion
Malfunctions	Market jesse istered mplants mal Battery ilants mal Battery aletions rapy Function npromised rapy	Regular Regular Regular Regular North Mort Imp Dept The Com	4,000 2,000 27 1 + 0 = 1 Norm	Including Normal Battery Depletion	125,000 70,000 907 24 + 12 = 36 Norm	Including Normal Battery Depletion	37,000 17,000 240 3 + 8 = 11 Norm	Including Normal Battery Depletion	1,000 300 9 0 + 0 = 0 Norm	Including Normal Battery Depletion	16,000 6,000 902 3 + 0 = 3	Including Normal Battery Depletion	57,000 2,000 2,900 — — 143 Norm	Including Normal Battery Depletion	59,000 4,000 2,203 — — 36	Including Normal Batter Depletion

	continued
	oummar)
١	"
	rvival
	3
(2
	evice 5

ΙP	G	Implantak	ole	Pulse Generato													
			16 yr	99.9 +0.0/-0.0 at 233 mo	71.7 +1.6/-1.7 at 233 mo	100.0 +0.0/-0.1 at 195 mo	51.8 +3.0/-3.1 at 195 mo										
			14 yr	99.9	80.4 +0.7/-0.7	100.0 +0.0/-0.1	69.0 +1.5/-1.6										
		_	12 yr	99.9 +0.0/-0.0	83.6 +0.6/-0.6	100.0	81.9	100.0 +0.0/-0.1 at 141 mo	25.8 +2.3/-2.3 at 141 mo	100.0 +0.0/-0.1 at 141 mo	46.4 +3.4/-3.5 at 141 mo	99.9 +0.1/-0.4 at 141 mo	89.7 +2.2/-2.8 at 141 mo	100.0 +0.0/-0.0 at 139 mo	52.9 +4.6/-4.9 at 139 mo	100.0 +0.0/-0.0 at 140 mo	23.8 +2.3/-2.3 at 140 mo
		_	10 yr	99.9	87.0 +0.5/-0.5	100.0	89.2 +0.7/-0.8	100.0	67.4 +1.1/-1.1	100.0	75.9 +1.4/-1.4	99.9 +0.1/-0.4	93.5 +1.5/-2.0	100.0	75.2 +2.9/-3.2	100.0	67.9
		-	8 yr	99.9	91.8 +0.4/-0.4	100.0	94.7 +0.5/-0.5	100.0	92.5 +0.5/-0.5	100.0 +0.0/-0.1	92.2 +0.6/-0.7	99.9 +0.1/-0.4	97.2 +0.8/-1.2	100.0	95.1	100.0	92.5
		-	7 yr	99.9 +0.0/-0.0	95.1	100.0	96.9 +0.3/-0.4	100.0	96.3 +0.3/-0.3	100.0	94.9 +0.5/-0.5	99.9 +0.1/-0.4	98.1 +0.6/-0.9	100.0	96.8	100.0	96.4 +0.3/-0.3
		-	6 yr	99.9	97.6 +0.2/-0.2	100.0	98.2 +0.2/-0.3	100.0 +0.0/-0.0	97.9 +0.2/-0.2	100.0	97.3 +0.3/-0.4	99.9 +0.1/-0.4	98.9 +0.4/-0.7	100.0	97.6	100.0	98.0
	(9)	-	5 yr	99.9	98.6 +0.1/-0.1	100.0 +0.0/-0.1	98.9 +0.2/-0.2	100.0	98.8 +0.2/-0.2	100.0	98.4 +0.2/-0.3	99.9 +0.1/-0.4	99.1 +0.4/-0.6	100.0	98.6 +0.4/-0.6	100.0	98.8 +0.1/-0.1
	Device Survival Probability (%)	-	4 yr	99.9 +0.0/-0.0	99.2 +0.1/-0.1	100.0	99.5	100.0 +0.0/-0.0	99.4 +0.1/-0.1	100.0 +0.0/-0.1	99.1 +0.2/-0.2	100.0 +0.0/-0.0	99.8 +0.1/-0.2	100.0	98.8 +0.4/-0.6	100.0	99.4 +0.1/-0.1
	al Proba	iplant	3 yr	99.9	99.5	100.0	99.8 +0.1/-0.1	100.0	99.6 +0.1/-0.1	100.0	99.5 +0.1/-0.1	100.0	99.8 +0.1/-0.2	100.0	99.4 +0.3/-0.4	100.0	99.7
	e Surviv	Years After Implant	2 yr	99.9	99.7	100.0	100.0 +0.0/-0.0	100.0	99.8	100.0	99.8 +0.1/-0.1	100.0 +0.0/-0.0	99.9	100.0	99.7	100.0	99.9
	Devic	Years	1 yr	100.0 +0.0/-0.0	99.9	100.0	100.0 +0.0/-0.0	100.0	99.9	100.0	99.9 +0.0/-0.1	100.0	99.9 +0.1/-0.2	100.0	99.9	100.0	99.9
				Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
		la	tоТ	46	I	4		4		-		-		0		=	
	ctions	erapy sction Not mpromised	un⊣	I	I	I		I		I		I		I		I	
ned	Malfunctions	erapy Function npromised		1	1	I		I		1		I				T	
contin		rmal Battery snoifelo	Nor	1,594	elayed	762		1,828		687		38		160		2,522	
Device Survival Summary continued		bətsmi SU əvi stnslc	tэА	4,000	Advisories: See page 159 – 1991 Potential Delayed Restoration of Permanent Settings	1,000		3,000		2,000		1,000		300		4,000	
/al Su		jistered Implants		58,000	159 – 199 nent Setti	17,000		26,000		18,000		4,000		3,000		38,000	
Survi		Market ease		Dec-89	See page of Perma	Mar-92		Jul-96		Jul-96		Oct-95		Oct-95		Oct-95	
Device		del mber	oM inM	8330, 8331, 8331M, 8340, 8341, 8341M,	Advisories: Restoratior	7107, 7108		7088, 7089		8088, 8089		8085, 8086		7864, 7865, 7866		7860, 7861, 7862	
		۸lin	Fan	Minix /		Minuet		Preva DR		Preva SR		Prevail S		Prodigy D		Prodigy DR	

itinued
ry cor
mma
al Su
urviv
/ice S
De

ΙP	G	Implantab	ole	Pulse G	enerat	tors, cont	inued										
			16 yr														
			14 yr			100.0 +0.0/-0.0 at 145 mo	49.7 +3.2/-3.2 at 145 mo										
			12 yr	100.0 +0.0/-0.0 at 139 mo	80.0 +4.3/-5.2 at 139 mo	100.0	50.6 +3.0/-3.1										
			10 yr	100.0	89.6 +2.3/-3.0	100.0	74.9							99.9 +0.0/-0.1 at 107 mo	90.5	99.9 +0.1/-0.2 at 106 mo	90.8 +2.0/-2.5 at 106 mo
			8 yr	100.0	97.2 +1.0/-1.5	100.0	92.2 +0.6/-0.6					100.0 +0.0/-0.0 at 87 mo	97.5	99.9 +0.0/-0.1	94.4	99.9	95.6
			7 yr	100.0	98.8 +0.5/-0.9	100.0	95.3 +0.4/-0.4					100.0	97.5	99.9 +0.0/-0.1	97.8 +0.4/-0.4	99.9	97.3 +0.5/-0.6
			6 yr	100.0	99.1	100.0	97.0 +0.3/-0.3					100.0 +0.0/-0.0	98.7	99.9	99.1	99.9	98.7
	(%)		5 yr	100.0	99.1	100.0 +0.0/-0.0	98.0 +0.2/-0.3					100.0 +0.0/-0.0	98.7	100.0 +0.0/-0.1	99.6	99.9	99.3 +0.2/-0.3
	ability (9		4 yr		99.1	100.0	98.8 +0.2/-0.2	_				100.0	99.6	100.0	99.8	100.0 +0.0/-0.1	99.7
	Device Survival Probability (%)	nplant	3 yr	100.0	99.7	100.0 +0.0/-0.0	99.3	100.0 +0.0/-0.0 at 26 mo	100.0 +0.0/-0.0 at 26 mo	100.0 +0.0/-0.0 at 26 mo	99.9 +0.0/-0.2 at 26 mo	100.0 +0.0/-0.0	99.6	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.8
	e Surviv	Years After Implant	2 yr	100.0	99.8 +0.1/-0.3	100.0 +0.0/-0.0	99.6	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.9	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.9
	Devic	Years	1 yr		99.8 +0.1/-0.3	100.0	99.8 +0.1/-0.1	100.0	100.0	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	100.0	100.0	100.0
				Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion								
		ls	тот	0		4		-		0		0	(0) ubset)	9	(1) ubset)	9	(3)
	ctions	erapy nction Not mpromised	ın⊣	I		I		0		0		0	(0) + (0) = (0) (advisory-related subset)	-	(1) + (0) = (1) (advisory-related subset)	0	= (0)
ned	Malfunctions	erapy Function mpromised		1		T		+		+		+	(0) + (advisory	+	(1) + (advisory	+	(3)
contin		rmal Battery pletions		41		836		0		-		5		117		65	
mary		bətsmi SU əvi: stnslc	tэА	300		3,000		37,000		22,000		200	otential	00009	otential	4,000	otential
al Sum		jistered Implants	SN Seg	2,000		22,000		42,000		26,000		1,000	22 – 2005 F Ject Wires	16,000	22 – 2005 F Ject Wires	12,000	22 – 2005 P rect Wires
Device Survival Summary continued		Market ease	lэЯ	Oct-95		Oct-95		, 90-lut		90-Inf		Aug-99	Advisories: <u>See page 152</u> – 2005 Potential Separation of Interconnect Wires	Aug-99	Advisories: <u>See page 152</u> – 2005 Potential Separation of Interconnect Wires	Sep-99	Advisories: <u>See page 152</u> – 2005 Potential <u>Separation of Interconnect Wires</u>
vice S								SEDRO1, J		SESRO1, J SESO1		SS103, A SS106	lvisories: Soaration or	SDR203 A	lvisories: Soaration o	SSR203 S	lvisories: S paration o
De		del mber	οW	/ S 8164, 8165, 8166								SS	Ad		Ad		Sep
		γlin	Fan	Prodigy S		Prodigy SR		Sensia DR		Sensia SR		Sigma 100 S		Sigma 200 DR		Sigma 200 SR	

Device Survival Summary continued

'U	Implantal	bie	Pulse (∍enera	tors, c	ontinu	ed									
		16 yr														
		14 yr													100.0 +0.0/-0.3 at 148 mo	73.2 +4.3/-4.9 at 148 mo
		12 yr							100.0 +0.0/-0.2 at 143 mo	47.2 +4.5/-4.7 at 143 mo	99.9 +0.0/-0.0 at 140 mo	9.0 +1.0/-0.9 at 140 mo			100.0	76.5 +3.7/-4.3
		10 yr	99.8 +0.0/-0.0 at 109 mo	90.7 +1.7/-2.1 at 109 mo	99.9 +0.0/-0.1 at 107 mo	88.9 +2.2/-2.8 at 107 mo			100.0	79.2 +2.4/-2.6	99.9	68.7 +0.5/-0.5	99.9 +0.1/-0.2 at 119 mo	37.8 +4.3/-4.3 at 119 mo	100.0	90.0
		8 yr	99.8	96.1	99.9	94.9 +0.6/-0.7	100.0 +0.0/-0.0 at 87 mo	97.6 +1.4/-3.1 at 87 mo	100.0 +0.0/-0.2	93.8 +1.1/-1.4	99.9	92.8 +0.2/-0.2	99.9	75.9 +2.3/-2.5	100.0 +0.0/-0.3	95.9
		7 yr	99.8 +0.0/-0.0	98.1 +0.2/-0.2	99.9 +0.0/-0.1	97.7 +0.3/-0.3	100.0 +0.0/-0.0	97.6 +1.4/-3.1	100.0	96.2 +0.8/-1.0	99.9	96.6 +0.1/-0.1	99.9 +0.1/-0.2	88.7 +1.4/-1.6	100.0	97.5
		6 yr	99.9 +0.0/-0.0	99.0	99.9 +0.0/-0.1	98.6 +0.2/-0.2	100.0 +0.0/-0.0	98.7 +0.8/-2.1	100.0	97.4 +0.6/-0.8	99.9	98.1 +0.1/-0.1	99.9 +0.1/-0.2	94.0 +1.0/-1.1	100.0	98.1
(9		5 yr	99.9 +0.0/-0.0	99.4 +0.1/-0.1	99.9 +0.0/-0.0	99.4 +0.1/-0.1	100.0	99.4 +0.4/-1.7	100.0	98.9	100.0	99.0	99.9 +0.1/-0.2	97.0 +0.6/-0.8	100.0	98.9
bility (%		4 yr	99.9	99.7	100.0 +0.0/-0.0	99.7	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.3 +0.3/-0.4	100.0	99.4 +0.0/-0.1	99.9 +0.1/-0.2	98.6 +0.4/-0.6	100.0	99.2
al Proba	plant	3 yr	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.8 +0.0/-0.1	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.5 +0.2/-0.4	100.0	99.7	99.9 +0.1/-0.2	99.5 +0.2/-0.3	100.0	99.7
Device Survival Probability (%)	Years After Implant	2 yr	100.0	99.9	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.9	100.0	99.9	100.0	99.8 +0.1/-0.2	100.0	99.8
Device	Years ,	1 yr	100.0	100.0	100.0	100.0 +0.0/-0.0	100.0+0.0/-0.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	99.9
				B > 6												
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	и	ŏtoT	92		15		0	(0) ubset)	1 Excluding Normal Battery Depletion	Including Normal Battery Depletion	50 Excluding Normal Battery Depletion	Including Normal Battery Depletion	3 Excluding Normal Battery Depletion	Including Normal Battery Depletion	1 Excluding Normal Battery Depletion	Including Normal Battery Depletior
ıctions	rapy ction Mot npromised il	uoɔ	5 = 76		2 = 15		0 = 0	= (0) subset)		Including Normal Battery Depletion		Including Normal Battery Depletion		Including Normal Battery Depletion		Including Normal Battery Depletior
Malfunctions	npromised	Con The mo Con	= 76	= (15) ed subset)	= 15	= (4) ed subset)	0	= (0) ed subset)		Including Normal Battery Depletion		Including Normal Battery Depletion		Including Normal Battery Depletion		Including Normal Battery Depletion
Malfunctions	npromised rapy ction Not npromised	Dep The The Fund	+ 5 = 76		+ 2 = 15		0 0 +	= (0) subset)		Including Normal Battery Depletion		Including Normal Battery Depletion		Including Normal Battery Depletion		Including Normal Battery Depletion
Malfunctions	rapy Function rapy Function rapy ction Not ction Not rapromised	Acti Mori Dep The Con The Fund	71 + 5 = 76	(15) + (0) = (15) (advisory-related subset)	13 + 2 = 15	$\frac{(4)}{(advisory-related subset)}$	0 = 0 + 0	otential $(0) + (0) = (0)$ (advisory-related subset)	-	Including Normal Battery Depletion	50	Including Normal Battery Depletion	- 3	Including Normal Battery Depletion		Including Normal Battery Depletion
Malfunctions	ve US lants mal Battery aletions rapy Function promised rapy rapy rapy rapy	Estin Actil Imp Morr Morr Dep The Com	394 71 + 5 = 76	(15) + (0) = (15) (advisory-related subset)	191 13 + 2 = 15	$\frac{(4)}{(advisory-related subset)}$	2 0 + 0 = 0	otential $(0) + (0) = (0)$ (advisory-related subset)	195 — 1	Including Normal Battery Depletion	10,066 - 50	Including Normal Battery Depletion	295 — 3	Including Normal Battery Depletion	84 - 1	Including Normal Battery Depletion
Malfunctions	mated ve US lants lants mal Battery letions rapy Function rapy Function rapy Function rapy Function rapy Function rapy Function rapy rapy rapy	Rege USI Estii Mori Mori Dep The Com	53,000 394 71 + 5 = 76	(15) + (0) = (15) (advisory-related subset)	20,000 191 13 + 2 = 15	$\frac{(4)}{(advisory-related subset)}$	200 5 0 + 0 = 0	otential $(0) + (0) = (0)$ (advisory-related subset)	300 195 - 1	Including Normal Battery Depletion	7,000 10,066 - 50	Including Normal Battery Depletion	100 295 — — 3	Including Normal Battery Depletion	500 84 - 1	Including Normal Battery Depletion
Malfunctions	Market sase istered mplants we US lants lants mal Battery lants rapy Function rapy Function rapy Function rapy Function rapy Function	Regient Regien	107,000 53,000 394 71 + 5 = 76		54,000 20,000 191 13 + 2 = 15		1,000 200 5 0 $+$ 0 $=$ 0	= (0) subset)	3,000 300 195 — — 1	Including Normal Battery Depletion	122,000 7,000 10,066 — — 50	Including Normal Battery Depletion	4,000 100 295 — — 3	Including Normal Battery Depletion	4,000 500 84 - 1	Including Normal Battery Depletion

U	Implanta	DIE	Pulse G	enera	lors, co	munu	eu	
		16 yr						
		10 yr 12 yr 14 yr 16 yr	100.0 +0.0/-0.0 at 153 mo	43.2 +2.3/-2.4 at 153 mo				
		12 yr	100.0	994 989 982 96.9 94.5 80.6 52.5 +0.1/-0.1 +0.1/-0.1 +0.2/-0.2 +0.2/-0.2 +0.3/-0.3 +0.7/-0.7 +1.5/-1.5	100.0	53.4 +4.7/-5.0		
			100.0 +0.0/-0.0 +0.0/-0.0	80.6	100.0 100.0	998 99.6 99.5 99.2 99.1 99.0 98.3 88.7 +0.1/-0.2 +0.2/-0.3 +0.2/-0.3 +0.3/-0.4 +0.3/-0.4 +0.3/-0.4 +0.4/-0.6 +1.5/-1.7		
		8 yr	100.0 +0.0/-0.0	94.5	100.0	98.3		
		7 yr	100.0	96.9	100.0	99.0		
		6 yr	100.0	98.2 +0.2/-0.2	100.0	99.1		
(%)		5 yr	100.0	98.9	100.0	99.2		
Device Survival Probability (%)		4 yr	100.0	99.4 +0.1/-0.1	100.0	99.5		
al Proba	nplant	3 yr	100.0 +0.0/-0.0 +0.0/-0.0	99.9 +0.0/-0.0 +0.1/-0.1	100.0	99.6	100.0 +0.0/-0.0 at 26 mo	99.9 +0.0/-0.1 at 26 mo
e Surviv	Years After Implant	2 yr		99.9			100.0	99.9 +0.0/-0.1
Devic	Years	1 yr	100.0	100.0 +0.0/-0.0	100.0	99.9 +0.1/-0.1	100.0	100.0
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	ין	510T	7 Excluding Normal Battery Depletion	Including Normal Battery Depletion	0 Excluding Normal Battery Depletion	Including Normal Battery Depletion	2 Excluding Normal Battery Depletion	Including Normal Battery Depletion
ctions	yder ction Not npromised il	Fun	Nor	Including Normal Battery Depletion		Including Normal Battery Depletion		Including Normal Battery Depletion
Malfunctions	ction Not pesimorqr	Con The Tun Con	7 Norm	Including Normal Battery Depletion		Including Normal Battery Depletion	= 2	Including Normal Battery Depletion
Malfunctions	npromised rapy ction Not npromised	Dep The The Fund	. – 7 Norm	Including Normal Battery Depletion		Including Normal Battery Depletion	+ 2 = 2	Including Normal Battery Depletion
Malfunctions	letions rapy Function rapy rapy ction Not ction Not rapy	Acti Imp Nor Dep The Com The Fund	_ 7 Norm	Including Normal Battery Depletion	0	Including Normal Battery Depletion	+ 2 = 2	Including Normal Battery Depletion
Malfunctions	ve US lants mal Battery letions rapy Function promised rapy repy rapy	Estin Acti Imp Nor Nor Dep The Com	2,012 — 7 Norm	Including Normal Battery Depletion	196 — — 0	Including Normal Battery Depletion	1 0 + 2 = 2	Including Normal Battery Depletion
Malfunctions	istered mplants we US ve US lants mal Battery rapy Function ppromised rapy rapy	Regele USI Actifump Mori Inp Dep The Com	5,000 2,012 — 7 Norm	Including Normal Battery Depletion	1,000 196 — — 0	Including Normal Battery Depletion	34,000 1 0 + 2 = 2	Including Normal Battery Depletion
Malfunctions	Market istered istered mplants we US we US lants mal Battery lants mal Battery lants mal Battery mal Battery rapy Function rapy Function rapy Function rapy Function rapy Function	US N Regle US I Mori Inp Mori Inp The Com	50,000 5,000 2,012 — 7 Norm	Including Normal Battery Depletion	5,000 1,000 196 — — 0	Including Normal Battery Depletion	38,000 $34,000$ 1 0 $+$ 2 $=$ 2	Including Normal Battery Depletion



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated I	ongevity	_				
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators			
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.3 6.0	**			
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**			
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**			
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**			
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**			
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.			
EnPulse DR	E1DR01, E1DR03, E1DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**			
EnPulse DR	E1DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**			
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**			
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**			
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**			
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**			
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**			
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.6 8.0 5.4	12.3 10.3 7.8	**			
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**			
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**			
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**			
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**			

^{**}Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

	Estimated Long	evity			
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 920 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend	8416, 8417, 8417M, 8418, 8419	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	15.6 11.3 9.0	17.7 14.5 12.5	If programmed to non-rate responsive mode (e.g., VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g., VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g., VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g., VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (A, RV) Nominal 4.0 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.

 $^{^{**}\}mbox{Telemetry}$ indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

Estimated	Longevity

		Estimated L	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Prodigy D	7864, 7865, 7866	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy S	8164, 8165, 8166	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**
Sensia DR	SEDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera-i D	7964i, 7965i, 7966i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Thera-i DR	7960i, 7961i, 7962i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Thera-i DR	7968i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 5.4 3.9	8.3 6.9 5.5	**
Thera-i S	8964i, 8965i, 8966i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Thera-i SR	8960i, 8961i, 8962i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Thera-i VDD	8968i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	11.5 9.6 7.7	12.4 11.1 9.7	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**

 $^{^{**}\}mbox{Telemetry}$ indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 20 years with its multicenter, global chronic lead studies.

Leads Performance Analysis

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted, nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

Returned Product Analysis Shortfalls

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads that are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although returned product analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

System Longevity Study (SLS)

The SLS is a prospective, multicenter, global study designed to monitor the performance of marketreleased cardiac therapy products. Medtronic has been monitoring the performance of its cardiac therapy products for 26 years and has evaluated the performance of more than 75,000 leads, with data reported from 14 countries on four continents.

Patients are eligible for enrollment in the study if:

- 1 They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2 They participated in a qualifying study of a market-released Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

Lead Complications

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

Clinical Observations

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3,000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance
- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Method for Estimating Lead Performance continued

The Standard Actuarial Method is used to determine estimates of lead survival.

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is abandoned or explanted, or the patient is no longer available for follow-up. The data analyses assume that the patient is still part of the study and there are no lead complications at the time of the report cutoff date unless specifically reported by the center.

Medtronic evaluates center compliance with study protocol through, at a minimum, annual clinical monitoring at each study site. Additionally, study center personnel must be trained in the study procedures prior to participating, and they must adhere to the policies and procedures of their local ethics boards.

Implant times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, patient leaves the study or the lead is no longer being used), or the cutoff date of the report. If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are reported in PPR tables.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve.

Although the report provides tabular data in 1-year intervals, the curves are actually computed and plotted using 3-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Method for Estimating Lead Performance continued

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, including data from 14 countries on four continents, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

Returned Product Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

Lead malfunctions are divided into three categories: Implant Damage, Electrical, and Other. Typical examples of implant damage are stylet perforation, cut or torn insulation, bent or distorted conductors, over-retracted helixes, and conductor fracture due to over-torquing. An electrical malfunction is defined as a hardware malfunction resulting in a break in the insulation or a break in the conductor that could affect the electrical performance of the lead. A break in the insulation is defined as a breach allowing entry of body fluids or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions, environmental stress cracking (ESC), and metal ion

oxidation (MIO). A break in the conductor of a lead is defined as the loss of continuity in the metallic components that could interrupt the current flow or voltage. Examples include fractured conductors and defective crimps.

Leads damaged after explant or damaged due to failure to heed warnings or contraindications in the labeling are not considered device malfunctions.

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis from the United States. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS centers around the world.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides the number of leads registered as implanted and the number remaining active based on the status recorded in the Medtronic Device Registration System.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Returned Product Analysis results for these models are included here for reference and comparison.

Left-Heart Leads

2187 Attain

Product Characteristics

US Market Release	Aug-01	Serial Number Prefix	LEY	US Returned Product Ana	alysis
Registered US Implants	12,000	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Continuous Curve	Implant Damage	7
Estimated Active US Implants	4,300	Polarity	Unipolar	Electrical Malfunction	0
Advisories	None	Steroid	No	Other	16

System Longevity Study Results

Qualifying Complications 1 Total

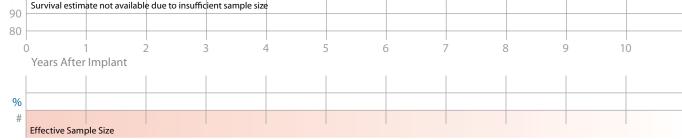
Number of Leads Enrolled in Study 134 Cumulative Months of Follow-Up 5,978 Number of Leads Active in Study 38 Failure to Capture

100 Lead Survival Probability (%) 90 80 2 3 4 9 5 6 10 Years After Implant 1 yr 2 yr 3 yr 4 yr at 54 mo % 99.1 99.1 99.1 99.1 99.1 47 108 88 70 57 Effective Sample Size

2188 Attain

Product Characteristics

U	JS Market Release	Aug-01	Serial Number Pr	efix LEB		US Returned Product Ana	llysis
F	Registered US Implants	1,800	Type and/or Fixa	tion Transvenous, Core Cardiac Vein, Can		Implant Damage	1
E	Estimated Active US Implants	400	Polarity	Bipolar		Electrical Malfunction	1
A	Advisories	None	Steroid	No		Other	(
stem l	Longevity Study Results		(Qualifying Complications	1 Total		
١	Number of Leads Enrolled in Stu	dy 14	ļ	Extra Cardiac Stimulation	1		
	Cumulative Months of Follow-Up	•	.				
	Number of Leads Active in Study						
	variable of Leads Netive in Study						
90 80 80	Survival estimate not available due	to insufficient	sample size				
90							
80							
	0 1 2	3	4	5 6	7 8	9 10	
3	Years After Implant						
5							
%							
í #							



Left-Heart Leads continued

485

Effective Sample Size

376

284

4193 Attain

Product Characteristics

	US Market Re	ease	May-0)2 Sei	rial Number Pre	fix BAA			US Returne	d Product Ana	alysis
	Registered US Implants 98,100 Type and/or Fixati		oe and/or Fixati		svenous, Left \ , Distal Double		nt Damage	65			
	Estimated Act	tive US Implar	nts 54,10	00 Po	larity	Uni	oolar		Electrical N	Malfunction	23
	Advisories		Nor	ne Ste	eroid	Yes				Other	64
/ster	n Longevity S	tudy Results	;		Q	ualifying Co	mplications	34 Total			
	Number of Le	ads Enrolled i	n Study	673		Condu	ıctor Fracture	1	Lead D	islodgement	13
	Cumulative M	onths of Follo	ow-Up 2	2,161		Extra Cardia	c Stimulation	6	Unspecified Cl	inical Failure	3
	Number of Le	ads Active in	Study	259		Failu	re to Capture	11			
R 10	00										
9	90						1				
8	30										
	0	1	2	3	4	5	6	7 8	9	10	
3	Years Afte	r Implant				-	-				
10 9 8		1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo				
	%	95.8	94.7	93.9	93.9	93.9	93.9				

94

46

4194 Attain

Product Characteristics

198

T12T	Attuill			Troduct C	.iiaiacteiist	1C3			
	US Market Rel	ease	Aug-04	Serial Numl	ber Prefix	LFG		US Returned Product A	nalysis
	Registered US	Implants	75,000	Type and/o	r Fixation	Transvenous, Left V Cardiac Vein, Distal		Implant Damage	96
	Estimated Act	ive US Implants	57,700	Polarity		Bipolar		Electrical Malfunction	14
	Advisories		None	Steroid		Yes		Other	7
System	n Longevity St	tudy Results			Qualif	ying Complications	7 Total		
	Number of Lea	ads Enrolled in S	tudy 517	,		Failure to Capture	1		
	Cumulative M	onths of Follow-	Up 10,982	2		Lead Dislodgement	6		
	Number of Lea	ads Active in Stu	dy 401						
_ 10	0								
%) >: 9!				_					
abilit 8									
oba		1 2					7		
Lead Survival Probability (%)	0 Years After		3	4	5	6	7 8	9 10	
≥.	lears Arter		1	ı	ı	1			
l Su		1 yr 2	yr 3 y	r at 4	42 mo				
eac %	%	99.1	8.0 98.	.0 98	3.0				
	#	324 2	14 76	41					
	Effective Sam	1 -				1			

www.CRDMPPR.medtronic.com



4195 Attain

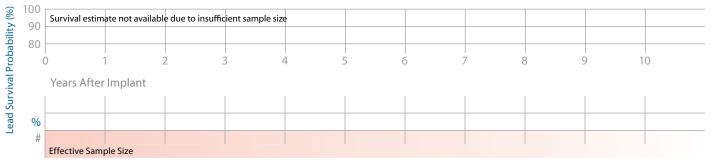
Product Characteristics

US Market Release	Aug-08	Serial Number Prefix	AAD	US Returned Product An	alysis
Registered US Implants	2,420	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Deployable Lobe Fixation	Implant Damage	11
Estimated Active US Implants	2,400	Polarity	Unipolar	Electrical Malfunction	2
Advisories	None	Steroid	Yes	Other	8

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study 24 Cumulative Months of Follow-Up 373 Number of Leads Active in Study 23



Left-Heart Leads continued

Lead Survival Summary (95% Confidence Interval)

		ase		Study		nths of udy	Device	Survival	Probabil	ity (%)						
<u>.</u>		US Market Release	eads Enrolled	Leads Active in Study	Qualifying Complications	Cumulative Months Follow-Up in Study	Years A	fter Impl	ant							
Model Number	Family	US Maı	Leads	Leads	Qualify Compl	Cumul	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
2187	Attain	Aug-01	134	38	1	5,978	99.1 +0.8/-5.2	99.1 +0.8/-5.2	99.1 +0.8/-5.2	99.1 +0.8/-5.2	99.1 +0.8/-5.2 at 54 mo					
2188	Attain	Aug-01	14	1	1	383	Survival e	stimate no	t available	due to insu	ıfficient saı	mple size				
4193	Attain	May-02	673	259	34	22,161	95.8 +1.3/-2.0	94.7 +1.6/-2.2	93.9 +1.7/-2.5	93.9 +1.7/-2.5	93.9 +1.7/-2.5	93.9 +1.7/-2.5 at 69 mo				
4194	Attain	Aug-04	517	401	7	10,982	99.1 +0.6/-1.6	98.0 +1.1/-2.2	98.0 +1.1/-2.2	98.0 +1.1/-2.2 at 42 mo						
4195	Attain	Aug-08	24	23	0	373	Survival e	stimate no	t available	due to insu	ıfficient sar	mple size				

Source: System Longevity Study Data as of January 31, 2009

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
2187	Attain	Aug-01	12,000	4,300	7	0	16
2188	Attain	Aug-01	1,800	400	1	1	0
4193	Attain	May-02	98,100	54,100	64	19	65
4194	Attain	Aug-04	75,000	57,700	93	6	7
4195	Attain	Jun-08	2,420	2,400	11	2	8

Source: Returned Product Analysis Data as of January 31, 2009

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 BI
4193	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI
4195	Attain	Transvenous Cardiac Vein Deployable Lobes	Polyurethane (55D)	MP35N	Platinum Alloy	IS-1 Uni

Defibrillation Leads

6721, 6921 Epicardial Patch

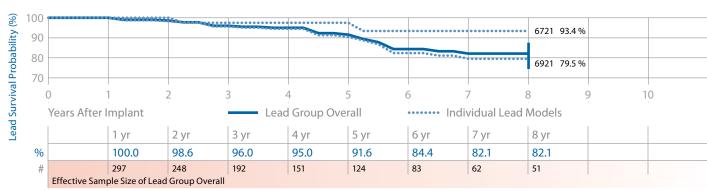
Product Characteristics

US Market Release	Feb-93	Serial Number Prefix	TBH, TBG, TBB, TAD, TAC, or TAB	US Returned Product Anal	lysis
Registered US Implants	8,300	Type and/or Fixation	Epicardial Defib Patch, Suture	Implant Damage	5
Estimated Active US Implants	1,300	Polarity	Defib Electrode only	Electrical Malfunction	80
Advisories	None	Steroid	No	Other	0

System Longevity Study Results

Qualifying Complications 28 Total

Number of Leads Enrolled in Study	407	Conductor Fracture	20	Insulation (not further defined)	3
Cumulative Months of Follow-Up	18,283	Failure to Capture	2		
Number of Leads Active in Study	12	Impedance Out of Range	3		



6930 Sprint Fidelis

Product Characteristics

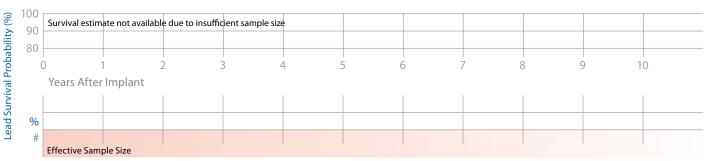
US Market Release	Sep-04	Serial Number Prefix	LFK	US Returned Product Ana	alysis
Registered US Implants	400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	0
Estimated Active US Implants	300	Polarity	True Bipolar/One Coil	Electrical Malfunction	2
Advisories	1	Steroid	Yes	Other	0
See page 151 – 2007 Potential Co	onductor				

System Longevity Study Results

Wire Fracture

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	4
Cumulative Months of Follow-Up	83
Number of Leads Active in Study	4



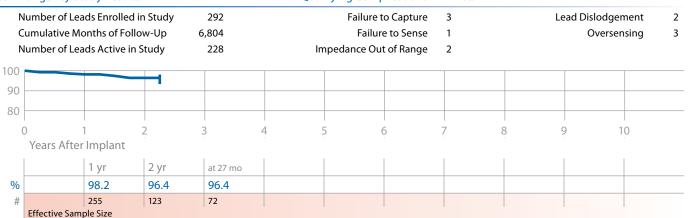
6931 Sprint Fidelis

Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFL	US Returned Product An	alysis
Registered US Implants	8,100	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Screw-in	Implant Damage	28
Estimated Active US Implants	6,000	Polarity	True Bipolar/One Coil	Electrical Malfunction	102
Advisories	1	Steroid	Yes	Other	0
See page 151 – 2007 Potential Co	onductor				
Wire Fracture					

System Longevity Study Results

Qualifying Complications 11 Total



6932 Sprint

Lead Survival Probability (%)

Product Characteristics

US Market Release		Release Aug-96 Serial Number Prefix TCA				US Returned Prod	duct Analys	
	Registered US Implants	15,000	Type and/or Fixat	ion Transvenous, Vent Sense, Tines	, Defib and Pace/	Implant Dar	image	
1	Estimated Active US Implants	5,700	Polarity	True Bipolar/One C	Coil	Electrical Malfun	ction :	
,	Advisories	None	Steroid	Yes		C	Other	
tem	Longevity Study Results		C	Qualifying Complications	8 Total			
	Number of Leads Enrolled in Stud	dy 410)	Extra Cardiac Stimulation	1			
	Cumulative Months of Follow-Up	20,997	,	Failure to Capture	2			
Í	Number of Leads Active in Study	72	!	Failure to Sense	2			
				Oversensing	3			
100								
100								
90		3	4	5 6	7 8	9	10	
90		3	4	5 6	7 8	9	10	
90	0 1 2	1		5 6	,	9 yr 9 yr	10 at 114 mo	
90	0 1 2 Years After Implant 2 yr	з у	r 4 yr		7 yr 8	1	1	
90	0 1 2 Years After Implant 1 yr 2 yr 99.4 98.4	з у	r 4 yr	5 yr 6 yr	7 yr 8	yr 9 yr 6.7 96.7	at 114 mc	

6933, 6937, 6937A, 6963 SVC/CS

Product Characteristics

US Returned Product Analy	/sis
Implant Damage	31
Electrical Malfunction 2	200
Other	13
	Implant Damage Electrical Malfunction

System Longevity Study Results

Qualifying Complications 25 Total

Number of Leads Enrolled in Study	966	Conductor Fracture	15	Lead Dislodgement	1
Cumulative Months of Follow-Up	47,888	Failure to Capture	1	Unspecified Clinicial Failure	4
Number of Leads Active in Study	32	Impedance Out of Range	2		
		Insulation (not further defined)	2		



6935 Sprint Quattro Secure

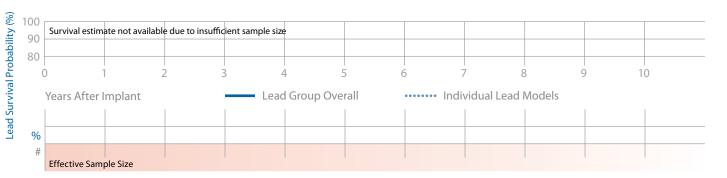
Product Characteristics

US	Market Release	Nov-08	Serial Number Prefix	TAU	US Returned Product Analys	sis
Re	gistered US Implants	590	Type and/or Fixation	Transvenous, Vent, Defib and Pace/		
				Sense, Screw-in	Implant Damage	0
Est	timated Active US Implants	580	Polarity	True Bipolar/One Coil	Electrical Malfunction	0
Ad	lvisories	None	Steroid	Yes	Other	0

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	2
Cumulative Months of Follow-Up	0
Number of Leads Active in Study	2



6936, 6966 Transvene

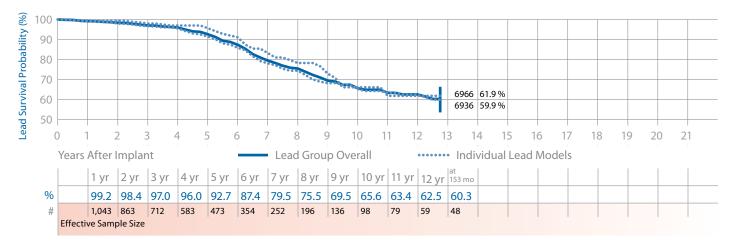
Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TAV or TAL	US Returned Product Ar	nalysis
Registered US Implants	23,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Implant Damage	90
Estimated Active US Implants	3,200	Polarity	True Bipolar/One Coil	Electrical Malfunction	487
Advisories	None	Steroid	No	Other	19

System Longevity Study Results

Qualifying Complications 150 Total

5	Impedance Out of Range	18	Conductor Fracture	1,350	Number of Leads Enrolled in Study
14	Insulation (not further defined)	2	Extra Cardiac Stimulation	67,840	Cumulative Months of Follow-Up
93	Oversensing	9	Failure to Capture	40	Number of Leads Active in Study
5	Unspecified Clinical Failure	4	Failure to Sense		



6939, 6999 Sub-Q Patch

Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TBA or TAP	US Returned Product An	alysis
Registered US Implants	3,600	Type and/or Fixation	Subcutaneous Defib Patch, Suture	Implant Damage	4
Estimated Active US Implants	300	Polarity	Defib Electrode Only	Electrical Malfunction	33
Advisories	None	Steroid	No	Other	1

System Longevity Study Results

Qualifying Complications 20 Total

Number of Leads Enrolled in Study	384	Conductor Fracture	10	Unspecified Clinical Failure
Cumulative Months of Follow-Up	17,726	Failure to Capture	2	
Number of Leads Active in Study	5	Insulation (not further defined)	6	



2

6942 Sprint

Product Characteristics

	US Market Release		Jul-97	Serial Number Prefix		t TCB	TCB			US Returned Product Ana				
		Registered US	Implants		17,700	Type and/or Fixation			Transvenous, Vent, Defib and Pace/Sense, Tines			Implant Damage		
	Estimated Active US Implants			ts	7,400	Polarity		Integr	ated Bipolar/	Two Coils	Ele	ectrical Malfunction	37	
		Advisories			None	Steroid		Yes				Other	5	
Sys	tem	n Longevity St	udy Results				Qua	llifying Com	nplications	7 Total				
		Number of Lea	ads Enrolled i	ո Study	351			Conduc	tor Fracture	1		Oversensin	g 3	
	Cumulative Months of Follow-Up		w-Up	15,650)		Failu	Failure to Sense		Unspe	Unspecified Clinical Failure			
		Number of Lea	ads Active in S	Study	57	,		Lead Dis	slodgement	1				
<u></u>	100)	,											
ead Survival Probability (%)	9(
pabili	8(
Prok		0	1 :	2	3	4		5	6	7	8	9 10		
ival		Years After	Implant											
Surv			1 yr	2 yr	3 y	r	4 yr	5 yr	6 yr	7 yr	8 yr	at 102 mo		
ead	9	6	98.9	98.9	97.	8	97.2	96.3	96.3	96.3	96.3	96.3		
_		,,	240	202	45.0		400	400	00	70		50		

Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr at 102 mo 98.9 98.9 97.8 97.2 96.3 96.3 96.3 96.3 96.3 % 248 156 108 202 128 83 70 60 50 Effective Sample Size

6943 Sprint

Product Characteristics

	US Market Release		Oct-97	Oct-97 Serial Number Prefix		TCE	US Returned Product Analysis				
	Registered	I US Implants	20,800	Type and/or F	ixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in		Implant Damage		amage	51
	Estimated	Active US Implants	8,800	Polarity		True Bipolar/One Coil			Electrical Malfunction		
	Advisories		None	Steroid		Yes			Other		8
Syster	n Longevit	y Study Results			Qualifyi	ng Complications	67 Total				
	Number of	f Leads Enrolled in :	Study 1,31		(Conductor Fracture	15	Insulation	(not further	defined)	1
	Cumulativ	e Months of Follow	<i>y</i> -Up 65,157	7		Failure to Capture 7			Lead Dislodgement		
	Number of	f Leads Active in St	udy 38°			Failure to Sense	5		Oversensing		31
						pedance Out of Range 4		Unspecified Clinical Failure			3
a 10	0										
%) \ \	00										
bilit											
oba	80										
Pre	0	1 2	3	4	5	6	7	8	9	10	
Lead Survival Probability (%)	Years A	fter Implant									
d Sur		1 yr	2 yr 3 y	r 4 yr	5 y	r 6 yr	7 yr	8 yr	9 yr	at 111 i	mo
Геас	%	98.8	98.0 96	.8 95.8	93.	6 91.8	91.2	90.8	88.8	88.8	
_	#	1,074	927 789	643	471	346	230	118	64	53	
	Effective	Sample Size									

6944 Sprint Quattro

Product Characteristics

US Market Release	Dec-00	Serial Number Prefix	TDC	US Returned Product Ana	alysis
Registered US Implants	31,900	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Implant Damage	31
Estimated Active US Implants	19,200	Polarity	True Bipolar/Two Coils	Electrical Malfunction	35
Advisories	None	Steroid	Yes	Other	8

System Longevity Study Results

Qualifying Complications 3 Total

Number of Leads Enrolled in Study	188	Oversensing	2
Cumulative Months of Follow-Up	7,482	Unspecified Clinical Failure	1
Number of Leads Active in Study	75		



6945 Sprint

Product Characteristics

	эртин			Troduct Cit	aracteristi							
	US Market Release	Se	ep-97	Serial Numb	er Prefix	TDA			US	Returned Pro	oduct An	alysis
	Registered US Implants	4	2,800	Type and/or	Fixation		ous, Vent, nse, Screw	Defib and in		Implant D	amage	198
	Estimated Active US Impla	nts 1	8,100	Polarity		Integrate	ed Bipolar/	Two Coils	El	ectrical Malfu	ınction	118
	Advisories		None	Steroid		Yes					Other	11
stem	Longevity Study Result	S			Qualify	ing Comp	ications	27 Total				
	Number of Leads Enrolled	in Study	1,157			Conductor	Fracture	3	lmp	edance Out o	of Range	5
	Cumulative Months of Foll	ow-Up	54,899		Extra	Cardiac Sti	mulation	1	•	Ove	rsensing	12
	Number of Leads Active in	•	229			Failure to	Capture	1	Unsp	ecified Clinica	•	1
		,					to Sense	4				
100												
90										_		
80												
	0 1	2	3	4	5	6		7	8	9	10	
	Years After Implant											
	1 yr	2 yr	3 yı	4 yı	5	yr	6 yr	7 yr	8 yr	9 yr	at 111	mo
%	99.6	99.1	98.	98.	1 97	7.0	95.9	95.5	94.0	94.0	94.0	
#	910	745	618	483	37	78	300	243	158	72	56	
	Effective Sample Size											

6947 Sprint Quattro Secure

Product Characteristics

US Market Release	Nov-01	Serial Number Prefix	TDG	US Returned Product An	alysis
Registered US Implants	206,100	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Implant Damage	476
Estimated Active US Implants	151,200	Polarity	True Bipolar/Two Coils	Electrical Malfunction	137
Advisories	None	Steroid	Yes	Other	25
	Registered US Implants Estimated Active US Implants	Registered US Implants 206,100 Estimated Active US Implants 151,200	Registered US Implants 206,100 Type and/or Fixation Estimated Active US Implants 151,200 Polarity	Registered US Implants 206,100 Type and/or Fixation Pace/Sense, Screw-in Estimated Active US Implants 151,200 Polarity True Bipolar/Two Coils	Registered US Implants 206,100 Type and/or Fixation Transvenous, Vent, Defib and Pace/Sense, Screw-in Implant Damage Estimated Active US Implants 151,200 Polarity True Bipolar/Two Coils Electrical Malfunction

System Longevity Study Results

Qualifying Complications 23 Total

Number of Leads Enrolled in Study	1,397	Conductor Fracture	3	Lead Dislodgement	3
Cumulative Months of Follow-Up	54,528	Failure to Sense	2	Oversensing	7
Number of Leads Active in Study	597	Impedance Out of Range	4	Unspecified Clinical Failure	2
		Insulation (not further defined)	2		



6948 Sprint Fidelis

Product Characteristics

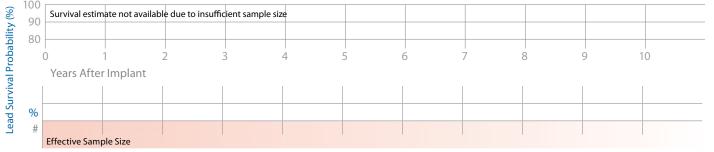
US Market Release	Sep-04	Serial Number Prefix	LFH	US Returned Product An	alysis
Registered US Implants	10,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	9
Estimated Active US Implants	7,900	Polarity	True Bipolar/Two Coils	Electrical Malfunction	17
Advisories	1	Steroid	Yes	Other	4
See page 151 - 2007 Potential (onductor				

System Longevity Study Results

Wire Fracture

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	30
Cumulative Months of Follow-Up	797
Number of Leads Active in Study	26



6949 Sprint Fidelis

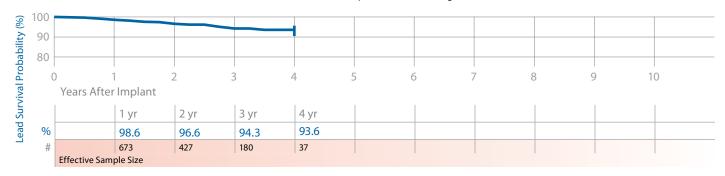
Product Characteristics

US Market Release	t Release Sep-04 Serial Number Prefix Lf		LFJ	US Returned Product Analysis					
Registered US Implants	ts 186,700 Type and/or Fixation mplants 135,900 Polarity 1 Steroid		Transvenous, Vent, Defib and Pace/ Sense, Screw-in	Implant Damage	461				
Estimated Active US Implants	135,900	Polarity	True Bipolar/Two Coils	Electrical Malfunction	1,435				
Advisories See page 151 – 2007 Potential Co	1 onductor	Steroid	Yes	Other	45				

System Longevity Study Results

Qualifying Complications 30 Total

Number of Leads Enrolled in Study	789	Conductor Fracture	9	Insulation (not further defined)	1
Cumulative Months of Follow-Up	21,439	Failure to Capture	2	Lead Dislodgement	1
Number of Leads Active in Study	576	Failure to Sense	2	Oversensing	11
		Impedance Out of Range	4		



6996 Sub-Q Lead

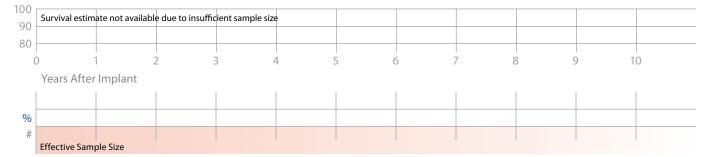
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	TCR	US Returned Product Ana	lysis
Registered US Implants	2,300	Type and/or Fixation	Subcutaneous Defib Coil, Suture	Implant Damage	1
Estimated Active US Implants	1,600	Polarity	One Defib Coil	Electrical Malfunction	3
Advisories	None	Steroid	No	Other	0
		0 116			

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study 17 Cumulative Months of Follow-Up 445 Number of Leads Active in Study 14



		vr 14 yr 16 yr 18 yr 20 yr							92.2 +2.9/-4.6 at 141 mo		62.5 60.3 +5.6/-6.2 +6.1/-6.7 at 153 mo											
		10 yr 12 yr						96.7 +1.9/-4.1 at 114 mo	92.2 92.2 +2.9/-4.6 +2.9		65.6 62.5 +5.1/-5.8 +5.6	86.1 +5.2/-7.9 at 99 mo	96.3 +2.0/-4.1 at 102 mo	88.8 +3.1/-4.3 at 111 mo		94.0 +2.1/-3.1 at 111 mo						
		8 yr	82.1 +5.5/-7.7					96.7	94.6 +2.0/-3.1		75.5 +3.9/-4.5	86.1 +5.2/-7.9	96.3 +2.0/-4.1	90.8 +2.1/-2.6		94.0 +2.1/-3.1						
		7 yr	82.1 +5.5/-7.7					97.8 +1.2/-2.9	95.2		79.5	87.7 +4.7/-7.1	96.3	91.2 +2.0/-2.5		95.5	97.0 +1.1/-1.8 at 78 mo					
		6 yr	84.4 +4.9/-7.0	Survival estimate not available due to insufficient sample size	•			97.8 +1.2/-2.9	96.4	Survival estimate not available due to insufficient sample size	87.4 +2.4/-3.1	91.1	96.3 +2.0/-4.1	91.8 +1.9/-2.3	95.9 +2.8/-8.1 at 69 mo	95.9	97.0	Survival estimate not available due to insufficient sample size	-		Survival estimate not available due to insufficient sample size	
		5 yr	91.6 +3.2/-4.9	sufficient s				97.8	97.0 +1.2/-2.0	nsufficient s	92.7	94.1	96.3	93.6	95.9 +2.8/-8.1	97.0	97.4	sufficient s			nsufficient s	
oility (%)		4 yr	95.0	ole due to ir			0	98.4 +0.9/-2.3	98.6	ole due to ir	96.0	98.2 +1.0/-2.6	97.2 +1.5/-3.6	95.8	97.6	98.1	98.1	ole due to ir		93.6 +2.1/-3.1	ole due to ir	
al Probal	ıplant	3 yr	3 +1.9/-3.3	notavailak		96.4		98.4 +0.9/-2.3	99.2 +0.4/-1.0	not availak	97.0 +1.0/-1.3	98.2 3 +1.0/-2.6	97.8	96.8	98.9	98.8 +0.6/-1.0	98.5	not availak		94.3	not availak	
, Device Survival Probability (%)	Years After Implant	2 yr	98.6 +0.9/-2.3	al estimate		96.4		98.4 +0.9/-2.3	99.2 +0.4/-1.0	al estimate	98.4 +0.6/-1.0	98.7	98.9	98.0 +0.6/-1.1	100.0	99.1	98.9 +0.5/-0.8	al estimate		96.6	alestimate	
Devie	Years	1 yr	100.0			98.2 +1.0/-2.5		, 99.4 +0.4/-1.8	99.6 +0.3/-0.8	0 Surviv	99.2	99.0	98.9	, 98.8 +0.5/-0.8	100.0	99.6	99.2			98.6 +0.7/-1.2		
sn Months Sin Study	1 əvita		28 18,283	- 83	Wire Fractur	11 6,804	Wire Fractur	8 20,997	25 47,888	0	150 67,840	20 17,726	7 15,650	67 65,157	3 7,482	27 54,899	23 54,528	0 797	Wire Fractur	30 21,439	Wire Fractur	
γpn12 ni ε	6ui/	(TilsuQ	12	4	– 2007 Potential Conductor Wire Fracture	228	– 2007 Potential Conductor Wire Fracture	72	32	7	40 1	7.	57	381	75	229	597	56	– 2007 Potential Conductor Wire Fracture	576	– 2007 Potential Conductor Wire Fracture	
pə	llo≀n∃	l sba91	407	4	2007 Potenti	292	2007 Potenti	410	996	2	1,350	384	351	1,311	188	1,157	1,397	30	2007 Potenti	789	2007 Potenti	
əseələ	ket Re	isM 2U	Feb-93	Sep-04		Sep-04	See page 151 – 2	Aug-96	Dec-93	Nov-08	Dec-93	Dec-93	Jul-97	Oct-97	Dec-00	Sep-97	Nov-01	Sep-04	page 151 – .	Sep-04	See page 151 – 2	
		Family	Epicardial Patch	Sprint Fidelis	Advisories: See page 151	Sprint Fidelis	Advisories: See	Sprint	SNC/CS	Sprint Quattro Secure	Transvene	Sub-Q Patch	Sprint	Sprint	Sprint Quattro	Sprint	Sprint Quattro Nov-01	Sprint Fidelis	Advisories: See page 151	Sprint Fidelis	Advisories: See	
		ləboM dmuM	6721, 6921	6930		6931		6932	6933, 6937, 6937A, 6963	6935	6936,	6669	6942	6943	6944	6945	6947	6948		6949		

Lead Survival Summary (95% Confidence Interval)

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
6721, 6921	Epicardial Patch	Feb-93	8,300	1,300	5	80	0
6930	Sprint Fidelis	Sep-04	400	300	0	2	0
6931	Sprint Fidelis	Sep-04	8,100	6,000	28	102	0
6932	Sprint	Aug-96	15,000	5,700	16	39	7
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	15,700	2,700	31	200	13
6935	Sprint Quattro Secure	Nov-08	590	580	0	0	0
6936, 6966	Transvene	Dec-93	23,700	3,200	90	487	19
6939, 6999	Sub-Q Patch	Dec-93	3,600	300	4	33	1
6942	Sprint	Jul-97	17,700	7,400	31	37	5
6943	Sprint	Oct-97	20,800	8,800	51	71	8
6944	Sprint Quattro	Dec-00	31,900	19,200	31	35	8
6945	Sprint	Sep-97	42,800	18,100	198	118	11
6947	Sprint Quattro Secure	Nov-01	206,100	151,200	476	137	25
6948	Sprint Fidelis	Sep-04	10,400	7,900	9	17	4
6949	Sprint Fidelis	Sep-04	186,700	135,900	461	1,435	45
6996	Sub-Q Lead	Jun-01	2,300	1,600	1	3	0

Reference Chart

			Pin Conf	figuration			
Model Number	Family	Туре	Pace/Sense	High Voltage	Lead Body Diameter	Insulation, Lead Body	Fixation, Steroid
6721	Epicardial Patch	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive
6934S	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid
6935	Sprint Quattro Secure	Endo RV True Bipolar Sensing	IS-1	DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive
6939	Sub-Q Patch	SQ Patch	_	DF-1	One Size	Silicone, Single Lumen	Suture
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6963	SVC/CS	Endo SVC/CS Coil	_	6.5 mm	7 Fr	Silicone, Single Lumen	Passive
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active
6996	Sub-Q Lead	SQ Coil	_	DF-1	7.5 Fr	Silicone, Single Lumen	Passive
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture

Pacing Leads

3830 SelectSecure

Product Characteristics

US Market Release	Aug-05	Serial Number Prefix	LFF	US Returned Product Ana	alysis
Registered US Implants	12,200	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	21
Estimated Active US Implants	10,600	Polarity	Bipolar	Electrical Malfunction	5
Advisories	None	Steroid	Yes	Other	1

Atrial Placement System Longevity Study Results **Qualifying Complications** 1 Total Number of Leads Enrolled in Study 166 Failure to Sense Cumulative Months of Follow-Up 5,129 Number of Leads Active in Study 95 Lead Survival Probability (%) 100 90 80 2 3 4 5 6 8 9 10 Years After Implant 1 yr 2 yr 3 yr 4 yr 99.4 % 99.4 99.4 99.4 114 78 68 45

Ventricular Placement

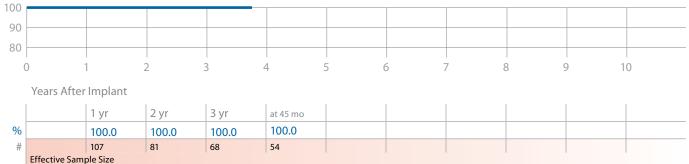
System Longevity Study Results

Effective Sample Size

Qualifying Complications 0 Total

Number of Leads Enrolled in Study 148 Cumulative Months of Follow-Up 4,983 Number of Leads Active in Study 82





4003, 4003M CapSure

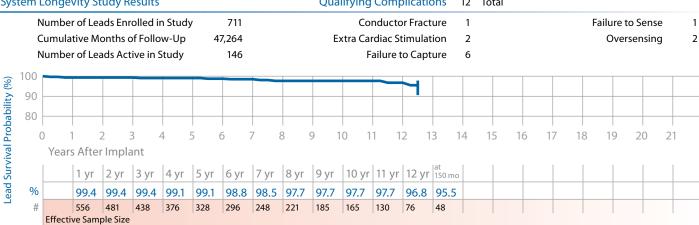
Product Characteristics

US Market Release	Jul-86	Serial Number Prefix	IH or LAX	US Returned Product Ana	alysis
Registered US Implants	38,000	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	24
Estimated Active US Implants	5,300	Polarity	Unipolar	Electrical Malfunction	60
Advisories	None	Steroid	Yes	Other	2

Ventricular Placement



Qualifying Complications 12 Total



Source: Medtronic Device Registration and Returned Product Analysis

Data as of January 31, 2009

4004, 4004M CapSure

Product Characteristics

US Market Release Feb-89		Serial Number Prefix PS or LAV		US Returned Product Ana	Analysis	
Registered US Implants	72,600	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	56	
Estimated Active US Implants	5,800	Polarity	Bipolar	Electrical Malfunction	688	
Advisories	1	Steroid	Yes	Other	19	
See page 157 – 1993 Lead Surviv	al Below					

Ventricular Placement

Expectations

System Longevity Study Results

Qualifying Complications 277 Total

Number of Leads Enrolled in Study	1,640	Conductor Fracture	7	Insulation (ESC)	4
Cumulative Months of Follow-Up	71,653	Electrical Abandonment	1	Insulation (MIO)	4
Number of Leads Active in Study	4	Extra Cardiac Stimulation	2	Insulation (not further defined)	7
		Failure to Capture	131	Medical Judgment	1
		Failure to Sense	62	Oversensing	25
		Impedance Out of Range	32	Unspecified Clinical Failure	1



4011 Target Tip

Product Characteristics

US Market Release	Nov-82	Serial Number Prefix	IB	US Returned Product Ana	alysis
Registered US Implants	58,400	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	29
Estimated Active US Implants	6,200	Polarity	Unipolar	Electrical Malfunction	152
Advisories	None	Steroid	No	Other	5

Ventricular Placement

Lead Survival Probability (%)

System Longevity Study Results Qualifying Complications 25 Total

 475
 414
 353
 299
 250
 219
 189
 165
 134

C	Numbe Lumula Numbe	tive Mo	onths o	f Follo	w-Up		851 1,409 2			Ex	ktra Cai	nducto diac St ailure t	imulat	ion	1 4 9		Insulat	ion (no		er def versei	,	10 1
100 90 80																1						
(Years	1	2 3 Impla 2 yr	3 4 int 3 yr	4	5 (5 yr	6 yr	7 8 7 yr	8 yr	9 1 9 yr	0 1	1 1 1 11 yr	- 1		4 1.	5 10		7 1	3 1	9 2	20	21
%		99.4	99.2	99.1	98.8	97.6	96.4	96.0	96.0	96.0	95.0	93.6	92.8	91.9	91.9	91.9	91.9					

109 81

556

626

Effective Sample Size

4012 Target Tip

Product Characteristics

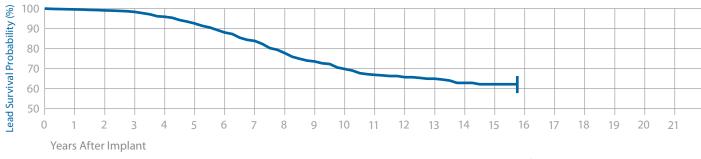
US Market Release	Jul-83	Serial Number Prefix	HQ	US Returned Product Analysis
Registered US Implants	93,700	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 50
Estimated Active US Implants	6,500	Polarity	Bipolar	Electrical Malfunction 827
Advisories	1	Steroid	No	Other 34
See page 158 – 1991 Lead Surv Expectations	ival Below			

Ventricular Placement

System Longevity Study Results

Qualifying Complications 316 Total

Number of Leads Enrolled in Study	2,543	Conductor Fracture	6	Insulation (ESC)	9
Cumulative Months of Follow-Up	151,162	Extra Cardiac Stimulation	3	Insulation (MIO)	4
Number of Leads Active in Study	10	Failure to Capture	126	Insulation (not further defined)	16
		Failure to Sense	77	Medical Judgment	1
		Impedance Out of Range	26	Oversensing	48



		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	at 189 mo			
%		99.6	99.1	98.4	95.9	92.6	88.1	83.9	77.8	73.6	69.8	66.9	65.7	65.0	62.9	62.2	62.2			
#		1,935	1,714	1,528	1,310	1,084	888	698	522	400	307	243	200	144	98	69	51			
	Effecti	ve Sam	ole Size																	

4023 CapSure SP

Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	LAK	US Returned Product Analy	sis
Registered US Implants	41,200	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	47
Estimated Active US Implants	9,600	Polarity	Unipolar	Electrical Malfunction	21
Advisories	None	Steroid	Yes	Other	6

Ventricular Placement

886

Effective Sample Size

765

System Longevity Study Results Qualifying Complications 20 Total Number of Leads Enrolled in Study 1,158 Extra Cardiac Stimulation 1 Insulation (not further defined) 1 Cumulative Months of Follow-Up 65,853 Failure to Capture 15 Lead Dislodgement 2 Number of Leads Active in Study Impedance Out of Range 341 1 100 Lead Survival Probability (%) 90 80 9 10 11 12 13 15 16 Years After Implant 1 yr | 2 yr | 3 yr | 4 yr | 5 yr | 6 yr | 7 yr | 8 yr | 9 yr | 10 yr | 11 yr | 12 yr | at _{147 mo} % 99.9 | 99.3 | 98.8 | 98.6 | 98.6 98.2 97.2 96.8 96.8 96.3 95.0 95.0 95.0

111

65

602

513

435

238

171

4024 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAJ	US Returned Product An	nalysis
Registered US Implants	222,100	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	264
Estimated Active US Implants	56,100	Polarity	Bipolar	Electrical Malfunction	135
Advisories	None	Steroid	Yes	Other	34

Ventricular Placement

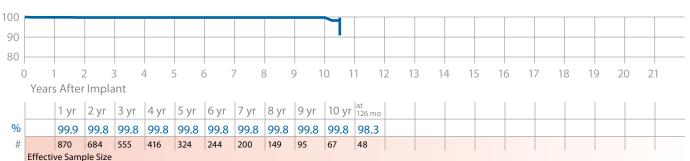
Lead Survival Probability (%)

System Longevity Study Results

Qualifying Complications 3 Total Failure to Capture

3

Number of Leads Enrolled in Study 1,214 Cumulative Months of Follow-Up 52,403 Number of Leads Active in Study 23

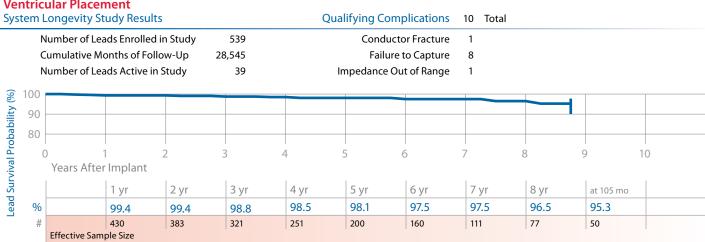


4033 CapSure Z

Product Characteristics

US Market Release	Not US released	Serial Number Prefix	LCA	US Returned Product Ana	lysis
Registered US Implants	NA	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	2
Estimated Active US Implants	NA	Polarity	Unipolar	Electrical Malfunction	0
Advisories	None	Steroid	Yes	Other	0

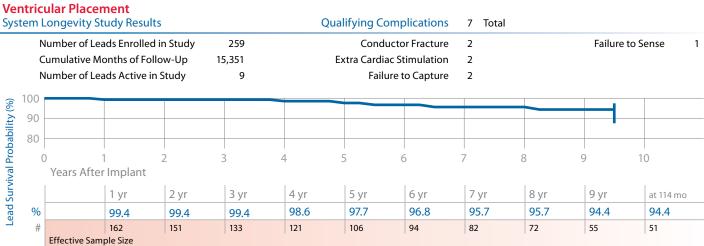
Ventricular Placement



4057, 4057M Screw-In

Product Characteristics

US Market Release	Aug-88	Serial Number Prefix	US Returned Product Analy				
Registered US Implants	10,100 Type and/or Fixation Transvenous, V or A, Screw-in		Transvenous, V or A, Screw-in	Implant Damage	39		
Estimated Active US Implants	1,800	Polarity	Unipolar	Electrical Malfunction	6		
Advisories	None	Steroid	No	Other	4		



4058, 4058M Screw-In

Product Characteristics

US Market Release	Jan-89	Serial Number Prefix	ZY or LAW	US Returned Product An	alysis
Registered US Implants	101,900	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	388
Estimated Active US Implants	20,800	Polarity	Bipolar	Electrical Malfunction	261
Advisories	None	Steroid	No	Other	23

Atrial Placement

System Longevity Study Results

Qualifying Complications 33 Total

Number of Leads Enrolled in Study	2,364	Extra Cardiac Stimulation	1	Insulation (not further defined)	1
Cumulative Months of Follow-Up	131,441	Failure to Capture	15	Lead Dislodgement	3
Number of Leads Active in Study	44	Failure to Sense	7	Oversensing	1
		Impedance Out of Range	5		



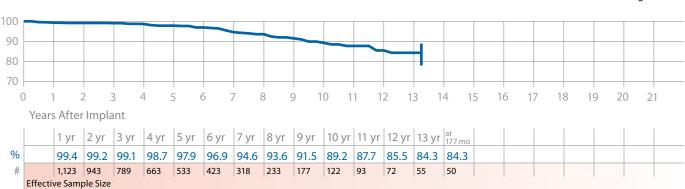
Ventricular Placement

Lead Survival Probability (%)

System Longevity Study Results

Qualifying Complications 53 Total

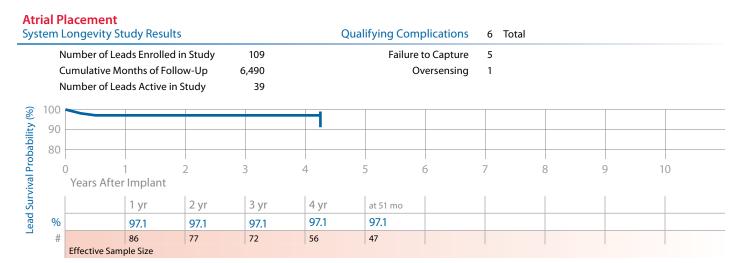
Number of Leads Enrolled in Study	1,690	Conductor Fracture	5	Impedance Out of Range	7
Cumulative Months of Follow-Up	77,493	Extra Cardiac Stimulation	3	Insulation (not further defined)	4
Number of Leads Active in Study	49	Failure to Capture	22	Lead Dislodgement	1
		Failure to Sense	10	Oversensing	1



4067 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LCV	US Returned Product Analys	is
Registered US Implants	1,000	Type and/or Fixation	Implant Damage	3	
Estimated Active US Implants	300	Polarity	Unipolar	Electrical Malfunction	1
Advisories	None	Steroid	Yes	Other	1



4068 CapSureFix

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCE	US Returned Product An	nalysis
Registered US Implants	124,800	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	406
Estimated Active US Implants	43,900	Polarity	Bipolar	Electrical Malfunction	111
Advisories	None	Steroid	Yes	Other	11

Atrial Placement

System Longevity Study Results

Qualifying Complications 60 Total

2	Insulation (ESC)	2	Conductor Fracture	2,411	Number of Leads Enrolled in Study
1	Insulation (not further defined)	1	Extra Cardiac Stimulation	124,306	Cumulative Months of Follow-Up
8	Lead Dislodgement	19	Failure to Capture	552	Number of Leads Active in Study
7	Oversensing	11	Failure to Sense		
3	Unspecified Clinical Failure	6	Impedance Out of Range		



164

90

Ventricular Placement

Lead Survival Probability (%)

System Longevity Study Results

Effective Sample Size

1,906 1,630 1,368 1,116 885

691

508

363

263

Qualifying Complications 38 Total

C	umu	lative	Month	ns of Fo	ed in Sti ollow-U in Stud	Jр	1,79 89,24 45	11			Extra	a Cardia Failt	ac Stim ure to C	racture ulation apture Sense	2 2 20 3				•		Ov	of Ra ersen cal Fai	sing		5 4 2
100																									
90												_								-					
80		_				_									-					-				-	
(0	1	2 ter Im	3	4	5	6	7	8	9	10	11	12	13	14	15	16	1.	7	18	19	2	0 2	21	

	Years	s After	Impla	ant													
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 129 mo					
%		99.3	98.8	98.8	98.3	98.0	97.5	96.4	96.0	94.2	94.2	94.2					
#		1,426	1,213	1,029	836	671	472	333	202	123	66	51					
	Effecti	ve Sam	ole Size														

4073 CapSure Sense

Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBF	US Returned Product Analysi					
Registered US Implants	600 Type and/or Fixation Transvenous,		Transvenous, Vent., Tines	Implant Damage	1				
Estimated Active US Implants	400	Polarity	Unipolar	Electrical Malfunction	0				
Advisories	None	Steroid	Yes	Other	0				

Atrial Placement

System Longevity Study Results Qualifying Complications 0 Total

Number of Leads Enrolled in Study 1 Cumulative Months of Follow-Up 52 Number of Leads Active in Study 1



Ventricular Placement

System Longevity Study Results Qualifying Complications 0 Total

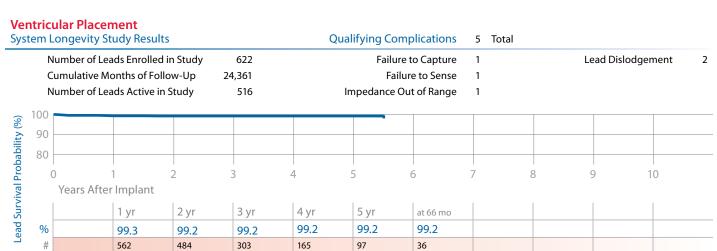
Number of Leads Enrolled in Study 100 Cumulative Months of Follow-Up 4,770 Number of Leads Active in Study 83



4074 CapSure Sense

Effective Sample Size

US Market Release	Jun-02	Serial Number Prefix	BBD	US Returned Product Analysis		
Registered US Implants	63,000	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	13	
Estimated Active US Implants	45,200	Polarity	Bipolar	Electrical Malfunction	8	
Advisories	None	Steroid	Yes	Other	1	

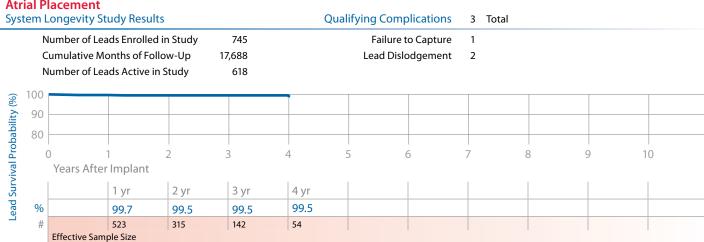


4076 CapSureFix Novus

Product Characteristics

US Market Release	arket Release Feb-04		BBL	US Returned Product Analysis		
Registered US Implants	199,200	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	96	
Estimated Active US Implants	165,500	Polarity	Bipolar	Electrical Malfunction	13	
Advisories	None	Steroid	Yes	Other	8	

Atrial Placement



Ventricular Placement

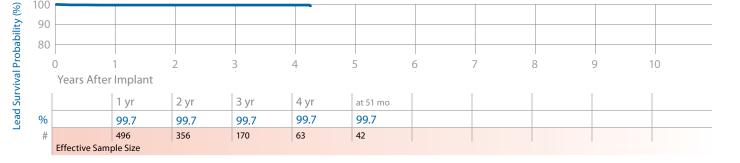
100

90

System Longevity Study Results

Qualifying Complications 2 Total Failure to Capture

Number of Leads Enrolled in Study 668 Cumulative Months of Follow-Up 17,812 Number of Leads Active in Study 555



4081 Target Tip

Product Characteristics

US Market Release	: Release Jul-89		erial Number Prefix LAC		sis
Registered US Implants	3,900	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	4
Estimated Active US Implants	800	Polarity	Unipolar	Electrical Malfunction	5
Advisories	None	Steroid	No	Other	0

Ventricular Placement System Longevity Study Results Qualifying Complications 3 Total Number of Leads Enrolled in Study 260 **Conductor Fracture** 1 Cumulative Months of Follow-Up 9,940 Failure to Sense 2 Number of Leads Active in Study 9 100 Lead Survival Probability (%) 90 80 3 4 5 6 8 9 10 Years After Implant 2 yr 3 yr 4 yr 5 yr 1 yr at 63 mo % 100.0 100.0 100.0 100.0 100.0 98.2

55

47

4092 CapSure SP Novus

191

Effective Sample Size

156

116

Product Characteristics

81

US Market Release	Sep-98	Serial Number Prefix LEP		US Returned Product Anal		
Registered US Implants	d US Implants 151,000 Type and/or Fixation Transvenous, Vent.,		Transvenous, Vent., Tines	Implant Damage	39	
Estimated Active US Implants	83,100	Polarity	Bipolar	Electrical Malfunction	19	
Advisories	None	Steroid	Yes	Other	5	

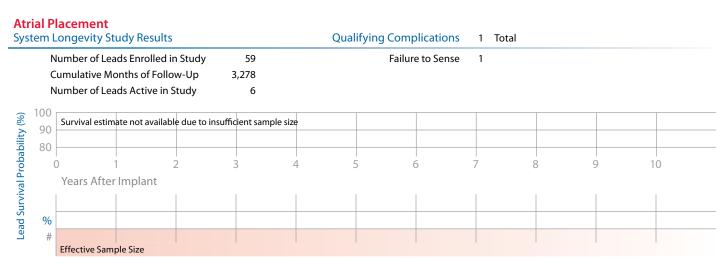
Ventricular Placement

System Longevity Study Results **Qualifying Complications** 17 Total Number of Leads Enrolled in Study 1,145 **Conductor Fracture** 3 Impedance Out of Range 1 Cumulative Months of Follow-Up Lead Dislodgement 55,839 Extra Cardiac Stimulation 1 4 Number of Leads Active in Study 512 8 Failure to Capture 100 Lead Survival Probability (%) 90 80 3 5 6 8 9 4 10 Years After Implant 5 yr 7 yr 1 yr 2 yr 3 yr 4 yr 6 yr at 90 mo 98.0 98.0 % 98.9 98.8 98.7 98.4 98.0 98.0 925 826 732 618 450 283 134 61 Effective Sample Size

4503, 4503M CapSure

Product Characteristics

US Market Release	Narket Release Jul-86		Serial Number Prefix MQ, LAY		alysis
Registered US Implants	8,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	2
Estimated Active US Implants	1,500	Polarity	Unipolar	Electrical Malfunction	12
Advisories	None	Steroid	Yes	Other	0



4504, 4504M CapSure

Product Characteristics

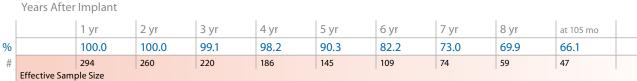
US Market Release	ket Release Mar-90		QM or LBA	US Returned Product An	US Returned Product Analysis		
Registered US Implants 15,400		Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	5		
Estimated Active US Implants	mated Active US Implants 1,700		Bipolar	Electrical Malfunction	172		
Advisories	1	Steroid	Yes	Other	4		
See page 156 – 1996 Lead Surviv	al Below						

Atrial Placement

System Longevity Study Results **Qualifying Complications** 48 Total

			ads Enrolled in S	,	368 Electrical Abandonment 19,879 Extra Cardiac Stimulation			Ir	Impedance Out of Range Insulation (MIO) Lead Dislodgement				
	Number of Leads Active in Study		udy	1		F	ailure to Captur	re 14					
								Failure to Sens	se 16		(Oversensing	3
(%)	100												
_	90												
robability	80												
<u> </u>	70												
rviva	60												
ad Sur	50												
Lea	()	1 2		3	4	5	6	7	8	9	10	





4512 Target Tip

Product Characteristics

US Market Release Jul-83		Serial Number Prefix	PF	US Returned Product Analysis		
Registered US Implants	10,300	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	4	
Estimated Active US Implants	1,200	Polarity	Bipolar	Electrical Malfunction	85	
Advisories	None	Steroid	No	Other	8	

Atrial Placement

Custom Langavity Ctudy Docults

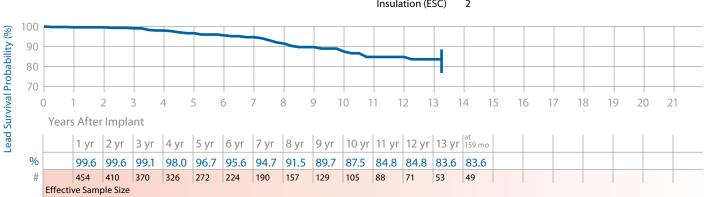
	System Longevity Study Results		Qualifying Complications	35	iotai	
Ī	Number of Leads Enrolled in Study	600	Electrical Abandonment	1	Insulation (MIO)	4
	Cumulative Months of Follow-Up	39,833	Failure to Capture	6	Insulation (not further defined)	2
	Number of Leads Active in Study	4	Failure to Sense	14	Lead Dislodgement	1

Insulation (ESC)

Oversensing

Impedance Out of Range

Qualifying Complications 25 Tatal

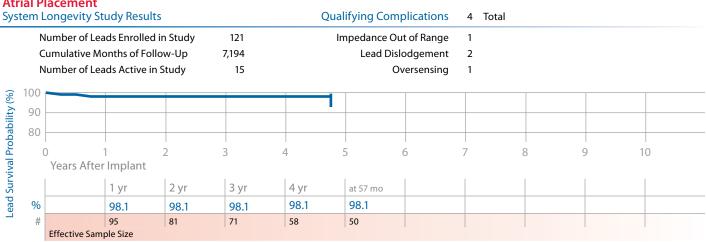


4523 CapSure SP

Product Characteristics

US Market Release Aug		Aug-91	Serial Number Prefix	ZE	US Returned Product Analy	sis
	Registered US Implants	11,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	5
	Estimated Active US Implants	3,200	Polarity	Unipolar	Electrical Malfunction	2
	Advisories	None	Steroid	Yes	Other	1

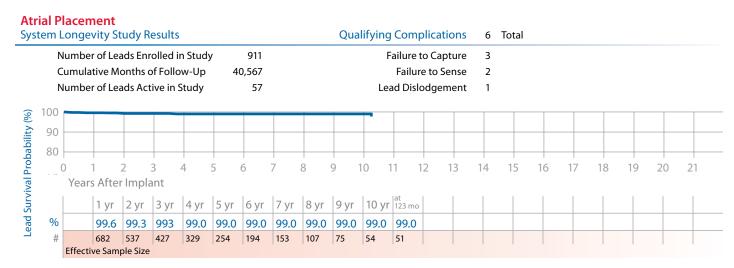
Atrial Placement



4524 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAR	US Returned Product Analysis			
Registered US Implants	ints 101,700 Type and/oi		Transvenous, Atrial-J, Tines	Implant Damage	47		
Estimated Active US Implants	32,300	Polarity	Bipolar	Electrical Malfunction	31		
Advisories	None	Steroid	Yes	Other	8		



4533 CapSure Z

Product Characteristics

	US Market Release			Not US Serial Number Prefix released		Prefix LCI	В			US Return	ed Product Ana	alysis
	Registered US	Implants		NA -	Type and/or Fix	kation Tra	nsvenous, Atrial	-J, Tines		lmp	lant Damage	0
	Estimated Active US Implants Advisories		nts	NA I	Polarity	Un	ipolar			Electrical	Malfunction	0
			N	one !	Steroid	Yes	5			Other		0
	I Placement m Longevity St	udy Result	5			Qualifying C	omplications	4 Total				
	Number of Lea	ads Enrolled	in Study	206		Fail	ure to Capture	1			Oversensing	1
	Cumulative M	onths of Foll	ow-Up	11,286	Failure to Sense 1							
	Number of Lea	ads Active in	Study	16	Lead Dislodger			1				
© 10	00											
ty (9	90						<u> </u>					
abilli	30											
rob	0	1	2	3	4	5	6	7	8	9	10	
Lead Survival Probability (%)	Years After	r Implant	2	5	4	5	0	/	0	9	10	
Sun		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 78 mo				
ead	%	100.0	99.4	98.8	97.9	97.9	97.9	97.9				
_	#	176	158	132	101	77	60	51			İ	

Effective Sample Size

4557, 4557M Screw-In

Product Characteristics

US Market Release	Aug-88	Serial Number Prefix	VQ or LAM	US Returned Product An	alysis
Registered US Implants	19,700	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	53
Estimated Active US Implants	4,400	Polarity	Unipolar	Electrical Malfunction	14
Advisories	None	Steroid	No	Other	4

	А	dvisor	ies				Non	e S	steroid				No									Other		4
		lacen onge		udy R	esults						Qua	lifying	g Com	plica	ations	6	Total							
	Ν	lumbe	r of Lea	ads Enr	olled i	n Study	/	294			E	xtra Ca	rdiac S	Stimu	ılation	1					Over	sensing	j	1
	C	umula	tive M	onths c	of Follo	w-Up	18	3,465				ı	Failure	to Ca	apture	3								
	Ν	lumbe	r of Lea	ads Act	ive in S	Study		10					Failu	re to	Sense	1								
(%)	100																							
	90																							
abil	80																							
Prob	()	1	2	3	4	5	1 6	1 7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	
ival		Years	s Aftei	r Impla	ant																			
-ead Survival Probability			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 vr	8 yr	9 yr	10 vr	at 126 mo											
ead	%		99.1	99.1	99.1	97.8	97.8	97.8	96.9	96.9	96.9												_	
_	#		197	179	163	142	125	112	101	86	65	56	49											
		Effecti		ple Size	1	_	-	_	1	1	1	1	1 -		'		'			1	1		1	

4558M Screw-In

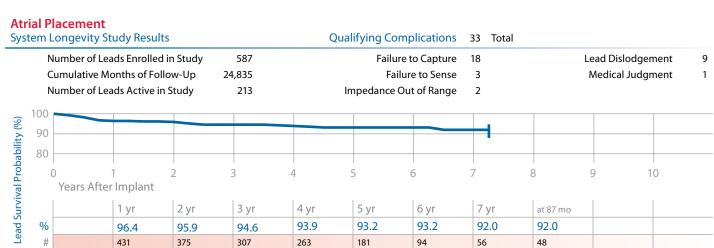
US Market Release	Nov-94	Serial Number Prefix	LDC	US Returned Product Ana	alysis
Registered US Implants	20,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	111
Estimated Active US Implants	5,400	Polarity	Bipolar	Electrical Malfunction	12
Advisories	None	Steroid	No	Other	1

em l	ongevity St	udy Result	S		Q	ualifying Co	mplications	11 Total			
١	Number of Lea	ds Enrolled	in Study	539		Electrical A	bandonment	1	Imp	edance Out of Rar	nge
C	Cumulative M	onths of Foll	ow-Up	22,441		Failu	ire to Capture	3	Insulation	n (not further defin	ed)
١	Number of Lea	ds Active in	Study	25		Fa	ilure to Sense	2		Oversens	ing
100											
90										1	
80											
	0	1	2	3	4	5	6	7	8	9 10	
	Years After	Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	
%		99.3	99.3	99.3	99.3	99.3	97.6	96.5	96.5	91.6	
#		353	296	249	191	139	96	83	64	49	

4568 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDD	US Returned Product An	alysis
Registered US Implants	69,700	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	198
Estimated Active US Implants	31,700	Polarity	Bipolar	Electrical Malfunction	18
Advisories	None	Steroid	Yes	Other	4



4574 CapSure Sense

Effective Sample Size

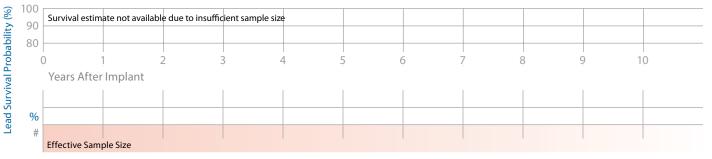
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBE	US Returned Product Analysis
Registered US Implants	39,900	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 7
Estimated Active US Implants	30,300	Polarity	Bipolar	Electrical Malfunction 2
Advisories	None	Steroid	Yes	Other 0

Atrial Placement

System Longevity Study Results Qualifying Complications 0 Total

Number of Leads Enrolled in Study 18 Cumulative Months of Follow-Up 325 Number of Leads Active in Study 16



4592 CapSure SP Novus

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	LER	US Returned Product Ana	alysis
Registered US Implants	74,400	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	13
Estimated Active US Implants	43,500	Polarity	Bipolar	Electrical Malfunction	5
Advisories	None	Steroid	Yes	Other	0

N	lumber of Leads Enrolle	d in Study	244		Failu	re to Capture	2			
	Cumulative Months of Fo	•	11,373			ilure to Sense	1			
	lumber of Leads Active i	•	84		Lead [Dislodgement	2			
00 90							1			
30										
(Years After Implant	2	3	4	5	6	7	8	9	10
		12	3 yr	4 yr	5 yr	6 yr	7 yr			
	1 yr	2 yr	J y							
%	97.8	97.8	97.8	97.8	97.0	97.0	97.0			

5023, 5023M CapSure SP

Product Characteristics

US Market Release	Nov-88	Serial Number Prefix	SX or LAS	US Returned Product Ana	alysis
Registered US Implants	9,900	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	15
Estimated Active US Implants	2,300	Polarity	Unipolar	Electrical Malfunction	7
Advisories	None	Steroid	Yes	Other	0

Ventricular Placement System Longevity Study Results Qualifying Complications 15 Total Number of Leads Enrolled in Study 1,353 **Conductor Fracture** 2 Impedance Out of Range Cumulative Months of Follow-Up 70,587 Extra Cardiac Stimulation 4 Number of Leads Active in Study 470 Failure to Capture 8 Lead Survival Probability (%) 100 90 9 12 13 14 16 17 10 11 15 18 Years After Implant 1 yr | 2 yr | 3 yr | 4 yr | 5 yr | 6 yr | 7 yr | 8 yr | 9 yr | 10 yr | 123 mo % 99.7 | 99.6 | 99.5 99.4 99.0 97.3 97.3 96.8 96.8 96.8 99.4 1,053 915 289 114 58 **Effective Sample Size**

5024, 5024M CapSure SP

Product Characteristics

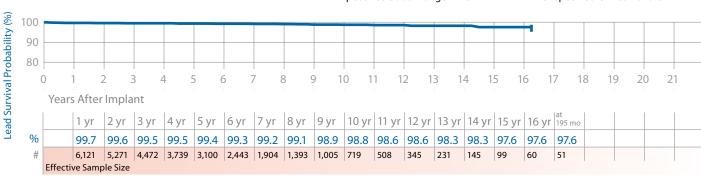
US Market Release	Mar-90	Serial Number Prefix	SY or LAT	US Returned Product Ar	nalysis
Registered US Implants	201,500	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	723
Estimated Active US Implants	56,200	Polarity	Bipolar	Electrical Malfunction	115
Advisories	None	Steroid	Yes	Other	29

Ventricular Placement

System Longevity Study Results

Qualifying Complications 48 Total

1	Insulation (ESC)	3	Conductor Fracture	8,140	Number of Leads Enrolled in Study
5	Insulation (not further defined)	2	Extra Cardiac Stimulation	431,840	Cumulative Months of Follow-Up
5	Lead Dislodgement	25	Failure to Capture	594	Number of Leads Active in Study
1	Oversensing	2	Failure to Sense		
1	Unspecified Clinical Failure	3	Impedance Out of Range		



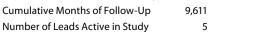
5026 CapSure

Product Characteristics

US Market Release	Feb-88	Serial Number Prefix	RZ	US Returned Product Ana	ılysis
Registered US Implants	7,400	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	60
Estimated Active US Implants	1,100	Polarity	Bipolar	Electrical Malfunction	7
Advisories	None	Steroid	Yes	Other	1

Ventricular Placement

System Longevity Study ResultsQualifying Complications4 TotalNumber of Leads Enrolled in Study168Electrical Abandonment1Cumulative Months of Follow-Up9,611Failure to Capture3





5033 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDK	US Returned Product Anal	lysis
Registered US Implants	2,400	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	6
Estimated Active US Implants	700	Polarity	Unipolar	Electrical Malfunction	1
Advisories	None	Steroid	Yes	Other	3

Ventricular Placement

Lead Survival Probability (%)

System Longevity Study Results

Qualifying Complications 26 Total

(Cumu	ılative	Month	Enrolle ns of Fo Active i	llow-L	Jp	1,89 96,19 26	5				Cond	ac Perfo uctor Fr ure to Ca	acture	7		Ins		edance (not fu Lead	ırther o		l)	4 1 2
100																							
90																							
90																							
80																							
	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	
	Yea	ars Aft	ter lm	plant																			
	1					1					1		lat	1				1	1				

	0	1 4		,		,	,	,		, ,	0 1		_) !) !	0 1	/	 17	20	21	
	Years	After	Impla	int																	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 141 mo								
%		99.7	99.6	99.1	99.0	98.7	98.3	97.7	97.2	96.4	96.4	95.7	95.7								
#		1,410	1,138	938	784	650	545	468	384	289	207	121	53								
	Effecti	ve Samp	ole Size																		

5034 CapSure Z

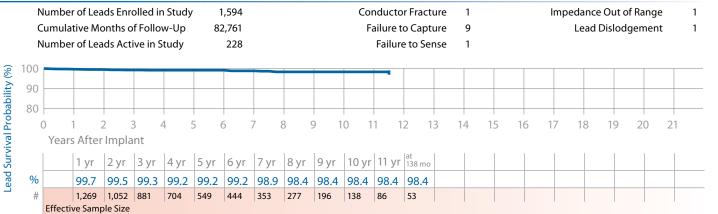
Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDF	US Returned Product Ana	alysis
Registered US Implants	56,300	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	85
Estimated Active US Implants	17,000	Polarity	Bipolar	Electrical Malfunction	31
Advisories	None	Steroid	Yes	Other	11

Ventricular Placement

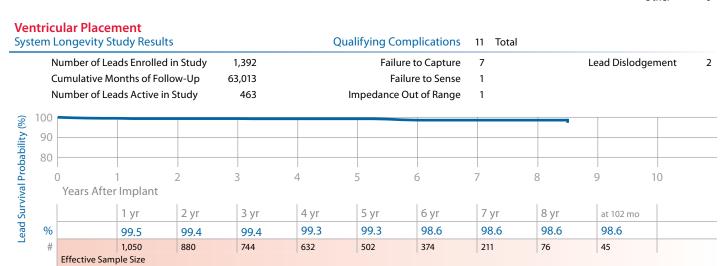
System Longevity Study Results

Qualifying Complications 13 Total



5054 CapSure Z Novus

US Market Release	Jun-98	Serial Number Prefix	LEH	US Returned Product Ana	lysis
Registered US Implants	85,400	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	43
Estimated Active US Implants	44,900	Polarity	Bipolar	Electrical Malfunction	16
Advisories	None	Steroid	Yes	Other	6



5068 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDJ	US Returned Product An	alysis
Registered US Implants	103,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	455
Estimated Active US Implants	40,600	Polarity	Bipolar	Electrical Malfunction	75
Advisories	None	Steroid	Yes	Other	15

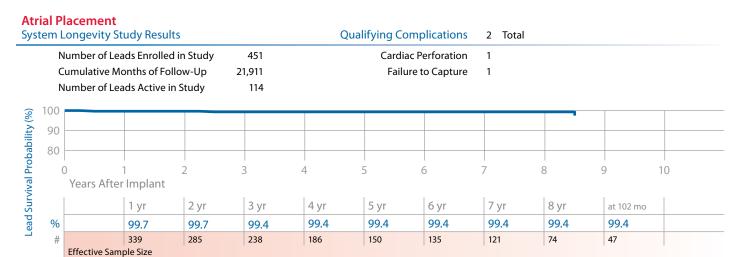
	ongevity Study Resu				, , ,	mplications				
Νι	umber of Leads Enrolle	ed in Study	968		Failu	re to Capture	2		Over	rsensing
Cι	ımulative Months of F	ollow-Up	32,929		Impedance	Out of Range	2			
Nι	umber of Leads Active	in Study	65		Lead [Dislodgement	1			
00										_
90										
80										
0	1	2	3	4	5	6	7	8	9	10
	Years After Implant									
		2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
L	1 yr	2 y i								
%	1 yr 99.6	99.6	99.6	99.2	99.2	99.2	99.2	98.4	98.4	98.4

Ventricular Placement

System Longevity Study Results Qualifying Complications 6 Total Number of Leads Enrolled in Study 1,359 Conductor Fracture 1 Lead Dislodgement 1 Cumulative Months of Follow-Up 37,307 Failure to Capture 3 Number of Leads Active in Study 119 Insulation (not further defined) 100 Lead Survival Probability (%) 90 80 3 4 5 8 9 10 Years After Implant 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 1 yr at 105 mo % 99.1 99.1 99.1 98.4 98.4 98.4 99.8 99.6 99.4 496 357 265 225 187 130 86 46 Effective Sample Size

5072 SureFix

US Market Release	Jun-98	Serial Number Prefix	LEM	US Returned Product Ana	alysis
Registered US Implants	8,900	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	28
Estimated Active US Implants	4,500	Polarity	Bipolar	Electrical Malfunction	5
Advisories	None	Steroid	Yes	Other	1



5076 CapSureFix Novus

Product Characteristics

US Market Release	Aug-00	Serial Number Prefix	PJN	US Returned Product An	nalysis
Registered US Implants	1,025,600	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	949
Estimated Active US Implants	723,800	Polarity	Bipolar	Electrical Malfunction	276
Advisories	None	Steroid	Yes	Other	84

	Advisories			None	Steroid		Yes				Other	84
	Placement Longevity St	udy Results				Qua	alifying Co	mplications	16 Total			
	Number of Lea Cumulative Mo Number of Lea	onths of Follov	w-Up	2,678 104,689 1,207		Ī	Condu Extra Cardia	ac Perforation actor Fracture ac Stimulation are to Capture	1 1 2 4	Insulation (no	nce Out of Range t further defined) ad Dislodgement Oversensing	2 1 4 1
(%) 900 900 900 900 900 900 900 900 900 90												
Lead Survival Probability (%)	0	1 2	2	3	4		5	6	7	8 9) 10	
urviva	Years After	Implant 1 yr	2 yr	3 yı	r 4	· yr	5 yr	6 yr	7 yr	at 90 mo		
ead S	5	99.7	99.6	99.		9.2	99.2	99.0	99.0	99.0		
<u> </u>	Effective Sam	1,965 ple Size	1,683	1,37	4 1	,020	628	425	147	55		

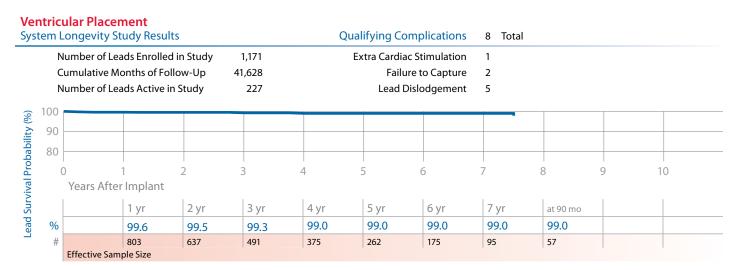
Ventricular Placement

N	lumber of Lea	ds Enrolled in	Study	1,521		Cardia	ac Perforation	1		Failure to Sense	
		onths of Follow	,	55,080		Condu	uctor Fracture	1	Impe	edance Out of Range	
N	lumber of Lea	ds Active in S	tudy	556		Failu	ire to Capture	3	·	Lead Dislodgement	
100								_			
90											
80											
(0	1 2	2	3	4	5	6	7	8	9 10	
	Years After	Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 87 mo		
%		99.6	99.4	99.3	99.1	99.1	99.1	99.1	99.1		
#		1,036	849	693	556	351	231	74	44		

5092 CapSure SP Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	US Returned Product Ana	alysis
Registered US Implants	111,800	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	48
Estimated Active US Implants	61,600	Polarity	Bipolar	Electrical Malfunction	28
Advisories	None	Steroid	Yes	Other	11



5524, 5524M CapSure SP

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	XV or LAV	US Returned Product Analysis
Registered US Implants	60,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 67
Estimated Active US Implants	21,000	Polarity	Bipolar	Electrical Malfunction 25
Advisories	None	Steroid	Yes	Other 7

Atrial Placement

Lead Survival Probability (%)

System Longevity Study Results Qualifying Complications 38 Total

Number of Leads Enrolled in Study	4,445	Conductor Fracture	1	Insulation (not further defined)	2
Cumulative Months of Follow-Up	241,326	Failure to Capture	22	Lead Dislodgement	4
Number of Leads Active in Study	482	Failure to Sense	4	Oversensing	4
		Impedance Out of Range	1		



5534 CapSure Z

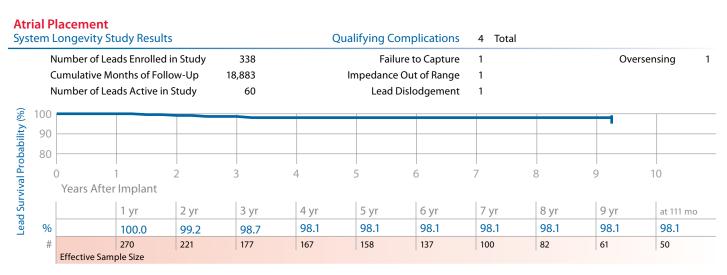
Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDG	US Returned Product Ana	alysis
Registered US Implants	26,300	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	29
Estimated Active US Implants	9,300	Polarity	Bipolar	Electrical Malfunction	8
Advisories	None	Steroid	Yes	Other	5

em L	ongevity Study R	esults			Qualifying Co	omplications	6 Total			
N	lumber of Leads Enr	olled in Study	261		Faile	ure to Capture	5			
C	Cumulative Months of	of Follow-Up	12,779		Impedance	Out of Range	1			
Ν	lumber of Leads Act	ive in Study	23							
00										
90										
						1				
90	0 1	2	3	4	5	6	7	8	9	10
80	0 1 Years After Impla	_	3	4	5	6	7	8	9	10
80		_	3 3 yr		5 5 yr	6 6 yr	7 at 78 mo	8	9	10
	Years After Impla	ant		4 yr			7 at 78 mo 97.1	8	9	10

5554 CapSure Z Novus

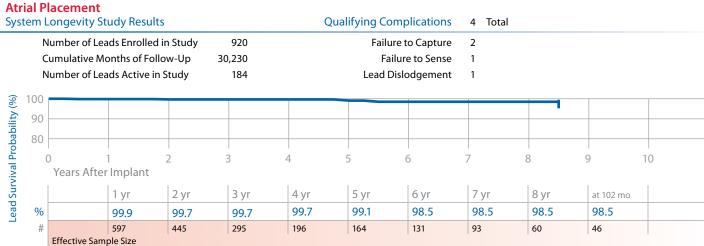
US Market Release	Jun-98	Serial Number Prefix	LEJ	US Returned Product Ana	lysis
Registered US Implants	54,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	8
Estimated Active US Implants	31,500	Polarity	Bipolar	Electrical Malfunction	12
Advisories	None	Steroid	Yes	Other	4



5568 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDN	US Returned Product An	alysis
Registered US Implants	70,400	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	264
Estimated Active US Implants	45,000	Polarity	Bipolar	Electrical Malfunction	15
Advisories	None	Steroid	Yes	Other	12

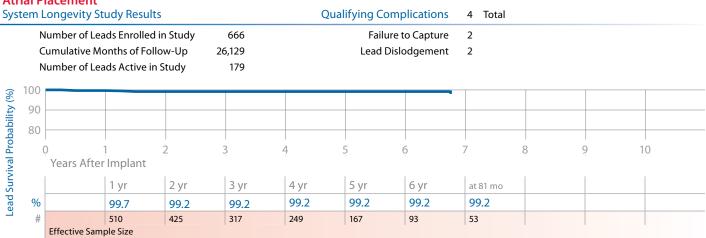


5592 CapSure SP Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEU	US Returned Product Ana	alysis
Registered US Implants	27,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	6
Estimated Active US Implants	18,100	Polarity	Bipolar	Electrical Malfunction	3
Advisories	None	Steroid	Yes	Other	0

Atrial Placement



5594 CapSure SP Novus

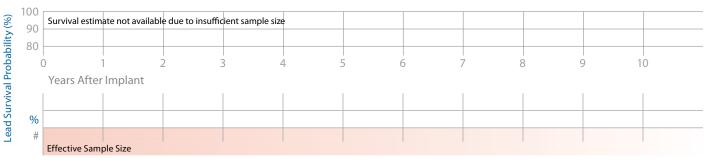
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	LFD	US Returned Product Analy	/sis
Registered US Implants	10,900	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	0
Estimated Active US Implants	8,100	Polarity	Bipolar	Electrical Malfunction	4
Advisories	None	Steroid	Yes	Other	0

Atrial Placement

System Longevity Study Results **Qualifying Complications** 0 Total

Number of Leads Enrolled in Study 18 Cumulative Months of Follow-Up 1,068 Number of Leads Active in Study 12



6940 CapSureFix

US Market Release	Oct-98	Serial Number Prefix	TCP	US Returned Product An	alysis
Registered US Implants	25,500	Type and/or Fixation	Transvenous, A or V, Screw-in	Implant Damage	114
Estimated Active US Implants	10,100	Polarity	Bipolar	Electrical Malfunction	21
Advisories	None	Steroid	Yes	Other	3

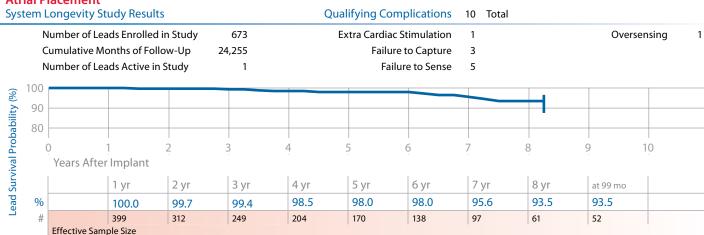
tem l	Placement Longevity St	udy Result	ts		Q	ualifying Co	mplications	7 Total				
		umber of Leads Enrolled in Study umulative Months of Follow-Up		818 38,362	Conductor Fracture Failure to Sense		1 2		Ove	Oversensing		
1	Number of Lea	ads Active in	n Study	151		Lead [Dislodgement	1				
100										_		
90												_
80												
	0	1	2	3	4	5	6	7	8	9	10	
	Years Afte	Implant										
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 111 mg	0
%		99.9	99.9	98.8	98.5	98.5	98.5	98.5	98.5	98.5	98.5	
#		598	500	400	330	276	225	195	158	61	48	

6957 Spectraflex

Product Characteristics

US Market Release	Jul-79	Serial Number Prefix	VC	US Returned Product Ana	alysis
Registered US Implants	29,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	85
Estimated Active US Implants	2,000	Polarity	Unipolar	Electrical Malfunction	39
Advisories	None	Steroid	No	Other	25

Atrial Placement



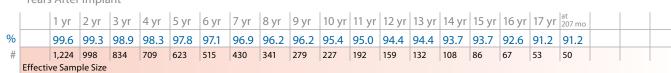
Ventricular Placement

System Longevity Study Results

Qualifying Complications 42 Total

Number of Leads Enrolled in Study	1,853	Conductor Fracture	14	Impedance Out of Range	1
Cumulative Months of Follow-Up	96,335	Extra Cardiac Stimulation	2	Insulation (not further defined)	1
Number of Leads Active in Study	17	Failure to Capture	18	Oversensing	4
,		Failure to Sense	2	3	





6957J Spectraflex

Product Characteristics

US Market Release	Sep-80	Serial Number Prefix	GG	US Returned Product Ana	alysis
Registered US Implants	30,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	74
Estimated Active US Implants	2,100	Polarity	Unipolar	Electrical Malfunction	30
Advisories	None	Steroid	No	Other	30

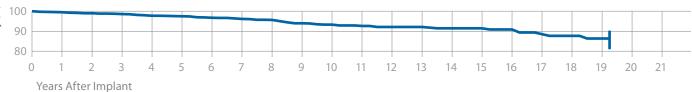
Atrial Placement

System Longevity Study Results

Qualifying Complications 88 Total

Number of Leads Enrolled in Study	2,348	Conductor Fracture	13	Insulation (ESC)	1
Cumulative Months of Follow-Up	160,477	Extra Cardiac Stimulation	3	Insulation (not further defined)	3
Number of Leads Active in Study	22	Failure to Capture	48	Lead Dislodgement	2
		Failure to Sense	14	Oversensing	3
		land a dam an Out of Dam and	- 1		

Impedance Out of Range



		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	18 yr	19 yr	at 231 mo	
%		99.5	99.0	98.6	97.8	97.5	96.8	96.2	95.7	94.0	93.3	92.7	92.2	92.2	91.5	91.5	90.9	88.6	87.7	86.4	86.4	
#		1,775	1,556	1,359	1,204	1,075	914	765	651	553	464	393	320	257	207	160	125	99	70	54	49	
	Effecti	ve Samı	ole Size																			

6961 Tenax

Lead Survival Probability (%)

Product Characteristics

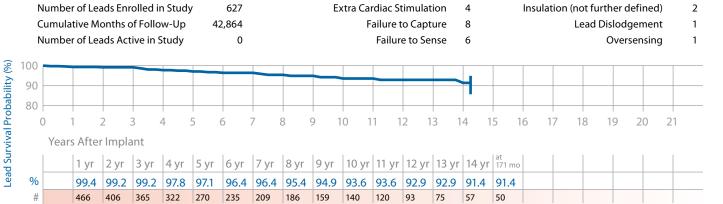
US Market Release	Jan-78	Serial Number Prefix	ТВ	US Returned Product Analysis
Registered US Implants	44,700	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 103
Estimated Active US Implants	2,100	Polarity	Unipolar	Electrical Malfunction 27
Advisories	None	Steroid	No	Other 0

Ventricular Placement

System Longevity Study Results

Effective Sample Size

Qualifying Complications 22 Total



6962 Tenax

Product Characteristics

	US Market Release	Jan-78	Serial Number Prefix	UB	US Returned Product An	alysis
	Registered US Implants	70,600	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	170
	Estimated Active US Implants	3,200	Polarity	Bipolar	Electrical Malfunction	84
Advisories		None	Steroid	No	Other	0

Ventricular Placement

System Longevity Study Results

Qualifying Complications 52 Total

Number of Leads Enrolled in Study	1,483	Conductor Fracture	5	Impedance Out of Range	3
Cumulative Months of Follow-Up	109,942	Extra Cardiac Stimulation	1	Insulation (not further defined)	2
Number of Leads Active in Study	2	Failure to Capture	27	Lead Dislodgement	1
		Failure to Sense	10	Oversensing	3



		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	18 yr	19 yr	20 yr	
%		99.0	98.2	97.4	96.9	96.7	96.5	96.4	96.2	96.0	95.3	95.0	94.6	93.5	93.5	93.5	92.1	91.3	90.4	90.4	90.4	
#		1,082	968	857	757	676	611	559	489	420	364	306	260	213	177	147	122	103	83	65	51	
	Effecti	ve Samı	ple Size																			

20 yr

18 yr

16 yr

		_					01 + 10	Q + 10					01 + 10				
		14 yr			95.5 +2.4/-4.9 at 150 mo		91.9 +3.1/-4.7	62.9 +4.0/-4.2	95.0 +2.3/-4.2 at 147 mo				95.0 +2.1/-3.4	84.3 +4.6/-6.4 at 159 mo			
		12 yr			96.8 +1.7/-3.3	50.6 +5.0/-5.2 at 129 mo	92.8 +2.7/-4.2	65.7 +3.5/-3.7	95.0 +2.3/-4.2	98.3 +1.4/-7.5 at 126 mo			96.1 +1.4/-2.1	85.5 +4.2/-5.9		92.1 +3.0/-4.5 at 138 mo	94.2 +2.1/-3.2 at 129 mo
		10 yr			97.7 +1.1/-2.4	51.5 +4.8/-5.0	95.0 +1.9/-3.0	69.8 +3.1/-3.4	96.3 +1.5/-2.5	99.8 +0.1/-0.7	95.3 +2.5/-5.2 at 105 mo	94.4 +3.1/-6.8 at 114 mo	96.1 +1.4/-2.1	89.2 +3.1/-4.1		94.8 +1.5/-2.1	94.2 +2.1/-3.2
		8 yr			97.7 +1.1/-2.4	58.1 +4.2/-4.5	96.0 +1.6/-2.4	77.8 +2.5/-2.7	96.8 +1.3/-1.9	99.8 +0.1/-0.7	96.5 +1.9/-3.8	95.7 +2.5/-5.9	97.5 +0.8/-1.3	93.6 +1.9/-2.6		96.0 +1.1/-1.4	96.0
		7 yr			98.5 +0.8/-1.8	64.1 +3.7/-4.1	96.0 +1.6/-2.4	83.9 +2.0/-2.2	97.2 +1.1/-1.9	99.8 +0.1/-0.7	97.5 +1.3/-2.7	95.7 +2.5/-5.9	98.2 +0.6/-1.0	94.6 +1.7/-2.3		97.1 +0.8/-1.1	96.4
		6 yr			98.8 +0.7/-1.5	69.4 +3.4/-3.7	96.4 +1.4/-2.3	88.1 +1.7/-1.9	98.2 +0.8/-1.3	99.8 +0.1/-0.7	97.5 +1.3/-2.7	96.8 +2.0/-5.3	98.3 +0.6/-0.9	96.9		97.2 +0.8/-1.0	97.5 +0.8/-1.2
		5 yr			99.1 +0.5/-1.2	77.1 +2.9/-3.2	97.6 +1.1/-1.8	92.6 +1.2/-1.5	98.6 +0.6/-1.1	99.8	98.1 +1.0/-2.2	97.7 +1.6/-4.7	98.7 +0.5/-0.7	97.9 +0.8/-1.2	97.1 +1.9/-5.9 at 51 mo	97.6 +0.6/-0.9	98.0
ity (%)		4 yr	99.4 +0.5/-3.8	100.0 at 45 mo	99.1	87.4 +2.1/-2.4	98.8 +0.7/-1.2	95.9 +0.8/-1.1	98.6 +0.6/-1.1	99.8 +0.1/-0.7	98.5 +0.8/-1.9	98.6 +1.1/-4.1	99.1 +0.4/-0.6	98.7 +0.5/-1.0	97.1 +1.9/-5.9	98.1 +0.5/-0.8	98.3
Device Survival Probability (%)	ant	3 yr	99.4 +0.5/-3.8	100.0	99.4 +0.4/-1.1	96.3 +1.0/-1.4	99.1 +0.5/-1.2	98.4 +0.5/-0.7	98.8 +0.5/-1.1	99.8 +0.1/-0.7	98.8 +0.7/-1.7	99.4 +0.5/-3.5	99.5 +0.2/-0.5	99.1 +0.4/-0.8	97.1 +1.9/-5.9	98.3 +0.5/-0.7	98.8 +0.4/-0.7
Survival	Years After Implant	2 yr	99.4 +0.5/-3.8	100.0	99.4 +0.4/-1.1	99.3 +0.4/-0.7	99.2 +0.5/-1.0	99.1 +0.4/-0.5	99.3 +0.4/-0.9	99.8 +0.1/-0.7	99.4 +0.4/-1.4	99.4 +0.5/-3.5	99.6 +0.2/-0.4	99.2 +0.4/-0.7	97.1 +1.9/-5.9	98.8 +0.4/-0.6	98.8 +0.4/-0.7
Device	Years A	1 yr	99.4 +0.5/-3.8	100.0	99.4 +0.4/-1.1	99.8 +0.1/-0.5	99.4 +0.4/-1.0	99.6 +0.2/-0.3	99.9 +0.1/-0.6	99.9 +0.1/-0.5	99.4 +0.4/-1.4	99.4 +0.5/-3.5	99.9 +0.1/-0.4	99.4 +0.3/-0.7	97.1 +1.9/-5.9	99.0 +0.4/-0.5	99.3
Months in Study			5,129	4,983	47,264	540 4 277 71,653 Survival Below Expectations	54,409	543 10 316 151,162 Survival Below Expectations	65,853	52,403	28,545	15,351	131,441	77,493	6,490	124,306	89,241
su	ifying olicatio		-	0	12	277 w Expe	25	316 w Expe	20	ж	10	7	33	53	9	28	37
γbu32 ni s	vitoA s	греэд	95	82	146	4 val Belo	7	10 val Belo	341	23	39	6	44	49	39	552	457
pə	s Enrol	греэд	166	148	711		851		1,158	1,214	539	259	2,364	1,690	109	2,411	1,799
əseələ	arket R	w sn	Aug-05	Aug-05	Jul-86	Feb-89	Nov-82	Jul-83	Aug-91	Oct-91	Not US released	Aug-88	Jan-89	Jan-89	Jan-97	Mar-96	Mar-96
	ıpeı	Сһап	Atrial	Vent	Vent	Vent page 157	Vent	Vent	Vent	Vent	Vent	Vent	Atrial	Vent	Atrial	Atrial	Vent
	λį	lims4	SelectSecure	SelectSecure	CapSure	CapSure Vent Feb-89 1, Advisories: See page 157 – 1993 Lead	Target Tip	Target Tip Vent Jul-83 2,, Advisories: See page 158 – 1991 Lead	CapSure SP	CapSure SP	CapSure Z	Screw-In	Screw-In	Screw-In	CapSureFix	CapSureFix	CapSureFix
		ppoM imuM	3830	3830	4003, 4003M	4004, 4004M	4011	4012	4023	4024	4033	4057, 4057M	4058, 4058M	4058, 4058M	4067	4068	4068

91.9 +3.1/-4.7 at 183 mo

95.0 +2.1/-3.4 at 177 mo

Lead Survival Summary (95% Confidence Interval)

Lead Survival Summary continued

		20 yr															
	_	18 yr															
		16 yr															
		14 yr										83.6 +5.0/-6.8 at 159 mo					
		12 yr										84.8 +4.6/-6.3		99.0 +0.6/-1.2 at 123 mo		96.9 +1.8/-4.4 at 126 mo	
	_	10 yr									66.1 +7.7/-9.2 at 105 mo	87.5 +3.9/-5.5		99.0 +0.6/-1.2		96.9 +1.8/-4.4	91.6 +4.5/-8.9 at 108 mo
	_	8 yr							98.0 +0.8/-1.2 at 90 mo		69.9 +7.0/-8.7	91.5 +2.9/-4.3		99.0 +0.6/-1.2		96.9 +1.8/-4.4	96.5
	_	7 yr							98.0 +0.8/-1.2		73.0 +6.5/-8.2	94.7 +2.0/-3.2		99.0	97.9 +1.4/-4.2 at 78 mo	96.9 +1.8/-4.4	96.5
		6 yr	mple size		99.2 +0.4/-1.2 at 66 mo			98.2 +1.5/-10.5 at 63 mo	98.0 +0.8/-1.2	mple size	82.2 +5.1/-6.8	95.6 +1.8/-2.8		99.0	97.9 +1.4/-4.2	97.8 +1.4/-3.6	97.6
	_	5 yr	Survival estimate not available due to insufficient sample size	100.0 at 51 mo	99.2 +0.4/-1.2		99.7 +0.2/-1.0 at 51 mo	100.0	98.0 +0.8/-1.2	Survival estimate not available due to insufficient sample size	90.3	96.7	98.1 +1.4/-5.3 at 57 mo	99.0	97.9 +1.4/-4.2	97.8 +1.4/-3.6	99.3
ility (%)	_	4 yr	due to ins	100.0	99.2 +0.4/-1.2	99.5 +0.3/-1.0	99.7 +0.2/-1.0	100.0	98.4 +0.6/-1.1	due to ins	98.2 +1.1/-3.0	98.0 +1.0/-2.0	98.1 +1.4/-5.3	99.0	97.9 +1.4/-4.2	97.8 +1.4/-3.6	99.3
Probabil	ant	3 yr	x available	100.0	99.2 +0.4/-1.2	99.5 +0.3/-1.0	99.7 +0.2/-1.0	100.0	98.7 +0.5/-1.0	x available	99.1	99.1 +0.6/-1.5	98.1 +1.4/-5.3	99.3 +0.4/-1.0	98.8 +0.9/-3.6	99.1 +0.7/-2.8	99.3
Device Survival Probability (%)	Years After Implant	2 yr	stimate no	100.0	99.2 +0.4/-1.2	99.5 +0.3/-1.0	99.7 +0.2/-1.0	100.0	98.8 +0.5/-0.9	stimate no	100.0	99.6 +0.3/-1.2	98.1 +1.4/-5.3	99.3 +0.4/-1.0	99.4 +0.5/-3.5	99.1 +0.7/-2.8	99.3
Device	Years A	1 yr	Survival e	100.0	99.3 +0.5/-1.1	99.7 +0.2/-0.9	99.7 +0.2/-1.0	100.0	98.9 +0.5/-0.9	Survival e	100.0	99.6 +0.3/-1.2	98.1 +1.4/-5.3	99.6 +0.3/-0.7	100.0	99.1 +0.7/-2.8	99.3
Months o in Study			52	4,770	24,361	17,688	17,812	9,940	55,839	3,278	19,879 ctations	39,833	7,194	40,567	11,286	18,465	22,441
su	ifying olicatio		0	0	5	m	2	m	17	-	48 ow Expe	35	4	9	4	9	=
γbut2 ni s	evitoA s	рвэд	-	83	516	618	555	6	512	9	1 ival Belo	4	15	57	16	10	25
pə	s Enroll	реәղ	-	100	622	745	899	260	1,145	29	368 ad Survi	009	121	911	206	294	539
elease	arket R	w sn	Jun-02	Jun-02	Jun-02	Feb-04	Feb-04	Jul-89	Sep-98	Jul-86	Mar-90 368 1 48 19,875 6 - 1996 Lead Survival Below Expectations	Jul-83	Aug-91	Oct-91	Not US released	Aug-88	Nov-94
	ıpeı	Сһап	Atrial	Vent	Vent	Atrial	Vent	Vent	Vent	Atrial	Atrial See page 156	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
	ίλ	ims7	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	Target Tip	CapSure SP Novus	CapSure	CapSure Advisories: Se	Target Tip	CapSure SP	CapSure SP	CapSure Z	Screw-In	Screw-In
		mnN	4073	4073	4074	4076	4076	4081	4092	4503, 4503M	4504, 4504M	4512	4523	4524	4533	4557, 4557M	4558M

				ı	ı	ı			ı		I	I	I		ı	I			
		20 yr																	
		18 yr					97.6 +1.2/-2.3 at 195 mo												
		16 yr					97.6 +1.2/-2.3											97.1 +1.0/-1.5 at 174 mo	
		14 yr					98.3 +0.7/-1.0											97.1	
		12 yr				96.8 +1.4/-2.6 at 123 mo	98.6 +0.5/-0.7		95.7 +1.6/-2.6 at 141 mo	98.4 +0.7/-1.5 at 138 mo								97.1	
		10 yr				96.8 +1.4/-2.6	98.8 +0.4/-0.6		96.4 +1.3/-2.0	98.4 +0.7/-1.5	98.6 +0.7/-1.3 at 102 mo	98.4 +1.1/-3.3	98.4 +1.0/-2.7 at 105 mo	99.4 +0.4/-1.9 at 102 mo				97.6	
		8 yr	92.0 +2.8/-4.1 at 87 mo			97.3 +1.2/-2.0	99.1		97.2 +1.0/-1.5	98.4 +0.7/-1.5	98.6 +0.7/-1.3	98.4 +1.1/-3.3	98.4 +1.0/-2.7	99.4 +0.4/-1.9	99.0 +0.4/-0.8 at 90 mo	99.1 +0.5/-0.8 at 87 mo	99.0 +0.6/-1.1 at 90 mo	98.4 +0.6/-0.7	
		7 yr	92.0 +2.8/-4.1		97.0	97.3 +1.2/-2.0	99.2 +0.2/-0.3	95.7 +2.7/-7.2 at 75 mo	97.7 +0.9/-1.4	98.9 +0.5/-0.9	98.6 +0.7/-1.3	99.2 +0.5/-1.5	98.4 +1.0/-2.7	99.4 +0.4/-1.9	99.0	99.1 +0.5/-0.8	99.0	98.9	
		6 yr	93.2 +2.1/-3.0	mple size	97.0	99.0	99.3 +0.2/-0.2	95.7 +2.7/-7.2	98.3 +0.6/-1.2	99.2 +0.4/-0.8	98.6 +0.7/-1.3	99.2 +0.5/-1.5	99.1 +0.5/-1.5	99.4 +0.4/-1.9	99.0	99.1 +0.5/-0.8	99.0	99.2 +0.3/-0.4	
		5 yr	93.2 +2.1/-3.0	ufficient sa	97.0	99.4	99.4	97.1	98.7	99.2 +0.4/-0.8	99.3	99.2	99.1	99.4 +0.4/-1.9	99.2 +0.3/-0.6	99.1	99.0	99.3	
lity (%)		4 yr	93.9 +1.9/-2.7	due to ins	97.8	99.4	99.5	97.1	99.0	99.2 +0.4/-0.8	99.3 +0.3/-0.8	99.2 +0.5/-1.5	99.1	99.4 +0.4/-1.9	99.2 +0.3/-0.6	99.1	99.0	99.4	
Probabi	lant	3 yr	94.6	ot available	97.8 +1.4/-3.5	99.5	99.5	98.2 +1.4/-5.2	99.1	99.3 +0.3/-0.7	99.4 +0.3/-0.6	99.6 +0.3/-0.9	99.4 +0.4/-1.1	99.4	99.5	99.3 +0.3/-0.8	99.3	99.5	
evice Survival Probability (%)	Years After Implant	2 yr	95.9	estimate not available due to insufficient sample size	97.8	99.6 +0.3/-0.6	99.6	99.2 +0.7/-4.8	99.6	99.5 +0.3/-0.6	99.4 +0.3/-0.6	99.6 +0.3/-0.9	99.6 +0.3/-0.8	99.7 +0.3/-1.5	99.6	99.4 +0.3/-0.6	99.5 +0.3/-0.8	99.8	
Device	Years A	1 yr	96.4	Survival	97.8 +1.4/-3.5	99.7 +0.2/-0.5	99.7 +0.1/-0.2	100.0	99.7 +0.2/-0.4	99.7 +0.2/-0.5	99.5	99.6 +0.3/-0.9	99.8 +0.1/-0.6	99.7 +0.3/-1.5	99.7 +0.1/-0.4	99.6 +0.2/-0.5	99.6 +0.2/-0.7	99.8	
Months o in Study			24,835	325	11,373	70,587	431,840	9,611	96,195	82,761	63,013	32,929	37,307	21,911	104,689	55,080	41,628	241,326	
su	/ing oitsoi	Qualify Compli	33	0	5	15	47	4	56	13	=	9	9	2	16	0	∞	38	
γbut2 ni ε	evitoA	r speə7	213	16	84	470	594	5	263	228	463	65	119	114	1,207	556	227	482	
pə	Iloau	l sbas l	587	18	244	1,353	8,140	168	1,899	1,594	1,392	896	1,359	451	2,678	1,521	1,171	4,445	
əseələ	ket R	16M 2U	Jan-97	Jun-02	Oct-98	Nov-88	Mar-90	Feb-88	Feb-96	Feb-96	Jun-98	Jan-97	Jan-97	Jun-98	Aug-00	Aug-00	Jun-98	Mar-90	
) 6 L	Chamb	Atrial	Atrial	Atrial	Vent	Vent	Vent	Vent	Vent	Vent	Atrial	Vent	Atrial	Atrial	Vent	Vent	Atrial	
		Family	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure SP	CapSure	CapSure Z	CapSure Z	CapSure Z Novus	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus	CapSure SP	
		ləboM edmuM	4568	4574	4592	5023, 5023M	5024, 5024M	5026	5033	5034	5054	5068	5068	5072	5076	5076	5092	5524, 5524M	

$\overline{}$
(1)
=
-
_
9
0
\rightarrow
Œ
ā
_
_
_
\subseteq
$\overline{}$
.=
S
_
<u></u>
10
>
.=
>
_
$\overline{}$
.=
S
_
$\boldsymbol{\sigma}$
ea(
7.

				ı									
		20 yr									86.4 +3.9/-5.4 at 231 mo		90.4
		18 yr								91.2 +3.4/-5.4 at 207 mo	87.7 +3.3/-4.5		90.4
	_	16 yr								92.6 +2.7/-4.2	90.9 +2.1/-2.7	91.4 +3.5/-5.7 at 171 mo	92.1
	_	14 yr								93.7 +2.2/-3.2	91.5 +1.9/-2.5	91.4 +3.5/-5.7	93.5 +1.8/-2.6
	_	12 yr								94.4 +1.9/-2.7	92.2 +1.7/-2.2	92.9 +2.7/-4.3	94.6
	_	10 yr		98.1 +1.2/-3.0 at 111 mo	98.5 +1.0/-3.2 at 102 mo			98.5 +0.8/-1.6 at 111 mo	93.5 +3.1/-5.9 at 99 mo	95.4 +1.5/-2.2	93.3 +1.5/-1.9	93.6 +2.5/-3.8	95.3 +1.3/-1.8
	_	8 yr		98.1 +1.2/-3.0	98.5 +1.0/-3.2			98.5 +0.8/-1.6	93.5 +3.1/-5.9	96.2 +1.2/-1.7	95.7 +1.0/-1.3	95.4 +1.9/-3.1	96.2
		7 yr	97.1 +1.6/-3.5 at 78 mo	98.1 +1.2/-3.0	98.5 +1.0/-3.2	99.2 +0.5/-1.2 at 81 mo		98.5 +0.8/-1.6	95.6 +2.3/-4.6	96.9	96.2 +1.0/-1.2	96.4 +1.5/-2.7	96.4
		6 yr	97.1 +1.6/-3.5	98.1 +1.2/-3.0	98.5 +1.0/-3.2	99.2 +0.5/-1.2	mple size	98.5 +0.8/-1.6	98.0 +1.2/-2.9	97.1 +1.0/-1.4	96.8 +0.8/-1.1	96.4 +1.5/-2.7	96.5
	_	5 yr	97.1 +1.6/-3.5	98.1 +1.2/-3.0	99.1 +0.7/-2.6	99.2 +0.5/-1.2	Survival estimate not available due to insufficient sample size	98.5 +0.8/-1.6	98.0	97.8 +0.8/-1.2	97.5 +0.7/-1.0	97.1 +1.3/-2.3	96.7 +0.9/-1.4
ity (%)	_	4 yr	97.1 +1.6/-3.5	98.1 +1.2/-3.0	99.7 +0.2/-1.1	99.2 +0.5/-1.2	due to ins	98.5 +0.8/-1.6	98.5 +0.9/-2.5	98.3 +0.7/-1.0	97.8 +0.6/-0.8	97.8 +1.1/-2.0	96.9 +0.9/-1.2
Probabil	ant	3 yr	97.8 +1.3/-3.1	98.7 +0.9/-2.7	99.7 +0.2/-1.1	99.2 +0.5/-1.2	ıt available	98.8 +0.6/-1.6	99.4 +0.4/-2.0	98.9 +0.4/-0.9	98.6 +0.4/-0.7	99.2 +0.5/-1.3	97.4 +0.8/-1.2
evice Survival Probability (%)	Years After Implant	2 yr	97.8 +1.3/-3.1	99.2 +0.6/-2.4	99.7 +0.2/-1.1	99.2 +0.5/-1.2	stimate no	99.9 +0.1/-0.8	99.7 +0.3/-1.6	99.3 +0.3/-0.6	99.0	99.2 +0.5/-1.3	98.2 +0.7/-0.9
Device	Years A	1 yr	98.3 +1.1/-2.8	100.0	99.9 +0.1/-0.8	99.7 +0.2/-1.1	Survivale	99.9 +0.1/-0.8	100.0	99.6 +0.2/-0.5	99.5 +0.2/-0.5	99.4 +0.4/-1.1	99.0
Months in Study			12,779	18,883	30,230	26,129	1,068	38,362	24,255	96,335	160,477	42,864	109,942
su	ifying plicatio		9	4	4	4	0	7	10	42	88	22	52
γbu32 ni e			23	09	184	179	12	151	-	17	22	0	2
pə	llorn3 s	реәղ	261	338	920	999	81	818	673	1,853	2,348	627	1,483
elease	larket R	w sn	Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	Oct-98	Jul-79	Jul-79	Sep-80	Jan-78	Jan-78
	nber	Сһап	Atrial	Atrial .	Atrial .	Atrial .	Atrial .	Atrial	Atrial .	Vent	Atrial	Vent	Vent .
	λļ	ims7	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	CapSureFix	Spectraflex	Spectraflex	Spectraflex	Tenax	Tenax
		poM muM	534	554	268	592	594	940	1957	1957	6957	1961	3962

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
3830	SelectSecure	Aug-05	12,200	10,600	21	5	1
4003, 4003M	CapSure	Jul-86	38,000	5,300	24	60	2
4004, 4004M	CapSure	Feb-89	72,600	5,800	56	688	19
4011	Target Tip	Nov-82	58,400	6,200	29	152	5
4012	Target Tip	Jul-83	93,700	6,500	50	827	34
4023	CapSure SP	Aug-91	41,200	9,600	47	21	6
4024	CapSure SP	Oct-91	222,100	56,100	264	135	34
4033	CapSure Z	Not US released	NA	NA	2	0	0
4057, 4057M	Screw-in	Aug-88	10,100	1,800	39	6	4
4058, 4058M	Screw-in	Jan-89	101,900	20,800	388	261	23
4067	CapSureFix	Jan-97	1,000	300	3	1	1
4068	CapSureFix	Mar-96	124,800	43,900	406	111	11
4073	CapSure Sense	Jun-02	600	400	1	0	0
4074	CapSure Sense	Jun-02	63,000	45,200	13	8	1
4076	CapSureFix Novus	Feb-04	199,200	165,500	96	13	8
4081	Target Tip	Jul-89	3,900	800	4	5	0
4092	CapSure SP Novus	Sep-98	151,000	83,100	39	19	5
4503, 4503M	CapSure	Jul-86	8,000	1,500	2	12	0
4504, 4504M	CapSure	Mar-90	15,400	1,700	5	172	4
4512	Target Tip	Jul-83	10,300	1,200	4	85	8
4523	CapSure SP	Aug-91	11,200	3,200	5	2	1
4524	CapSure SP	Oct-91	101,700	32,300	47	31	8
4533	CapSure Z	Not US released	NA	NA	0	0	0
4557, 4557M	Screw-in	Aug-88	19,700	4,400	53	14	4
4558M	Screw-in	Nov-94	20,000	5,400	111	12	1
4568	CapSureFix	Jan-97	69,700	31,700	198	18	4
4574	CapSure Sense	Jun-02	39,900	30,300	7	2	0
4592	CapSure SP Novus	Oct-98	74,400	43,500	13	5	0
5023, 5023M	CapSure SP	Nov-88	9,900	2,300	15	7	0
5024, 5024M	CapSure SP	Mar-90	201,500	56,200	723	115	29
5026	CapSure	Feb-88	7,400	1,100	60	7	1
5033	CapSure Z	Feb-96	2,400	700	6	1	3
5034	CapSure Z	Feb-96	56,300	17,000	85	31	11
5054	CapSure Z Novus	Jun-98	85,400	44,900	43	16	6
5068	CapSureFix	Jan-97	103,100	40,600	455	75	15
5072	SureFix	Jun-98	8,900	4,500	28	5	1
5076	CapSureFix Novus	Aug-00	1,025,600	723,800	949	276	84
5092	CapSure SP Novus	Jun-98	111,800	61,600	48	28	11
5524, 5524M	CapSure SP	Mar-90	60,600	21,000	67	25	7
5534	CapSure Z	Feb-96	26,300	9,300	29	8	5
5554	CapSure Z Novus	Jun-98	54,800	31,500	8	12	4
	•						
5568	CapSureFix	Jan-97	70,400	45,000	264	15	12

continued

US Returned Product Analysis Summary continued

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5592	CapSure SP Novus	Jun-98	27,800	18,100	6	3	0
5594	CapSure SP Novus	Jun-01	10,908	1,700	0	4	0
6940	CapSureFix	Oct-98	25,500	10,100	114	21	3
6957	Spectraflex	Jul-79	29,100	2,000	85	39	25
6957J	Spectraflex	Sep-80	30,000	2,100	74	30	30
6961	Tenax	Jan-78	44,700	2,100	103	27	0
6962	Tenax	Jan-78	70,600	3,200	170	84	0

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4003, 4003M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4003) IS-1 UNI (4003M)
4004, 4004M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Porous/Steroid	3.2 mm Low Profile (4004) IS-1 BI (4004M)
4011	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	5 mm
4012	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4057, 4057M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm (4057) IS-1 UNI (4057M)
4058, 4058M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/1 Filars	2.0 mm Helix	3.2 mm Low Profile (4058) IS-1 BI (4058M)
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4081	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	IS-1 UNI w/Removable 5 mm Sleeve
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4503, 4503M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4503) IS-1 UNI (4503M)
4504, 4504M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 3/4 Filars	Porous/Steroid	3.2 mm Low Profile (4504) IS-1 BI (4504M)
4512	Target Tip	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 2/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4557, 4557M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm (4557) IS-1 UNI (4557M)
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5023, 5023M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Porous Platinized/ Steroid	5 mm (5023) IS-1 UNI (5023M)

continued

Reference Chart continued

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5026	CapSure	Transvenous Ventricular Tines	Silicone	MP35N 6/4 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 BI (5524M)
5534	CapSure Z	Transvenous Atrial-J Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6940	CapSureFix	Transvenous A or V Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI
6957	Spectraflex	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm
6957J	Spectraflex	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm
6961	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 3 Filars	Ring Tip	5 mm
6962	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Ring Tip	5 mm Bifurcated

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

Product Characteristics

US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	US Returned Product Ana	alysis
Registered US Implants	23,100	Type and/or Fixation	Myocardial Stab-in, V or A, Peds	Implant Damage	15
Estimated Active US Implants	2,500	Polarity	Unipolar	Electrical Malfunction	97
Advisories	None	Steroid	No	Other	28

System Longevity Study Results

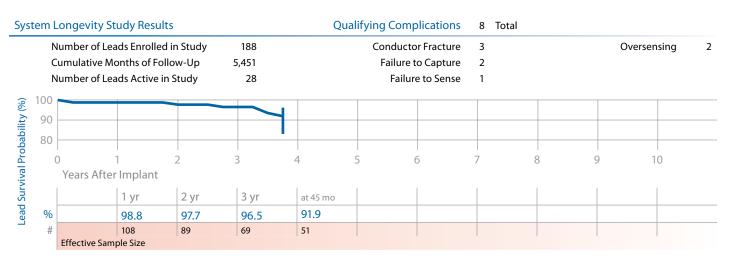
Qualifying Complications 10 Total

Number of Leads Enrolled in Study	179	Failure to Capture	4	Insulation (ESC)	1
Cumulative Months of Follow-Up	6,512	Failure to Sense	3	Insulation (not further defined)	1
Number of Leads Active in Study	4	Impedance Out of Range	1		



4965 CapSure Epi

US Market Release	Sep-96	Serial Number Prefix	LBT	US Returned Product Ana	nalysis 8 115 2
Registered US Implants	17,700	Type and/or Fixation	Epicardial Suture-On V or A	Implant Damage	8
Estimated Active US Implants	8,900	Polarity	Unipolar	Electrical Malfunction	115
Advisories	None	Steroid	Yes	Other	2



Epi/Myocardial Pacing Leads continued

4968 CapSure Epi

Product Characteristics

US Market Release	Sep-99	Serial Number Prefix	LEN	US Returned Product Analysis
Registered US Implants	16,000	Type and/or Fixation	Epicardial Suture-On V or A	Implant Damage 2
Estimated Active US Implants	10,000	Polarity	Bipolar	Electrical Malfunction 11
Advisories	None	Steroid	Yes	Other 0
Advisories	None	Steroid	Yes	Other 0

System Longevity Study Results

Qualifying Complications 34 Total

Number of Leads Enrolled in Study	543	Conductor Fracture	7	Impedance Out of Range	4
Cumulative Months of Follow-Up	22,604	Failure to Capture	14	Insulation (not further defined)	2
Number of Leads Active in Study	326	Failure to Sense	3	Oversensing	4



5071

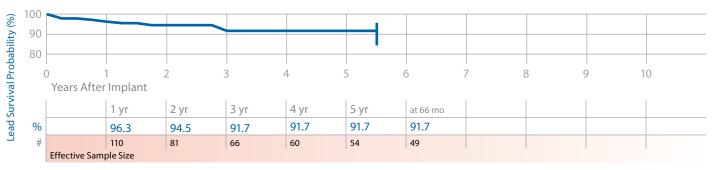
Product Characteristics

US Market Release	Dec-92	Serial Number Prefix LAQ		US Returned Product Analysis
Registered US Implants	33,900	Type and/or Fixation	Myocardial Screw-in Vent.	Implant Damage 29
Estimated Active US Implants	13,400	Polarity	Unipolar	Electrical Malfunction 7
Advisories	None	Steroid	No	Other 2

System Longevity Study Results

Qualifying Complications 11 Total

Number of Leads Enrolled in Study	229	Failure to Capture	9	
Cumulative Months of Follow-Up	7,092	Oversensing	2	
Number of Leads Active in Study	30			



Epi/Myocardial Pacing Leads continued

Effective Sample Size

	US Mar	ket Rel	ease			Jun-7	3	Serial Number Prefix			١	WV or WC					US Returned Product A					alysis
	Registe	red US	Implar	nts		180,10	0	Type and/or Fixation			ı	Myocar	dial Scı	ew-in '	Ven	t.				lant Da		115
	Estimat	ted Act	ive US	Implan	ts	5,00	0	Polarity	,		l	Unipolar						Electrical Malfunction				42
	Adviso	ries				Non	e	Steroid			1	No									Other	1
em	Longe	vity St	udy R	esults						Qua	lifying	Comp	olicatio	ons 6	59	Total						
	Numbe	er of Lea	ads Enr	olled ir	Study	,	985				Со	nducto	r Fract	ure	6			lmp	edance	e Out o	f Range	2
	Cumula	ative M	onths o	of Follo	w-Up	47	7,481			Ex	ktra Ca	rdiac St	imulat	ion	1				Ir	sulatio	n (MIO)	1
	Numbe	er of Lea	ads Act	ive in S	tudy		4				F	ailure t	o Capt	ure 3	30					Over	sensing	18
												Failur	e to Se	nse	11							
100)																					
90)								<u> </u>													
80)												Ч									
70)												-									
	0	1	2	3	4	5 (6	7	8	9 1	10 1	1 1	2 1	3 1	4	15	16	17	18	19	20 2	21
	Year	s Afte	· Impla	ant																		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 150 mo								
		1	İ	1	00.6	_	-	1		-	i –	i										
%	5	99.0	97.6	95.9	93.6	92.8	91.1	89.5	87.2	85.0	84.2	84.2	05.2	80.4								

Lead Survival Summary (95% Confidence Interval)

	I			I	ı	ı										
		16 yr														
								14 yr					80.4 +5.2/-6.8 at 150 mo			
												12 yr				
							10 yr					84.2 +3.9/-4.8				
		8 yr			91.7 +3.0/-4.7		87.2 +3.1/-4.1									
	Years After Implant	7 yr			91.7 +3.0/-4.7		89.5 +2.7/-3.4									
		6 yr			91.7 +3.0/-4.7	91.7 +4.0/-7.3 at 66 mo	91.1									
Device Survival Probability (%)		ter Implant	ter Implant	fter Implant	fter Implant	ofter Implant			5 yr	93.4 +3.7/-8.1 at 57 mo		93.2 +2.5/-4.0	91.7 +4.0/-7.3	92.8 +2.0/-2.6		
											4 yr	93.4 +3.7/-8.1	91.9 +4.3/-8.9 at 45 mo	94.5 +2.1/-3.4	91.7 +4.0/-7.3	93.6
							3 yr	96.5 +2.2/-5.8	96.5 +2.2/-6.1	95.9 +1.7/-2.7	91.7 +4.0/-7.3	95.9				
							Vfter Impl	rfter Impl	rfter Impl	fter Impl	fter Impl	Vfter Impl	2 yr	96.5 +2.2/-5.8	97.7	97.4 +1.2/-2.3
		1 yr	97.7 +1.6/-4.8	98.8 +0.9/-3.6	99.6 +0.3/-1.4	96.3 +2.1/-4.4	99.0									
Months o in Study			6,512	5,451	,604	7,092	,481									
	oitasil	Qualif GmoD	10	80	34 22,604	11 7	69 47,481									
γbut2 ni ε	evitoA	греәд	4	28	326	30	4									
pə	Enroll	rpeads	179	188	543	229	985									
Model Family			Oct-81	Sep-96	Sep-99	Dec-92	Jun-73									
			Spectraflex	CapSure Epi	CapSure Epi	(No brand name)	Tenax									
			4951, 4951M	4965	4968	5071	6917, 6917A									

Epi/Myocardial Pacing Leads continued

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	lmplant Damage	Electrical Malfunction	Other
4951, 4951M	Spectraflex	Oct-81	23,100	2,500	15	97	28
4965	CapSure Epi	Sep-96	17,700	8,900	8	115	2
4968	CapSure Epi	Sep-99	16,000	10,000	2	11	0
5071	(No brand name)	Dec-92	33,900	13,400	29	7	2
6917, 6917A	Tenax	Jun-73	180,100	5,000	115	42	1

Source: Returned Product Analysis Data as of January 31, 2009

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture-On V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5069	(No brand name)	Myocardial Screw-In	Silicone	MP35N Multifilars	3-Turn Helix	IS-1 UNI
5071	(No brand name)	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI
6917	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	3-Turn Helix	5 mm
6917A	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	2-Turn Helix	5 mm

VDD Single Pass Pacing Leads

5032 CapSure VDD

Product Characteristics

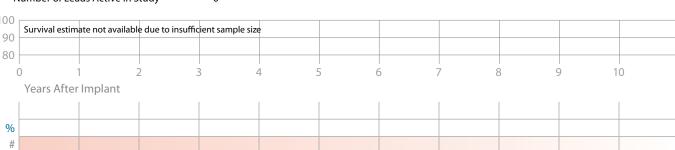
US Market Release	Mar-96	Serial Number Prefix LCL, LCN, LCM		US Returned Product Analysi	US Returned Product Analysis		
Registered US Implants	5,400	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Implant Damage 2	24		
Estimated Active US Implants	1,600	Polarity	Quadripolar	Electrical Malfunction 1	12		
Advisories	None	Steroid	Yes	Other	0		

System Longevity Study Results

Lead Survival Probability (%)

Qualifying Complications 1 Total Failure to Sense 1

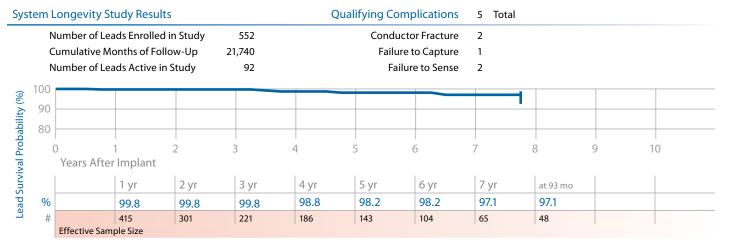
Number of Leads Enrolled in Study 38
Cumulative Months of Follow-Up 2,011
Number of Leads Active in Study 0



5038 CapSure VDD-2

Effective Sample Size

US Market Release Sep-98		Serial Number Prefix LEE, LEG, or LEF		US Returned Product Analysis		
Registered US Implants	8,200	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Implant Damage	6	
Estimated Active US Implants	3,800	Polarity	Quadripolar	Electrical Malfunction	5	
Advisories	None	Steroid	Yes	Other	1	



VDD Single Pass Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)

ā		US Market Release	Enrolled	Active in Study	Qualifying Complications	Cumulative Months of Follow-Up in Study		Survival I		ty (%)						
Model Numbe	Family	US Mai	Leads En	Leads	Qualify	Cumul	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
5032	CapSure VDD	Mar-96	38	0	1	2,011	Survival e	stimate no	t available	due to insu	fficient san	nple size				
5038	CapSure VDD-2	Sep-98	552	92	5	21,740	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.8 +0.2/-1.4	98.8 +0.8/-2.6	98.2 +1.2/-3.1	98.2 +1.2/-3.1	97.1 +1.8/-4.5	97.1 +1.8/-4.5 at 93 mo		

Source: System Longevity Study Data as of January 31, 2009

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5032	CapSure VDD	Mar-96	5,400	1,600	24	12	0
5038	CapSure VDD-2	Sep-98	8,200	3,800	6	5	1

Source: Returned Product Analysis Data as of January 31, 2009

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous Ventricular Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than 6-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a 6-month interval, a conservative approach has been adopted whereby only the maximum charge in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

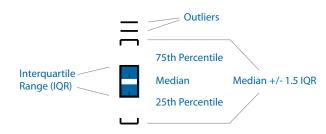
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

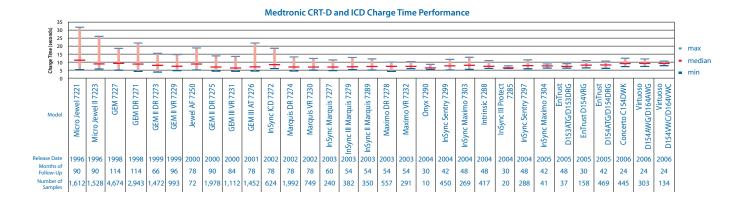
Data Presentation

Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data - the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the 25th percentile. The brackets around the box represent the variance in charge times (analogous to a confidence interval), and are calculated as a function of the median and IQR. Individual values falling outside the brackets are labeled as outliers.

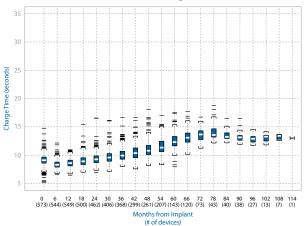
Results

As shown in the graph below, the performance of Medtronic ICD and CRT-D devices has improved. This graph shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel. A progression toward shorter mean charge times and less variation has occurred between 1996 and 2002. Models released after 2002 have limited experience but appear to be continuing this performance.

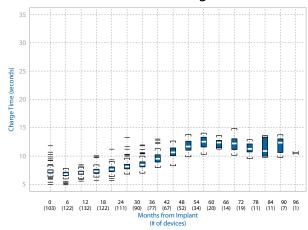




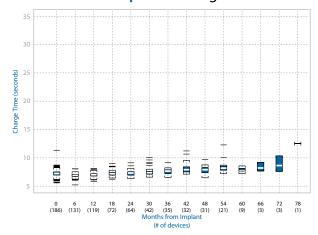
7227 GEM Charge Time



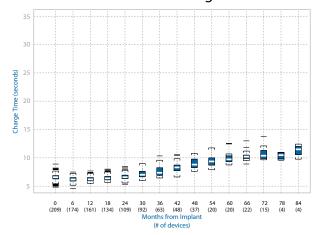
7229 GEM II VR Charge Time



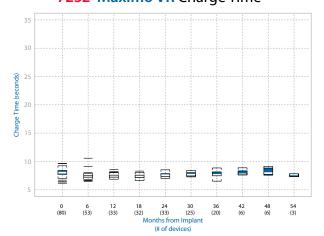
7230 Marquis VR Charge Time



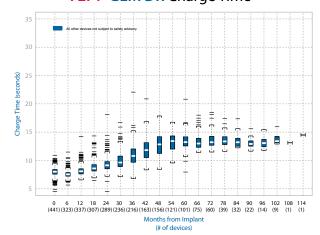
7231 GEM III VR Charge Time

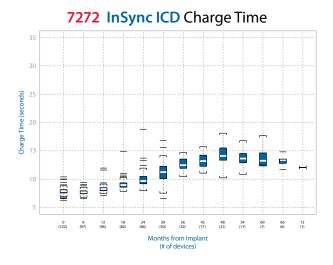


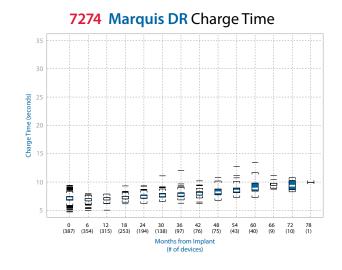
7232 Maximo VR Charge Time

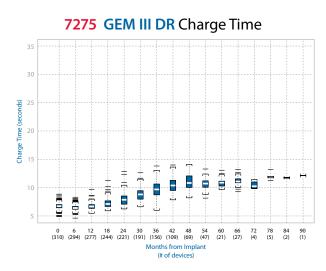


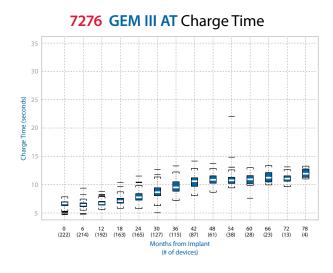
7271 GEM DR Charge Time

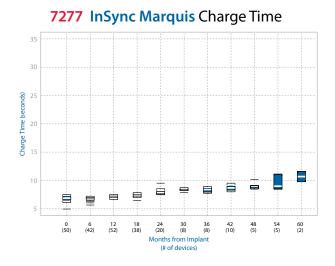


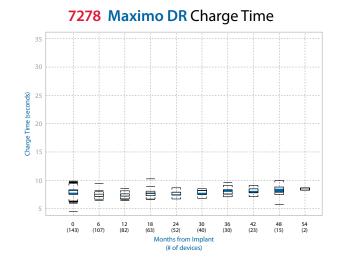




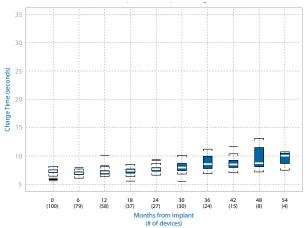




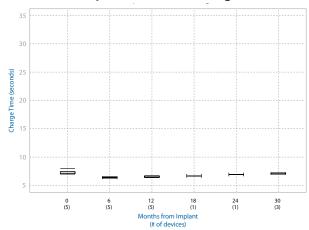




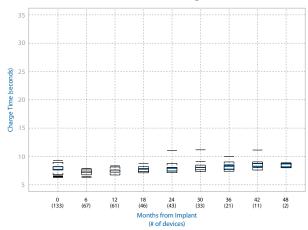
7279 InSync III Marquis Charge Time



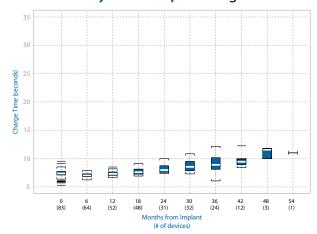
7285 InSync III Protect Charge Time



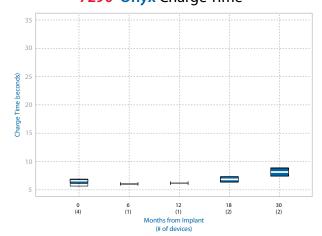
7288 Intrinsic Charge Time



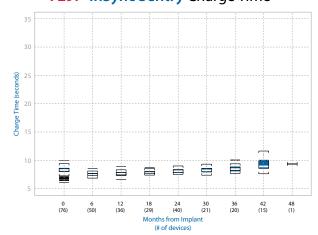
7289 InSync II Marquis Charge Time

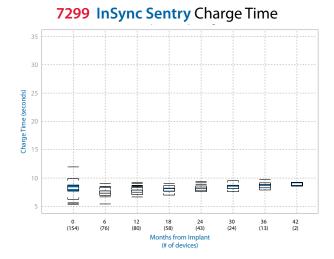


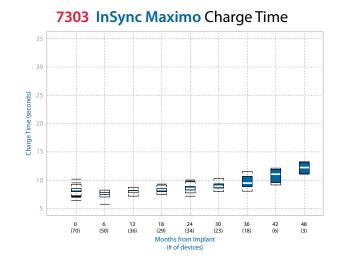
7290 Onyx Charge Time

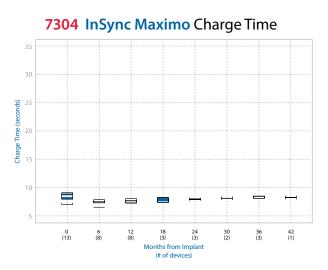


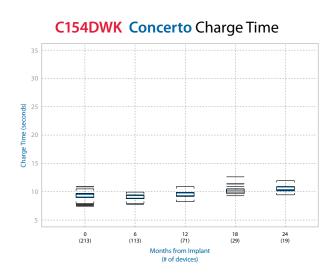
7297 InSync Sentry Charge Time

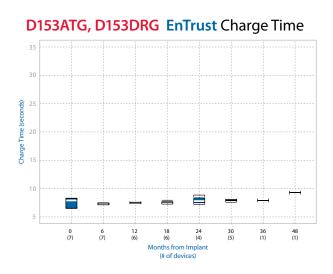


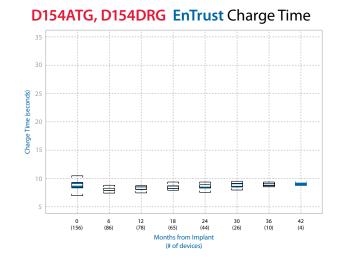


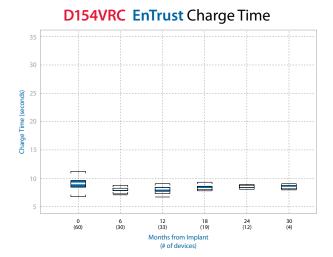


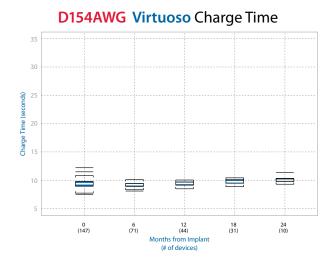


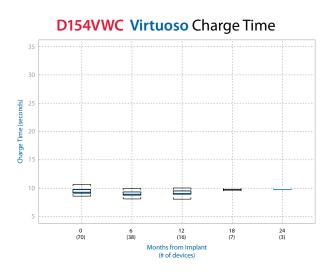












Advisories

6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture

Product

All Model 6930, 6931, 6948, and 6949 implantable defibrillation leads

Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for approximately 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

Patient Management Recommendations

Medtronic recommends you consider the following as part of routine follow-up for each patient:

- To reduce the risk of inappropriate detection and therapy due to oversensing, program VF detection for initial Number of Intervals to Detect (NID) to nominal settings 8/24) or longer at physician discretion and Redetect NID to nominal settings (12/16)
- Turn ON Patient Alert for RV Pacing, RV Defibrillation, and SVC
 Defibrillation impedance. For Concerto, Virtuoso, Consulta, Secura
 and Maximo II devices enrolled on the Medtronic CareLink Network,
 turn ON the Medtronic CareAlert Notifications for these same
 parameters.
- To optimize effectiveness of the lead impedance alert:
 - Review V. Pacing Lead Performance Trend to determine typical chronic impedance value for the patient (typical values for Fidelis leads should be 350-1,000 ohms)
 - Program lead impedance alert threshold for RV Pacing to 1,000 ohms, if the typical chronic impedance for the patient is ≤ 700 ohms, or
 - $-\,$ Program lead impedance alert threshold for RV Pacing to 1,500 ohms, if the typical chronic impedance for the patient is > 700 ohms
 - Program lead impedance alert threshold for RV Defibrillation and SVC Defibrillation to 100 ohms

Status Update

Sprint Fidelis lead performance continues to be in line with the information provided in the October 2007, May 2008 and March 2009 advisory communications. In consultation with the Independent Physician Quality Panel, our patient management recommendations are as follows:

- When a lead fracture is suspected or confirmed, we strongly recommend prompt patient attention. Patients should contact their physician without delay if they experience unexpected shocks.
- The Lead Integrity Alert (LIA¹) is expected to provide 3 days advance notice prior to inappropriate therapy to 76% of the patients with lead fractures. As a result, we strongly recommend that all Sprint Fidelis patients who have the ability to upgrade to Lead Integrity Alert do so promptly.

- The risk of prophylactic intervention appears to be greater than the risk of serious injury resulting from lead fracture even for pacemaker dependent patients, except in select individual patient circumstances as determined by the physician
- Special circumstances may apply to device change-out or upgrade procedures when a lead fracture has not occurred. At least four options are available, each of which carries risks and benefits that should be taken into consideration:
 - Leave a properly performing lead intact; this is likely to be the best choice for the majority of patients
 - Place a new ICD lead without extraction of the existing lead
 - Place a pace sense lead without the extraction of the existing lead.
 This option reflects the observation that approximately 90% of Fidelis failures are related to fractures in the pace sense circuit. It is unknown what the failure rate of the high voltage conductor would be should a pace sense conductor failure occur in the existing Sprint Fidelis lead.
 - Unusual patient circumstances may warrant extracting and implanting a new ICD lead. Factors to consider when making this decision include patient life expectancy, age, and comorbidities, number of implanted leads and duration of implant, and patient preference. Medtronic's Independent Physician Quality Panel recommends that if a lead requires removal, the procedure be performed by a physician with extensive lead extraction experience. (A new HRS consensus document on lead extraction is expected to be available in May 2009.)

Out of the initial implant population of 204,000 in the United States, approximately 150,100 remain implanted. According to System Longevity Study results, lead survival is estimated to be 93.6% (+2.1/-3.1) at 48 months. As the implanted population ages and the sample size increases for each time interval, the accuracy of the estimated survival probability will increase as shown by tighter confidence intervals.

As part of our commitment to keep you informed about Sprint Fidelis lead performance, Medtronic publishes the quarterly System Longevity Study's all-cause lead survival curve and the CareLink dataset lead survival curve for the Model 6949 lead at www.medtronic.com/fidelis. Semi-annual updates will also continue to be provided in the Product Performance Report. Additional information about the Sprint Fidelis lead is available at www.medtronic.com/fidelis.

Lead Integrity Alert[†]

Medtronic has released Lead Integrity Alert (LIA) software. LIA was designed to provide patients more advance notice via an audible sound of a potential lead fracture that could result in an unnecessary shock.

Data show that with LIA, approximately 76% of the patients with Sprint Fidelis leads are expected to receive 3 or more days advance warning of a potential lead fracture that could result in an unnecessary shock.

Upon hearing the alert, patients should contact their physician without delay.

LIA can be downloaded into nearly all Medtronic implantable cardioverter defibrillators (ICDs) and cardiac resynchronization therapy defibrillators (CRT-Ds) implanted worldwide.



Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Specific model and serial numbers of affected devices are available online at http://SigmaSNList.medtronic.com.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

Our modeling predicts a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. No provocative testing can predict which devices may fail.

Patient Management Recommendations

To assist physicians in their patient care and after discussion with physician consultants, Medtronic offers the following recommendations:

- Medtronic does not recommend replacement of these devices prior to normal elective replacement (ERI), based on the low probability of occurrence of a serious event in this population
- Continue routine follow-up in accordance with standard practice
- Advise patients to seek attention immediately if they experience return of symptoms (e.g., syncope or light-headedness)
- Determine whether device replacement is warranted on a case-by-case basis based upon consultation with patients, review of the individual

patient's medical history, and consideration of the relative risks of an invasive procedure

Status Update

The Sigma Family device performance related to the interconnect wires separation mechanism continues to be within Medtronic's engineering projections. As of January 31, 2009, 213 devices out of approximately 40,000 devices worldwide have been confirmed as having experienced interconnect wire separation. Fifty-three (53) of these devices were returned from the United States.

One hundred fifty-eight (158) of the 213 devices (0.40%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 55 devices (0.14%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Implant duration for the 213 devices confirmed as having experienced interconnect wire separation has ranged between 17 and 83 months, with an average of 61.3 months.

Out of the initial advisory population of 40,000 worldwide, approximately 16,200 remain implanted. Approximately 3,900 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Advisories continued

7274 Marquis DR 7230 Marquis VR 7278 Maximo DR 7232 Maximo VR

7277 InSync Marquis 7289 InSync II Marquis

7279 InSync III Marquis 7285 InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Specific model and serial numbers of affected devices are available online at http://MarquisSNList.medtronic.com.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

- Conduct quarterly (i.e., every 3 months) follow-up procedures
- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.

 Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, follow-up care should be sought promptly.

Status Update

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of January 31, 2009, 129 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. Sixty-six (66) of these devices were returned from the United States.

Of the 129 returns, 40 have been identified by patients reporting warmth in the ICD pocket, 44 by a regularly scheduled follow-up or during a non-device-related hospital visit, 17 by hand-held magnet test or CareLink attempt, nine by return of bradycardia symptoms, five by the Patient Alert sounding, and 14 unknown.

Implant duration for the 129 devices ranged between 11 to 70 months, with an average of 41 months.

Consistent with Medtronic projections, the observed rate of shorting is higher in the second half of device life than in the first half of device life. Of the devices that have exhibited shorting in the last half of device life, 48% occurred in the last quarter of device life and 31% in the last 10% of device life.

Out of the initial advisory population of 87,000 worldwide, approximately 23,900 remain implanted. Approximately 20,700 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Warranty

All Marquis devices are subject to a Limited Warranty. Devices returned to Medtronic and determined to be malfunctioning will be replaced or credited in accordance with the warranty terms. In addition, for devices subject to the Marquis advisory, should a physician decide to replace a device for a patient who is pacemaker dependent or who receives frequent VT/VF therapy, Medtronic will, upon receipt of a written statement from the physician setting forth the basis for early replacement of the device, provide a replacement device at no cost.



Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

Potential Fractured Power Supply Wires

Product

A specific subset of Kappa 700/600 dual chamber (D, DR, and VDD) implantable pulse generators has been identified by serial numbers. Hospitals and Physicians were notified. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 505-4636.

Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 dual chamber (D, DR, and VDD) series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free of charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. As of January 31, 2009, 308 out of approximately 180,000 distributed (0.17% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. One hundred sixty-three (163) of these devices were returned from the United States. Out of the initial implant population of 121,000 in the United States, approximately 24,700 remain implanted.

Advisories continued

7227Cx GEM 7229Cx GEM II VR

Original Date of Advisory: October 15, 1999

Potential Circuit Overload

Product

Model 7227Cx and Model 7229Cx implantable cardioverter defibrillators supplied before October 15, 1999, with serial numbers ending in an "H." For example, PIPxxxxxxH or PJJxxxxxxH, where x is a variable numeric, may be affected. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 723-4636.

IMPORTANT REMINDER:

Medtronic strongly advises physicians who have patients under their care affected by this issue to reprogram the Patient Alert feature "ON" without delay.

Advisory

Manufacturing error in a small percentage of devices may cause circuit overload when AX ≥ B High Voltage energy is delivered via an integrated bipolar lead. GEM Model 7227Cx and GEM II VR Model 7229Cx devices with dedicated bipolar sensing leads are not affected by this issue. Devices affected may not be able to subsequently charge to full energy and experience "charge circuit timeout."

Patient Management Recommendations

- Assessment of all patients with the potentially affected devices implanted AND an integrated bipolar ICD lead such as the Models 6942 and 6945 should take place without delay
- Reprogram polarity pathway to B ≥ AX for all cardioversion and defibrillation therapies
- Confirm correct device function:
 - Perform a full energy charging sequence
 - If "charge circuit timeout" is observed, contact your Medtronic representative
 - If device charges normally, it has not been damaged and will function appropriately with polarity programmed B ≥ AX

Recent studies have demonstrated that DFTs are similar or lower in a B ≥ AX polarity pathway when compared to $AX \ge B$.

Devices implanted with functional dedicated bipolar leads such as the Models 6932, 6934S, 6936, 6943, and 6966 are not affected.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 10,000 in the United States, approximately 1,200 remain implanted. The devices affected by this advisory are nearing the end of their expected battery longevity.



4504, 4504M CapSure Atrial Lead 4582 Target Tip Atrial Lead

Original Date of Advisory: October 4, 1996

Lead Survival Below Expectations

Product

All Model 4504, 4504M, and 4582 implantable pacing leads

Advisory

Lead survival probability is below expectations and is primarily associated with insulation degradation due to Metal Ion Oxidation (MIO).

Patient Management Recommendations

- Follow patients in accordance with Medicare Guidelines
- Avoid the use of the AAI or AOO mode
- During patient evaluation, give careful attention to lead performance such as:
 - Review patient ECG for indications of transient sensing and/or capture abnormalities
 - Monitor in clinic for impedance less than 250 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry), which would suggest lead failure
- Consider the use of unipolar if the pulse generator has this capability
- At the time of pacemaker system revision (e.g., normal pulse generator or ventricular lead revision), carefully evaluate lead integrity and patient status before choosing to reuse

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 16,600 in the United States, approximately 1,700 remain implanted. According to System Longevity Study results, lead survival is estimated to be 66.1% at 8 years, 9 months.



4004, 4004M CapSure Ventricular Lead **4082** Target Tip Ventricular Lead

Original Date of Advisory: October 8, 1993

Lead Survival Below Expectations

Product

All Model 4004/4004M and 4082 implantable pacing leads

Advisory

Lead survival probability is below expectations due primarily to polyurethane insulation failure (MIO) and conductor fracture (associated with "subclavian crush").

Patient Management Recommendations

- Increase, as appropriate, the frequency of patient evaluation through in-clinic visits supplemented with transtelephonic and/or ambulatory monitoring; for example, consistent with Guideline I under Medicare Pacemaker Monitoring Guidelines (50-1 Cardiac Pacemaker Evaluation Services)
- During patient evaluations, give careful attention to lead performance such as:
 - Reviewing patient ECGs carefully for indications of transient sensing and/or capture abnormalities
 - Monitoring in-clinic for impedances less than 300 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry), which would suggest lead failure
 - Eliciting and thoroughly investigating any patient complaints suggestive of lead failure

- Consider whether prophylactic replacement would be appropriate, especially in patients at high risk, such as pacemaker dependent patients
- Carefully evaluate lead integrity when performing routine pulse generator replacements. Replace lead if:
 - Insulation breaches are observed
 - Lead impedance is less than 300 ohms or has decreased by more than 30% from implant values
 - Impedance or voltage threshold measurements vary significantly when multiple readings are taken
 - If the risk of continued use outweighs the risk associated with implanting a new lead
- As always, individual circumstances and medical judgment dictate patient care and frequency of follow-up
- Consider lead replacement during normal pulse generator change-out. Carefully evaluate lead integrity and patient status before choosing to reuse.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 77,000 in the United States, approximately 6,000 remain implanted. According to System Longevity Study results, lead survival is 50.6% at 10 years, 9 months.



4012 Target Tip Ventricular Lead

Original Date of Advisory: September 26, 1991

Lead Survival Below Expectations

Product

All Model 4012 implantable pacing leads

Advisory

Lead survival probability beyond 5 years is below expectations due primarily to polyurethane insulation failure (due to ESC and/or MIO) and conductor fracture (associated with "subclavian crush").

Patient Management Recommendations

Consider increasing frequency of monitoring (e.g., from quarterly to bimonthly or monthly). Consider the following activities as part of normal follow-up procedures:

- Monitor for significant changes in impedance, which could be an indication of impending failure (pulse generator must have impedance telemetry capabilities)
- Review patient ECGs carefully for indications of transient sensing and/or capture abnormalities. This can be done using transtelephonic or in-clinic monitoring and/or using ambulatory monitoring.
- Elicit any patient complaints suggestive of lead failure and investigate thoroughly lead integrity/ performance characteristics following reports of patient complaints or symptoms using the above techniques

- Consider whether prophylactic replacement would be appropriate in patients at high risk, such as pacemaker dependent patients
- Evaluate carefully the integrity of the lead during routine pulse generator replacement before choosing to reuse. Specifically, Medtronic recommends placement of a new lead if:
 - Insulation breaches are observed
 - Lead impedance is less than 300 ohms or has decreased by more than 30% from implant values
 - Electrical properties such as impedance and threshold vary significantly when multiple readings are taken

As always, medical judgment must be used to establish the appropriate schedule and course of care for every individual, particularly pacemaker dependent or other patients at higher risk.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 96,800 in the United States, approximately 6,500 remain implanted. The System Longevity Study results show 62.2% lead survival at 15 years, 9 months.



Minix, Minix ST, Micro Minix IPGs

Original Date of Advisory: May 6, 1991

Potential Delayed Restoration of Permanent Settings

Product

All Models of the Minix, Minix ST, and Micro Minix families of implantable pulse generators

Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 4,100 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

Performance Notes

Clinical Management of VCM near Elective Replacement

Background

Medtronic Technical Services has received reports of devices going to ERI or end of life (EOL) sooner than expected after a normal follow-up in which the device longevity was projected to be approximately 18 months. It has been noted that these cases typically involve Kappa 700 devices where Ventricular Capture Management set the ventricular lead to high output (5 V, 1 ms), which occurs by device design when a high threshold is measured. It is important for physicians and allied professionals to understand VCM behavior as it relates to longevity so that they can, in turn, understand how this affects management of the device and follow-up visits as VCM equipped IPGs near the end of their expected longevity.

Device Longevity and VCM Behavior

Ventricular Capture Management is a feature that uses evoked response sensing to determine the stimulation threshold needed to capture the ventricular chamber. Proper detection of the evoked response is crucial to the VCM algorithm determining an accurate capture threshold. There are rare conditions, however, during which the VCM algorithm will not be able to measure the evoked response accurately. When this occurs, for safety reasons the VCM algorithm will reprogram the output to 5 V, 1 ms until the subsequent VCM measurement.

If the device has considerable remaining longevity, these occasional excursions to high output do not substantially affect remaining longevity. However, if the device has less than approximately 18 months remaining longevity, there is the possibility that the high output condition caused by the 5 V, 1 ms output will drain the battery and trigger ERI.

When ERI is declared by the device, VCM is disabled and the outputs are left at 5 V, 1 ms until the device is reprogrammed at an in-office follow-up. This increased current drain of a high output condition will speed depletion of the device, possibly resulting in the device getting to the EOL (battery voltage ≤ 2.15 V).

Please note that the following parameter changes occur when the device goes to ERI:

Table: IPG Therapy Parameter Changes at ERI

Parameter	Value
Pacing Mode	VVI
Lower Rate	65 bpm
Single Chamber Hysteresis	OFF
Sleep Function	OFF
Ventricular Capture Management	OFF
Atrial Sensing Assurance	OFF
Ventricular Sensing Assurance	OFF

Kappa 700 is Medtronic's first-generation VCM algorithm, which has a relatively higher incidence of evoked response undersensing compared to subsequent algorithms, resulting in more frequent high output conditions. Therefore, Kappa 700 products are the primary focus of this note. It should be noted that IPGs equipped with the second-generation VCM algorithm (Kappa 900, EnPulse, Adapta/Versa/Sensia, and Relia) have not been observed with evoked response undersensing in the general population, though the items listed in "Follow-Up Considerations" may also be used on these devices.

Follow-Up Considerations

- Estimated longevity in the event the device goes to high output can be determined by the following steps. This allows the clinician to determine follow-up frequency if he or she is concerned the device may go to ERI due to high output.
 - Program the ventricular channel to 5 V, 1 ms
 - Navigate to Data/Battery and Lead Measurements
 - When the message stating "Warning Old Data" is displayed, select "Yes" to measure battery voltage and lead impedance at the new ventricular outputs
 - An updated remaining longevity estimate will be calculated on the elevated outputs. Note the "Minimum Remaining Longevity." Clinical decisions can be based on this value.
 - Program the Amplitude and Pulse Widths back to their original values before leaving the session
- If the capture trends and lead impedance trends are stable, VCM can be programmed to "Monitor Only" for the remaining device life. This should be considered only if remaining longevity is 18 months or less.
- Follow-up frequency can be increased for those patients who do not have stable capture or lead impedance trends. This can be done via a CareLink Home Monitor, or in-office.

 $^{^1}$ Medtronic, Inc. (2001). Medtronic Kappa 700/600 Series Pacemaker Reference Guide (Chapter 4, p. 27). Can be retrieved from http://manuals.medtronic.com.

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of This Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- The amount of electrical energy expended in providing therapy to the patient
- The amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- The energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

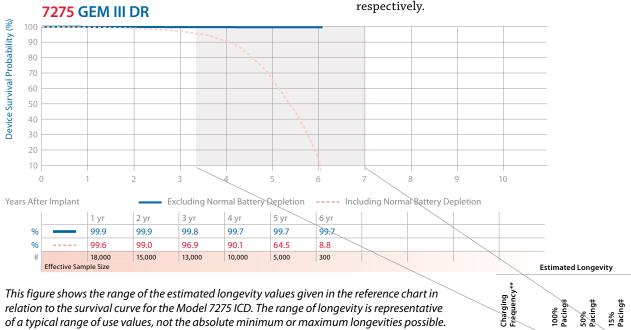
Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates, originally published in the device Technical Manual, are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.

Monthly

Semiannual



approximately the mid-point of the range of longevity values.

of a typical range of use values, not the absolute minimum or maximum longevities possible. In this example, the survival curve including normal battery depletion is approaching 50% at

5.0 5.5

Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation

Purpose of This Information

This article is intended to provide information for consideration when programming pacemaker operation in ICDs and pacemakers.

Background

Right ventricular pacing has been associated with increased risk of appropriate therapy for ventricular tachycardia (VT) and ventricular fibrillation (VF) in ICD patients.1 Abrupt changes in ventricular cycle lengths (short-long-short, S-L-S) may precede initiation of VT/VF in some instances. S-L-S sequences may be permitted in all forms of cardiac pacing. The pause lengths depend upon pacing mode and lower rate programming.²⁻⁴ Because pauses may be associated with VT/VF initiation, pause suppression algorithms have been developed in ICDs. Although pause suppression may have utility in specific patients with repolarization abnormalities and pause dependent VT, it has not been shown to reduce arrhythmia incidence in the general ICD population.5 Conversely, S-L-S sequences may occur with ventricular pacing in a variety of ways, including atrial tracking of premature atrial contractions (PACs) or by terminating pauses with ventricular paced beats. 6 In some patients, the ectopic depolarization pattern of a ventricular paced beat may be pro-arrhythmic, independent of pause timing. These observations have further enforced the desire to reduce unnecessary ventricular pacing.

Clinical Trial Observations

Medtronic-sponsored clinical trials were retrospectively analyzed to further understand pause-mediated (i.e., S-L-S) scenarios prior to VT/VF. S-L-S onset scenarios were observed in a minority of patients in all pacing modes. Pacemaker interactions prior to VT/VF are dependent on patient conditions, as well as the technical aspects of pacing operation (i.e., pacing mode, lower rate, and AV interval). Because a very low frequency of ventricular pacing is observed during Managed Ventricular Pacing (MVP)⁷⁻⁹ or VVI 40 pacing modes, ¹⁰ the long interval tended to terminate with a ventricular sense. In DDD mode, the long interval tended to be terminated by a ventricular pace. Long intervals of > 1,000 ms prior to VT/VF were rare in MVP mode. In these analyses, only an association between cardiac pacing and VT/VF initiation can be observed, causality cannot be established. The ongoing MVP (Managed Ventricular Pacing vs. VVI 40 Pacing) Trial, a 2-year, 1,000-patient prospective, randomized trial in ICD patients may offer more insight into the frequency of VT/ VF across pacing modes.11

Pacemaker Patients

In pacemaker patients, ventricular pacing has been associated with higher incidence of AT/AF and heart failure hospitalization. 12,13 MVP provides atrial rate support while dramatically reducing ventricular pacing in patients with sinus node dysfunction and transient AV block.9 However, as stated in Medtronic reference manuals, depending upon the patient's intrinsic rhythm and conduction, MVP may allow ventricular cycle variation and occasional pauses of up to twice the lower rate.

DDD pacing with long AV intervals may reduce ventricular pacing and may decrease the potential length of pauses compared to MVP. However, DDD with long AV interval programming does not appear to be as effective as AAI-based pacing modes at reducing ventricular pacing, $^{13,14}\,\mathrm{may}$ lead to endless loop tachycardia, $^{14,15}\,$ and does not completely eliminate pauses. Also, in DDD mode, a higher programmed lower rate or activation of rate response can lead to an increase in AV conduction times and a higher percentage of ventricular pacing. The potential benefits of reducing ventricular pacing must be weighed against the potential for longer ventricular pauses. Therefore, careful consideration should be given to pacemaker mode and lower rate programming, particularly in the setting of frequent AV block and repolarization abnormalities due to congenital Long QT, electrolyte imbalances, and some medications that prolong QT.

Conclusion

Pacemaker operation may interact with VT/VF initiation in a variety of ways. The patient's heart failure status, arrhythmia substrate, medications, and the relative importance of maintaining ventricular synchrony versus ensuring ventricular rate support must be weighed when choosing optimal hardware (ICD vs. pacemaker) and pacemaker programming (pacing mode, lower rate, etc.).

References

- ¹ Steinberg JS, Fischer A, Wang P, et al. The clinical implications of cumulative right $ventricular\ pacing\ in\ the\ multicenter\ automatic\ defibrillator\ trial\ II.\ \textit{JCardiovas} and all in the multicenter\ automatic\ defibrillator\ trial\ II.\ \textit{JCardiovas} and all in the multicenter\ automatic\ defibrillator\ trial\ II.\ \textit{JCardiovas} and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all interpretations and all interpretations are all inter$ Electrophysiol. April 2005;16(4):359-365.
- ² Pinski SL, Eguía LE, Trohman RG. What is the minimal pacing rate that prevents torsades de pointes? Insights from patients with permanent pacemakers. PACE. November 2002; 25(11):1612-1615.
- ³ Goldman DS, Levine PA. Pacemaker-mediated polymorphic ventricular tachycardia. PACE. October 1998; 21(10):1993-1995.
- ⁴ Gray CJ, Basta M, Sapp JL, Parkash R, Gardner MJ. Inappropriate application of managed ventricular pacing in a patient with Brugada syndrome leading to polymorphic ventricular tachycardia, ventricular fibrillation and implantable cardioverter debrillator shocks. *Heart Rhythm*. 2006, Abstract P1-89.
- ⁵ Friedman PA, Jalal S, Kaufman S, et al. Effects of a rate smoothing algorithm for prevention of ventricular arrhythmias: results of the Ventricular Arrhythmia Suppression Trial (VAST). *Heart Rhythm*. May 2006;3(5):573-580.
- ⁶ Himmrich E, Przibille O, Zellerhoff C, et al. Proarrhythmic effect of pacemaker stimulation in patients with implanted cardioverter-defibrillators. Circulation. July 15, 2003;108(2):192-197.
- 7 Sweeney MO, Ellenbogen KA, Casavant D, et al. Multicenter, prospective, randomized trial of a new atrial-based Managed Ventricular Pacing Mode (MVP) in dual chamber ICDs. J Cardiovasc Electrophysiol. 2005:16:1-7.
- 8 Sweeney MO, Shea JB, Fox V, et al. Randomized pilot study of a new atrial-based minimal ventricular pacing mode in dual-chamber implantable cardioverter-defibrillators. Heart Rhythm, July 2004;1(2):160-167.
- Gillis AM, Pürerfellner H, Israel CW, et al. Reducing unnecessary right ventricular pacing with the managed ventricular pacing mode in patients with sinus node disease and AV block. PACE. July 2006; 29(7):697-705.
- $^{\rm 10}$ Dual-chamber pacing or ventricular backup pacing in patients with an implantable defibrillator: the Dual Chamber and VVI Implantable Defibrillator (DAVID) Trial. *JAMA*. December 25, 2002;288(24):3115-3123.
- 11 Sweeney MO, Ellenbogen KA, Miller EH, Serfesee L, Sheldon T, Whellan D. The Managed ventricular pacing versus VVI 40 Pacing (MVP) Trial: clinical background, rationale, design, $and\ implementation.\ \textit{J Cardiovasc Electrophysiol}.\ December\ 2006; 17(12): 1295-1298.$
- 12 Sweeney MO, Ellenbogen KA, et al. Adverse effect of ventricular pacing on heart failure and atrial fibrillation among patients with normal baseline QRS duration in a clinical trial of pacemaker therapy for sinus node dysfunction. Circulation. June 17, 2003;107(23):2932-2937.
- 13 Nielsen JC, Kristensen L, Andersen HR, Mortensen PT, Pedersen OL, Pedersen AK. A randomized comparison of atrial and dual-chamber pacing in 177 consecutive patients with sick sinus syndrome: echocardiographic and clinical outcome. J Am Coll Cardiol. August 20, 2003;42(4):614-623.
- 14 Nielsen JC, Pedersen AK, Mortensen PT, Andersen HR. Programming a fixed long atrioventricular delay is not effective in preventing ventricular pacing in patients with sick sinus syndrome. Europace. April 1999; 1(2):113-120.
- $^{\rm 15}$ Dennis MJ, Sparks PB. Pacemaker mediated tachycardia as a complication of the autointrinsic conduction search function. PACE. June 2004;27(6 Pt 1):824-826.

AT500 Pacing System Follow-Up Protocol

Purpose of This Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below end of life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform transtelephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

Battery depletion curves are shown in Figure 1, with special focus on device longevity when programming EGM prestorage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately 9 days for each month pre-storage is ON
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM prestorage, or Holter Telemetry features

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/replacement occurs prior to end of life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary.



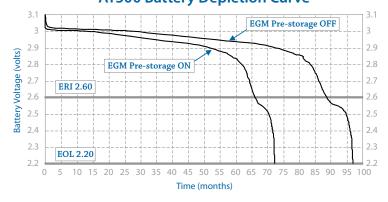


Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial - 2 V, 0.4 ms, 600 ohms, Ventricle - 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least one lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards, the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the technical article, "Clinical Management of High Voltage Lead System Oversensing."

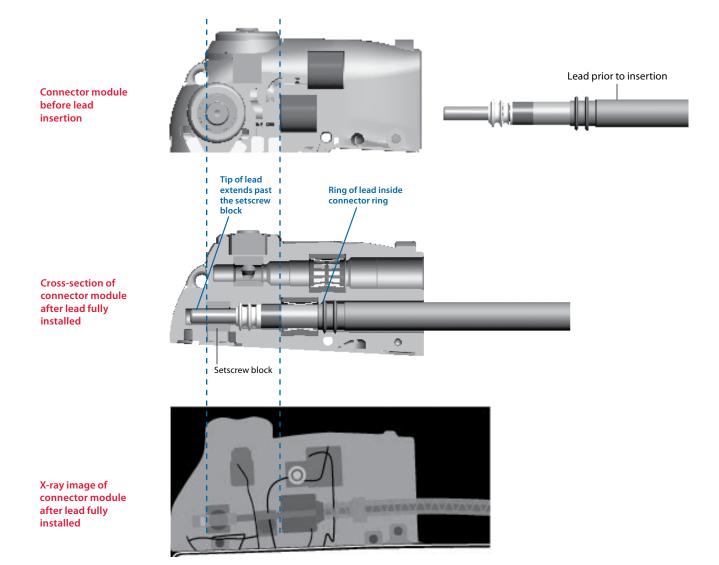
Performing the following steps can be used for each lead connection during the implant procedure:

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- 3 Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- 5 Tug gently on the lead to confirm a secure fit.

Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.1

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. J Cardiovasc Electrophysiol. September 2004;15(9):1095-1099.



GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactures and utilizes a unique lithium/ silver vanadium oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching middle of life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

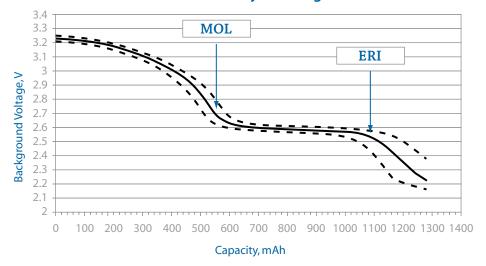
characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the battery in subsequently released models has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.

GEM II/III Battery Discharge Curve



General Follow-Up and Replacement of ICD Leads

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the nonsustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture
- Elicit and investigate any patient complaints/symptoms that may be suggestive of potential lead failure

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the System Longevity Study (SLS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed helow.

Factors that should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads. 1-3 Ultimately, the decision to replace an implanted lead involves medical judgment.
- ¹ Hauser RG, Cannom D, Hayes DL, et al. Long-term structural failure of coaxial polyurethane implantable cardioverter defibrillator leads. PACE. June 2002;25(6):879-882.
- ² Ellenbogen KA, Wood MA, Shepard RK, et al. Detection and management of an implantable cardioverter defibrillator lead failure: incidence and clinical implications. J Am Coll Cardiol. January 1, 2003;41(1):73-80.
- ³ Hauser RG, Kallinen LM, Almquist AK, Gornick CC, Katsiyiannis WT. Early failure of a small-diameter high-voltage implantable cardioverter-defibrillator lead. Heart Rhythm. July 2007;4(7):892-896.

Clinical Management of High-Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus, ICD systems attempt to dynamically adjust sensing of electrical events and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T and far-field P waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high-voltage therapies. This is due, in part, to the desire to err on the side of delivering lifesaving high voltage therapy rather than withholding it. Thus, an ICD system that is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/farfield sensing, electromagnetic interference, T wave sensing, connector issues, incomplete or complete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far-field sensing	Diaphragmatic muscle potentials in breathing, wide tip-to-ring (coil on integrated bipolar leads) spacing	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks	Check R waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change-out to true bipolar lead, or if true bipolar lead in use, one with closer tip-to-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave sensing	Drugs, ischemic tissue, exercise, Long QT syndrome, electrolyte imbalance	Sense markers seen on EGM related to T wave. False positive detection.	Check for R wave deterioration and characteristics. If R wave > 3.0 mV, reprogram sensitivity. If R wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header	This is an acute phenomenon seen within 6 months of implant (usually sooner)	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete conductor fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit	Characterized by chaotic oversensing related to motion of the fracture site	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead insulation breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.
Oversensing during interrogation with programming head (not wireless telemetry) with complete lead fracture	Interrogation with a programming head in combination with complete lead fracture that creates an open circuit can induce noise on the sensing circuitry inside the ICD can	Nonphysiologic sensed event on EGM. If detection is enabled during interrogation, oversensing may result in inappropriate therapy.	Quickly remove the programming head. CANCEL the interrupted interrogation and manually load the software for the specific device model. Reposition the programmer head over the device and immediately select SUSPEND. Device will resume detection when programming head is removed, or when RESUME is selected. Replace lead.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement	. Increase or Decrease .Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase, Especially in Bipolar System	Sudden and Significant Increase	Dislodgement	. Increase . Increase . Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/or Slew Rates for P and/or R Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P and/or R Waves	Dislodgement	Decrease Decrease .Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset, Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/ Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

Index

By Model Number

2187 83,86
2107 03,00
2188 83,86
3830 98, 130, 134, 136
4003 99, 130, 134, 136
4003M 99, 130, 134, 136
4004 100, 130, 134, 136, 157
4004 100, 130, 134, 130, 137
4004M 100, 130, 134, 136, 157
4011 100, 130, 134, 136
4010 101 100 104 106 150
4012 101, 130, 134, 136, 158
4023 101, 130, 134, 136
4024 102 130 134 136
4024 102, 130, 134, 136
4033 102, 130, 134, 136 4057 103, 130, 134, 136
4057 103 130 134 136
40E7M 102 120 124 126
4057M 103, 130, 134, 136
4058 104, 130, 134, 136
4058M 104, 130, 134, 136
4067 105, 130, 134, 136
4068 106, 130, 134, 136
4073 107, 131, 134, 136
4073 107, 131, 134, 130
4074 108, 131, 134, 136
4076 109, 131, 134, 136
1001 110 101 104 106
4081 110, 131, 134, 136 4082 157
4082 157
4092 110, 131, 134, 136
4193 84, 86
4194 84,86
4195 85, 86
•
4196 85, 86
4503 111, 131, 134, 136
4500M 111 101 104 106
4503M 111, 131, 134, 136
4504 111, 131, 134, 136, 156
4504M 111, 131, 134, 136, 156
4510 110 101 104 106
4512 112, 131, 134, 136
4523 112, 131, 134, 136
4524 113, 131, 134, 136
4500 110 101 104 106
4533 113, 131, 134, 136
4557 114, 131, 134, 136
4557M 114 131 134 136
4557M 114, 131, 134, 136 4558M 114, 131, 134, 136
4558M 114, 131, 134, 136
4568 115, 132, 134, 136
1571 115 122 121 126
4574 115, 132, 134, 136
4582 156
4592 116, 132, 134, 136
40E1 120 141 142
4951 138, 141, 142
4951M 138, 141, 142
4965 138, 141, 142
4060 120, 111, 112
4968 139, 141, 142
5023 116, 132, 134, 136
5023M 116, 132, 134, 136
5025W 110, 152, 154, 150
5024 117, 132, 134, 137
5024M 117, 132, 134, 137
5026 117, 132, 134, 137
5020 117, 102, 101, 107
5032 143, 144
5033 118, 132, 134, 137
5034 118, 132, 134, 137
5038 143, 144
5054 119, 132, 134, 137
5068 120, 132, 134, 137
5069 142
5071 139, 141, 142
5072 121, 132, 134, 137
5072 100 100 101 107
5076 122, 132, 134, 137
5092 123, 132, 134, 137
. , - ,,
550/ 100 100 10/ 107
5524 123, 132, 134, 137
5524M 123, 132, 134, 137
5524M 123, 132, 134, 137
5524M 123, 132, 134, 137 5534 124, 133, 134, 137
5524M 123, 132, 134, 137 5534 124, 133, 134, 137 5554 124, 133, 134, 137
5524M 123, 132, 134, 137 5534 124, 133, 134, 137 5554 124, 133, 134, 137 5568 125, 133, 134, 137
5524M 123, 132, 134, 137 5534 124, 133, 134, 137 5554 124, 133, 134, 137 5568 125, 133, 134, 137
5524M 123, 132, 134, 137 5534 124, 133, 134, 137 5554 124, 133, 134, 137 5568 125, 133, 134, 137 5592 125, 133, 135, 137
5524M 123, 132, 134, 137 5534 124, 133, 134, 137 5554 124, 133, 134, 137 5568 125, 133, 134, 137 5592 125, 133, 135, 137 5594 126, 133, 135, 137
5524M 123, 132, 134, 137 5534 124, 133, 134, 137 5554 124, 133, 134, 137 5568 125, 133, 134, 137 5592 125, 133, 135, 137

```
6917A 140, 141, 142
6921 87, 95, 96, 97
6930 87, 95, 96, 97, 151
6931 88, 95, 96, 97, 151
6932 88, 95, 96, 97, 155
6933 89, 95, 96, 97
6934S 97, 155
6935 89, 95, 96, 97
6936 90, 95, 96, 97, 155
6937 89, 95, 96, 97
6937A 89, 95, 96, 97
6939 90, 95, 96, 97
6940 126, 133, 135, 137
6942 91, 95, 96, 97, 155
6943 91, 95, 96, 97, 155
6944 92, 95, 96, 97
6945 92, 95, 96, 97, 155
6947 93, 95, 96, 97
6948 93, 95, 96, 97, 151
6949 94, 95, 96, 97, 151
6957 127, 133, 135, 137
6957J 128, 133, 135, 137
6961 128, 133, 135, 137
6962 129, 133, 135, 137
6963 89, 95, 96, 97
6966 90, 95, 96, 97, 155
6996 94, 95, 96, 97
6999 90, 95, 96, 97
7088 57, 73, 78
7089 57, 73, 78
7107 57, 73, 78
7108 57, 73, 78
7223 37
7227 23, 34, 37, 146, 155
7229 23, 34, 37, 146, 155, 165
7230 24, 34, 37, 146, 153
7231 24, 34, 37, 146, 165
7232 25, 34, 37, 146, 153
7253 42, 69, 77, 163
7271 25, 34, 37, 146
7272 13, 20, 22, 37, 147
7274 26, 34, 37, 147, 153
7275 26, 35, 37, 147, 161, 165
7276 27, 35, 37, 147, 165
7277 14, 20, 22, 37, 147, 153
7278 27, 35, 37, 147, 153
7279 148, 153
7285 148, 153
7287 37
7288 28, 35, 37, 148
7289 15, 20, 22, 148, 153
7290 28, 35, 37, 148
7295 22
7297 15, 20, 22, 148
7299 16, 20, 22, 149
7303 16, 20, 22, 149
7304 17, 20, 22, 149
7860 59, 73, 79
7861 59, 73, 79
7862 59, 73, 79
7864 59, 73, 79
7865 59, 73, 79
7866 59, 73, 79
7960i 65, 75, 79
7961i 65, 75, 79
7962i 65, 75, 79
7964i 65, 75, 79
7965i 65, 75, 79
7966i 65, 75, 79
```

```
8085 58, 73, 78
8086 58, 73, 78
8088 58, 73, 78
8089 58, 73, 78
8158 60, 74, 79
8160 60, 74, 79
8161 60, 74, 79
8162 60, 74, 79
8164 60, 74, 79
8165 60, 74, 79
8166 60, 74, 79
8330 56, 73, 78, 159
8331 56, 73, 78, 159
8331M 56, 73, 78, 159
8340 56, 73, 78, 159
8341 56, 73, 78, 159
8341M 56, 73, 78, 159
8342 56, 73, 78, 159
8416 55, 72, 78
8417 55, 72, 78
8417M 55, 72, 78
8418 55, 72, 78
8419 55, 72, 78
8424 56, 72, 78
8426 56, 72, 78
8427 56, 72, 78
8960i 67, 76, 79
8961i 67, 76, 79
8962i 67, 76, 79
8964i 66, 75, 79
8965i 66, 75, 79
8966i 66, 75, 79
8968i 67, 76, 79
ADD01 40, 69, 77
ADDR01 40, 69, 77
ADDR03 40, 69, 77
ADDR06 40, 69, 77
ADDRL1 40, 69, 77
ADDRS1 41, 69, 77
ADSR01 41, 69, 77
ADSR03 41, 69, 77
ADSR06 41, 69, 77
ADVDD01 42, 69, 77
AT501 42, 69, 77, 163
C154DWK 18, 21, 22, 149
C164AWK 18, 21, 22
C174AWK 18, 21, 22
D153ATG 29, 35, 38, 149
D153DRG 29, 35, 38, 149
D153VRC 38
D154ATG 29, 35, 38, 149
D154AWG 30, 36, 38, 150
D154DRG 29, 35, 38, 149
D154VRC 30, 36, 38, 150
D154VWC 31, 36, 38, 150
D164AWG 30, 36, 38
D164VWC 31, 36, 38
D224DRG 31, 36, 38
D224TRK 19, 21, 22
D224VRC 32, 36, 38
D284DRG 32, 36, 38
D284TRK 19, 21, 22
D284VRC 33, 36, 38
E1DR01 43, 69, 77
E1DR03 43, 69, 77
E1DR06 43, 69, 77
E1DR21 43, 69, 77
E2DR01 44, 70, 77
E2DR03 44, 70, 77
E2DR06 44, 70, 77
E2DR21 44, 70, 77
```

E2DR31 44, 70, 77

E2DR33 44, 70, 77 E2SR01 45, 70, 77 E2SR03 45, 70, 77 E2SR06 45, 70, 77 E2VDD01 45, 70, 77 KD701 49, 71, 78, 154 KD703 49, 71, 78, 154 KD706 49, 71, 78, 154 KDR401 47, 70, 77 KDR403 47, 70, 77 KDR601 48, 71, 77, 154 KDR603 48, 71, 77, 154 KDR606 48, 71, 77, 154 KDR651 49, 71, 77, 154 KDR653 49, 71, 77, 154 KDR701 50, 71, 78, 154 KDR703 50, 71, 78, 154 KDR706 50, 71, 78, 154 KDR721 51, 71, 78, 154 KDR801 53, 72, 78 KDR803 53, 72, 78 KDR901 53, 72, 78 KDR903 53, 72, 78 KDR906 53, 72, 78 KDR921 54, 72, 78 KSR401 48, 70, 77 KSR403 48, 70, 77 KSR701 52, 71, 78 KSR703 52, 71, 78 KSR706 52, 71, 78 KSR901 54, 72, 78 KSR903 54, 72, 78 KSR906 54, 72, 78 KVDD701 52, 71, 78, 154 KVDD901 55, 72, 78 P1501DR 46, 70, 77 SDR203 62, 74, 79, 152 SDR303 63, 75, 79, 152 SDR306 63, 75, 79, 152 SED01 61,74,79 SEDR01 61, 74, 79 SEDRL1 79 SES01 61, 74, 79 SESR01 61, 74, 79 SS103 62, 74, 79, 152 SS106 62, 74, 79, 152 SSR203 63, 74, 79, 152 SSR303 64, 75, 79, 152 SSR306 64, 75, 79, 152 SVDD303 64, 75, 79, 152 VEDR01 68, 76, 79

6917 140, 141, 142

7968i 66, 75, 79

8040 17, 21, 22

8042 18, 21, 22



By Family

A	CapSure SP Novus	G	Kappa 700 D
Adapta DR	4092 110, 131, 134, 136	GEM	KD701 49, 71, 78, 154
ADD01 40, 69, 77	4592 116, 132, 134, 136	7227 23, 34, 37, 146, 155	KD703 49, 71, 78, 154
	5092 123, 132, 134, 137	GEM DR	KD706 49, 71, 78, 154
ADDR01 40, 69, 77 ADDR03 40, 69, 77	5592 125, 133, 135, 137		Kappa 700 DR
	5594 126, 133, 135, 137	7271 25, 34, 37, 146	KDR701 50, 71, 78, 154
ADDRIA 40, 69, 77	CapSure VDD	GEM II VR	KDR703 50, 71, 78, 154
ADDRL1 40, 69, 77	5032 143, 144	7229 23, 34, 37, 146, 155,	KDR706 50, 71, 78, 154
ADDRS1 41, 69, 77	CapSure VDD-2	165	KDR721 51, 71, 78, 154
Adapta SR	5038 143, 144	GEM III AT	Kappa 700 SR
ADSR01 41, 69, 77	CapSure Z	7276 27, 35, 37, 147, 165	KSR701 52, 71, 78
ADSR03 41, 69, 77	4033 102, 130, 134, 136	GEM III DR	KSR703 52, 71, 78
ADSR06 41, 69, 77	4533 113, 131, 134, 136	7275 26, 35, 37, 147, 161,	KSR706 52, 71, 78
Adapta VDD	5033 118, 132, 134, 137	165	Kappa 700 VDD
ADVDD01 42, 69, 77	5034 118, 132, 134, 137	GEM III VR	KVDD701 52, 71, 78, 154
AT500	5534 124, 133, 134, 137	7231 24, 34, 37, 146, 165	Kappa 800 DR
7253 42, 69, 77, 163	CapSure Z Novus		KDR801 53, 72, 78
AT501 42, 69, 77, 163	5054 119, 132, 134, 137	1	KDR803 53, 72, 78
Attain	5554 124, 133, 134, 137	1	Kappa 900 DR
2187 83,86	Concerto	InSync	KDR901 53, 72, 78
2188 83, 86	C154DWK 18, 21, 22, 149	8040 17, 21, 22	KDR903 53, 72, 78
4193 84, 86	C164AWK 18, 21, 22	InSync ICD	KDR906 53, 72, 78
4194 84, 86	C174AWK 18, 21, 22	7272 13, 20, 22, 37, 147	Kappa 900 SR
4196 85, 86	C174AWR 10, 21, 22 Consulta	InSync Marquis	KSR901 54, 72, 78
		7277 14, 20, 22, 147, 153	
С	D224TRK 19, 21, 22	InSync Maximo	KSR903 54, 72, 78
		7303 16, 20, 22, 149	KSR906 54, 72, 78
CapSure	E	7304 17, 20, 22, 149	Kappa 900 VDD
4003 99, 130, 134, 136	EnPulse DR	InSync Sentry	KVDD901 55, 72, 78
4003M 99, 130, 134, 136	E1DR01 43, 69, 77	7297 15, 20, 22, 148	Kappa 920 DR
4004 100, 130, 134, 136,	E1DR03 43, 69, 77	7299 16, 20, 22, 149	KDR921 54, 72, 78
157	E1DR06 43, 69, 77	InSync II Marquis	
4004M 100, 130, 134, 136,	E1DR00 43, 63, 77 E1DR21 43, 69, 77	7289 15, 20, 22, 148, 153	L
157	EnPulse 2 DR	InSync II Protect	Legend
4503 111, 131, 134, 136	E2DR01 44, 70, 77	7295 22	8416 55, 72, 78
4503M 111, 131, 134, 136	E2DR01 44, 70, 77 E2DR03 44, 70, 77	InSync III Protect	8417 55, 72, 78
4504 111, 131, 134, 136,	E2DR05 44, 70, 77	7285 148, 153	
156		InSync III	8417M 55, 72, 78
4504M 111, 131, 134, 136,	E2DR21 44, 70, 77	8042 18, 21, 22	8418 55, 72, 78
156	E2DR31 44, 70, 77	InSync III Marquis	8419 55, 72, 78
5026 117, 132, 134, 137	E2DR33 44, 70, 77	7279 148, 153	Legend II
CapSureFix	EnPulse 2 SR	Intrinsic	8424 56, 72, 78
4067 105, 130, 134, 136	E2SR01 45, 70, 77	7288 28, 35, 37, 148	8426 56, 72, 78
4068 106, 130, 134, 136	E2SR03 45, 70, 77	Intrinsic 30	8427 56, 72, 78
4568 115, 132, 134, 136	E2SR06 45, 70, 77	7287 37	
5068 120, 132, 134, 137	EnPulse 2 VDD		M
5568 125, 133, 134, 137	E2VDD01 45, 70, 77	V	Marquis DR
6940 126, 133, 135, 137	EnRhythm DR	K	7274 26, 34, 37, 147, 153
CapSureFix Novus	P1501DR 46, 70, 77	Kappa 400 DR	Marquis VR
4076 109, 131, 134, 136	EnTrust	KDR401 47, 70, 77	7230 24, 34, 37, 146, 153
5076 122, 132, 134, 137	D153ATG 29, 35, 38, 149	KDR403 47, 70, 77	Maximo DR
CapSure Epi	D153DRG 29, 35, 38, 149	Kappa 400 SR	7278 27, 35, 37, 147, 153
4965 138, 141, 142	D153VRC 38	KSR401 48, 70, 77	
4968 139, 141, 142	D154ATG 29, 35, 38, 149	KSR403 48, 70, 77	Maximo II
CapSure Sense	D154DRG 29, 35, 38, 149	Kappa 600 DR	D284TRK 19, 21, 22
4073 107, 131, 134, 136	D154VRC 30, 36, 38, 150	KDR601 48, 71, 77, 154	Maximo II DR
4074 108, 131, 134, 136	Epicardial Patch	KDR603 48, 71, 77, 154	D284DRG 32, 36, 38
4574 115, 132, 134, 136	6721 87, 95, 96, 97	KDR606 48, 71, 77, 154	Maximo II VR
CapSure SP	6921 87, 95, 96, 97	KDR651 49, 71, 77, 154	D284VRC 33, 36, 38
4023 101, 130, 134, 136		KDR653 49, 71, 77, 154	Maximo VR
4024 102, 130, 134, 136			7232 25, 34, 37, 146, 153
4523 112, 131, 134, 136			Minix/Minix ST
4524 113, 131, 134, 136			8330 56, 73, 78, 159
5023 116, 132, 134, 136			8331 56, 73, 78, 159
5023M 116, 132, 134, 136			8331M 56, 73, 78, 159
5024 117, 132, 134, 137			8340 56, 73, 78, 159
5024M 117, 132, 134, 137			8341 56, 73, 78, 159
5524 123, 132, 134, 137			8341M 56, 73, 78, 159
550416 400 400 404 435			8342 56, 73, 78, 159

5524M 123, 132, 134, 137



By Family continued

Minuet	Sigma 200 SR	Thera-i DR
7107 57, 73, 78	SSR203 63, 74, 79, 152	7960i 65, 75, 79
7107 57, 73, 78	Sigma 300 DR	7961i 65, 75, 79
7100 57, 75, 70	SDR303 63, 75, 79, 152	7962i 65, 75, 79
	SDR306 63, 75, 79, 152	7968i 66, 75, 79
	Sigma 300 SR	Thera-i S
0	SSR303 64, 75, 79, 152	8964i 66, 75, 79
Onyx	SSR306 64, 75, 79, 152	8965i 66, 75, 79
7290 28, 35, 37, 148	Sigma 300 VDD	8966i 66, 75, 79
, , , , , , , , , , , , , , , , , , , ,	SVDD303 64, 75, 79, 152	Thera-i SR
6	Spectraflex	8960i 67, 76, 79
P	4951 138, 141, 142	8961i 67, 76, 79
Preva DR	4951M 138, 141, 142	8962i 67, 76, 79
7088 57, 73, 78	6957 127, 133, 135, 137	Thera-i VDD
7089 57, 73, 78	6957J 128, 133, 135, 137	8968i 67, 76, 79
Preva SR	Sprint	Transvene
8088 58, 73, 78	6932 88, 95, 96, 97	6934S 97
8089 58, 73, 78	6942 91, 95, 96, 97	6936 90, 95, 96, 97
Prevail S	6943 91, 95, 96, 97	6966 90, 95, 96, 97
8085 58, 73, 78	6945 92, 95, 96, 97	22 22, 22, 23, 2.
8086 58, 73, 78	Sprint Fidelis	
Prodigy D	6930 87, 95, 96, 97, 151	V
7864 59, 73, 79	6931 88, 95, 96, 97, 151	Versa DR
7865 59, 73, 79	6948 93, 95, 96, 97, 151	VEDR01 68, 76, 79
7866 59, 73, 79	6949 94, 95, 96, 97, 151	Virtuoso
Prodigy DR	Sprint Quattro	D154AWG 30, 36, 38, 150
7860 59, 73, 79	6944 92, 95, 96, 97	D164AWG 30, 36, 38
7861 59, 73, 79	Sprint Quattro Secure	D154VWC 31, 36, 38, 150
7862 59, 73, 79	6935 89, 95, 96, 97	D164VWC 31, 36, 38
Prodigy S	6947 93, 95, 96, 97	
8164 60, 74, 79	StarFix	
8165 60, 74, 79	4195 85, 86	
8166 60, 74, 79	Sub-Q Lead	
Prodigy SR	6996 94, 95, 96, 97	
8158 60, 74, 79	Sub-Q Patch	
8160 60, 74, 79	6939 90, 95, 96, 97	
8161 60, 74, 79	6999 90, 95, 96, 97	
8162 60, 74, 79	SureFix	
	5072 121, 132, 134, 137	
S	SVC/CS	
Screw-In	6933 89, 95, 96, 97	
4057 103, 130, 134, 136	6937 89, 95, 96, 97	
4057M 103, 130, 134, 136	6937A 89, 95, 96, 97	
4058 104, 130, 134, 136	6963 89, 95, 96, 97	
4058M 104, 130, 134, 136		
4557 114, 131, 134, 136	Т	
4557M 114, 131, 134, 136		
4558M 114, 131, 134, 136	Target Tip	
Secura DR	4011 100, 130, 134, 136	
D224DRG 31, 36, 38	4012 101, 130, 134, 136,	
SelectSecure	158 4081 110, 131, 134, 136	
3830 98, 130, 134, 136	4081 110, 131, 134, 130	
Sensia DR	4512 112, 131, 134, 136	
SED01 61,74,79	4512 112, 151, 154, 150	
SEDR01 61,74,79	Tenax	
SEDRL1 79	6917 140, 141, 142	
Sensia SR	6917A 140, 141, 142	
SES01 61, 74, 79	6961 128, 133, 135, 137	
SESR01 61, 74, 79	6962 128, 133, 135, 137	
Sigma 100 S	Thera-i D	

7964i 65, 75, 79

7965i 65, 75, 79

7966i 65, 75, 79

If you are looking for a model number or family that is not included in this report, you may call US Technical Services (see page 2).

SS103 62, 74, 79, 152

SS106 62, 74, 79, 152

SDR203 62, 74, 79, 152

Sigma 200 DR

Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits (pictured right) with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab.

CRDM Returned Product Analysis Laboratory Medtronic, Inc. 7000 Central Avenue NE MS RCE172 Minneapolis, MN 55432-3576 USA

Phone: 1 (800) 328-2518, ext. 44800 Email: crdm.returnedproduct@medtronic.com



www.medtronic.com

World Headquarters

Medtronic, Inc. 710 Medtronic Parkway Minneapolis, MN 55432-5604 USA

Tel: (763) 514-4000 Fax: (763) 514-4879

Medtronic USA, Inc.
Toll-free: 1 (800) 328-2518
(24-hour technical support for physicians and medical professionals)

Europe

Medtronic International Trading Sàrl Route du Molliau 31 CH-1131 Tolochenaz Switzerland

Tel: (41 21) 802 7000 Fax: (41 21) 802 7900

Canada

Medtronic of Canada Ltd. 6733 Kitimat Road Mississauga, Ontario L5N 1W3 Canada

Tel: (905) 826-6020 Fax: (905) 826-6620 Toll-free: 1 (800) 268-5346

Asia Pacific

Medtronic International, Ltd. 16/F Manulife Plaza The Lee Gardens, 33 Hysan Avenue Causeway Bay Hong Kong

Tel: (852) 2891 4456 Fax: (852) 2891 6830 enquiryap@medtronic.com

Latin America

Medtronic USA, Inc. Doral Corporate Center II 3750 NW 87th Avenue Suite 700 Miami, FL 33178

Tel: (305) 500-9328 Fax: (786) 709-4244

